

Fundamentals and applications of X-ray diffraction. Applications in catalysts characterization.

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Outline

1. Crystal lattice. Symmetry
2. X-ray diffraction
3. Braggs' peaks positions. Indexing
4. Relative intensities of Braggs' Peaks. Structure factor. Structure refinement
5. Sample preparation
6. Examples

What is crystal?

A material has a crystal structure if its constituents (such as atoms, molecules, or ions) are arranged in a 3D translationally periodic order forming a crystal lattice.

$$\text{Crystal} = \text{Lattice} * \text{Motif}$$

What is crystal?

~~A material has a crystal structure if its constituents (such as atoms, molecules, or ions) are arranged in a 3D translationally periodic order forming a crystal lattice~~

Crystal = Lattice * Motif

A material is a crystal if displays a sharp diffraction pattern with most of intensity concentrated in relatively sharp Bragg peaks.

Symmetry

Fundamental property of the orderly arrangements of atoms found in crystalline solids

rotation



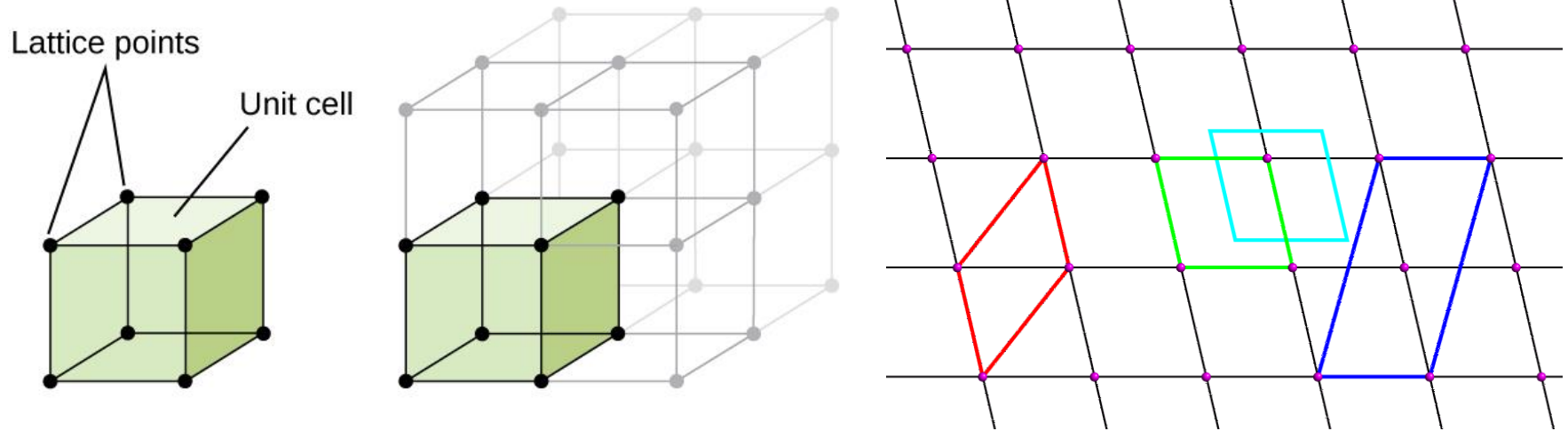
reflection



translation



Unit cell. Translational symmetry



Unit cell: smallest unit that repeats in the lattice (translation)

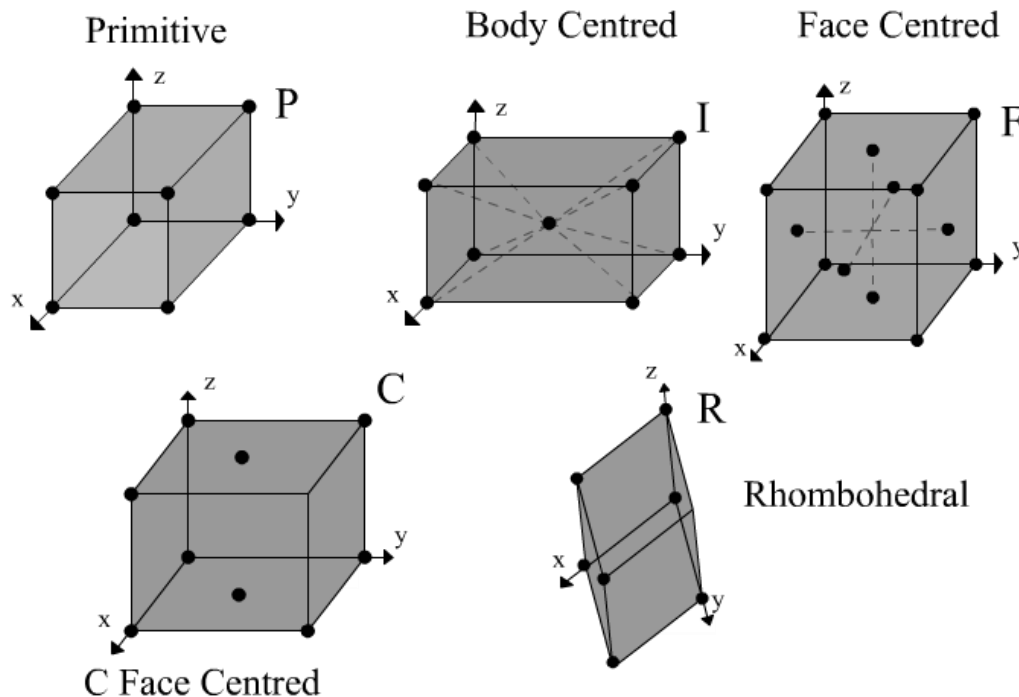
- minimum number of lattice points
- origin on one lattice point
- angles as close to 90° as possible

Unit cell centering

Unit cell: smallest unit that repeats in the lattice (translation)

- Primitive unit cell: lattice point only at corners
- Non-primitive unit cell: lattice points also at other positions

| Centering Type | Symbol |
|--------------------------|--------|
| Primitive - no centering | P |
| A-face centered | A |
| B-face centered | B |
| C-face centered | C |
| All-face centered | F |
| Body centered | I |
| Rhombohedrally centered | R |



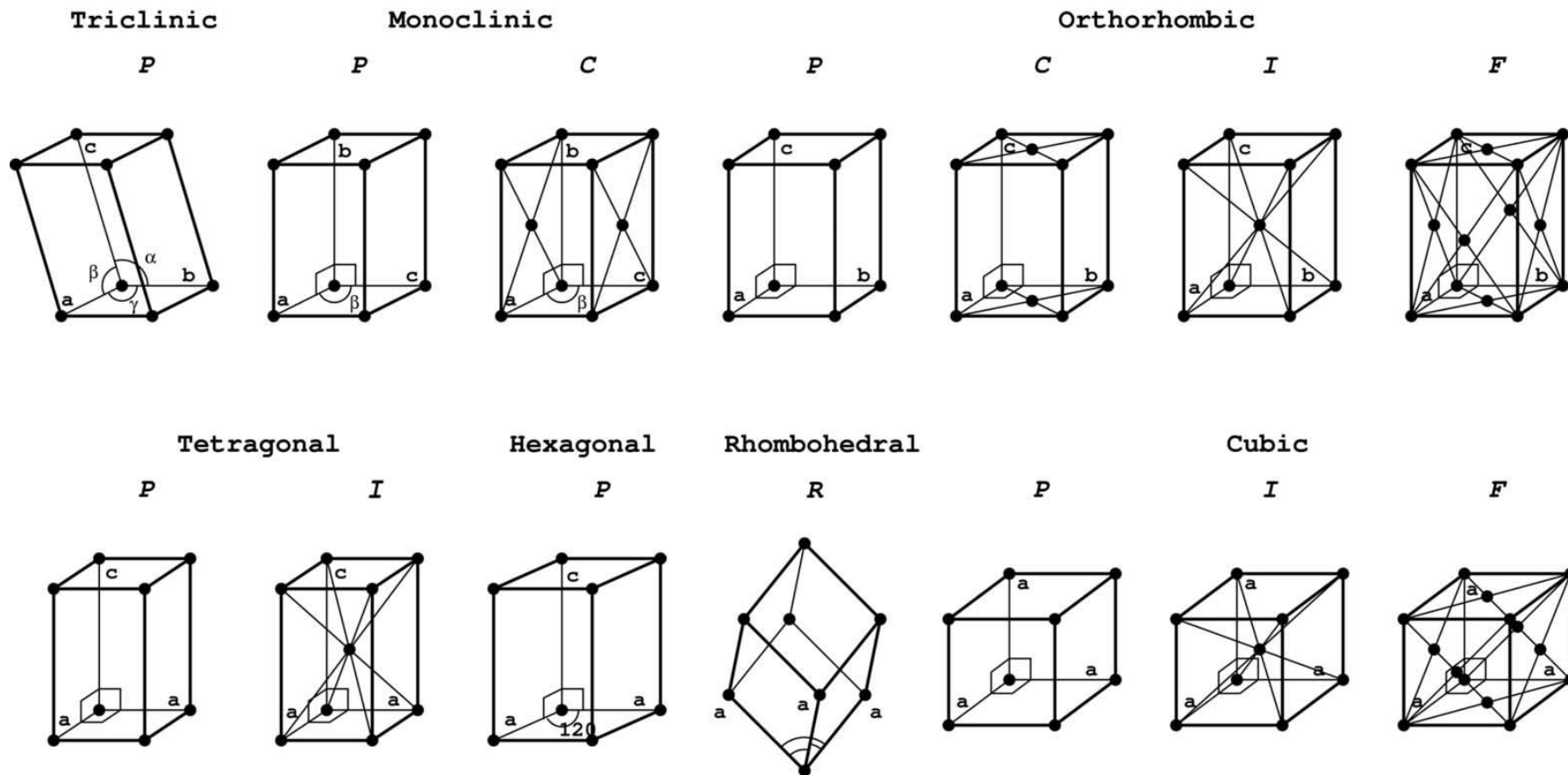
Crystal systems

Combining a lattice with the different orders of rotation symmetry leads to the seven possible crystal systems

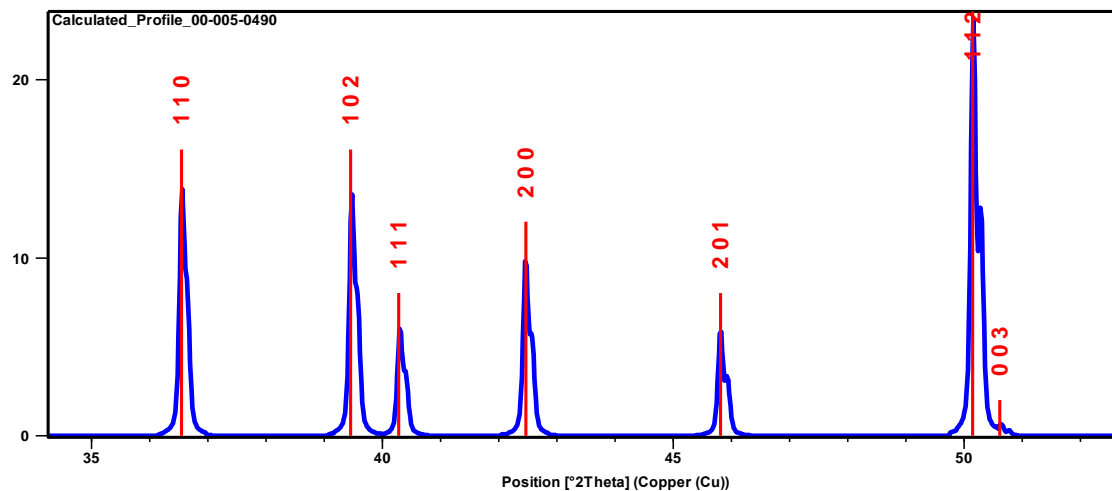
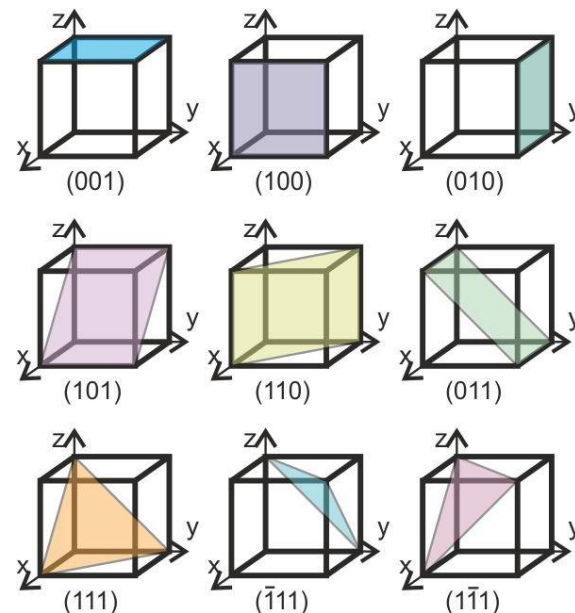
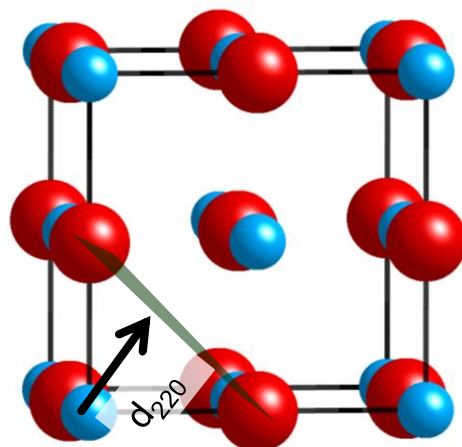
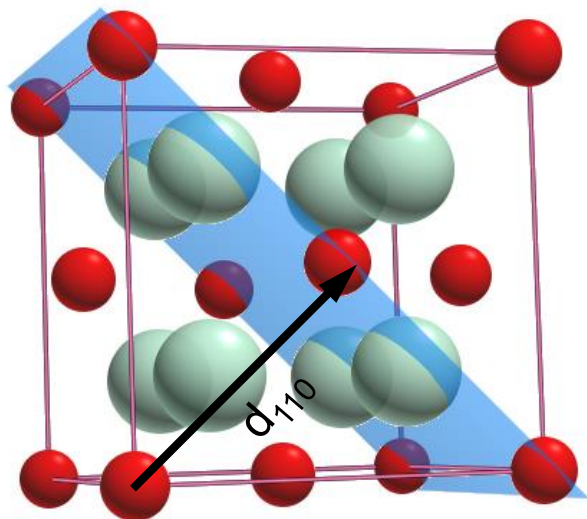
| Crystal System | Characteristic Symmetry | Unit-Cell Parameters |
|----------------|-------------------------|--|
| Triclinic | 1× 1-fold | $a \neq b \neq c; \alpha \neq \beta \neq \gamma$ |
| Monoclinic | 1× 2-fold | $a \neq b \neq c; \alpha = \gamma = 90^\circ; \beta \neq 90^\circ$ |
| Orthorhombic | 3× 2-fold | $a \neq b \neq c; \alpha = \beta = \gamma = 90^\circ$ |
| Tetragonal | 1× 4-fold | $a = b \neq c; \alpha = \beta = \gamma = 90^\circ$ |
| Trigonal | 1× 3-fold | $a = b \neq c; \alpha = \beta = 90^\circ; \gamma = 120^\circ$ |
| Hexagonal | 1× 6-fold | $a = b \neq c; \alpha = \beta = 90^\circ; \gamma = 120^\circ$ |
| Cubic | 4× 3-fold | $a = b = c; \alpha = \beta = \gamma = 90^\circ$ |

Bravais lattices

Combining crystal systems with unit cell centerings leads to the fourteen possible Bravais lattices

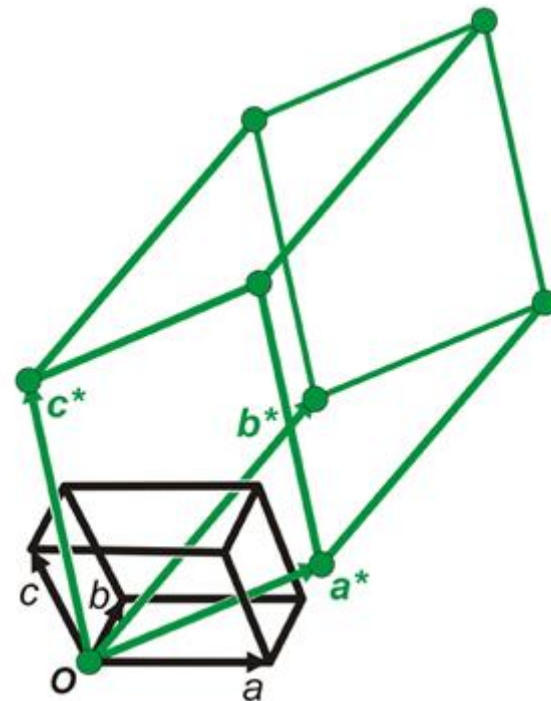
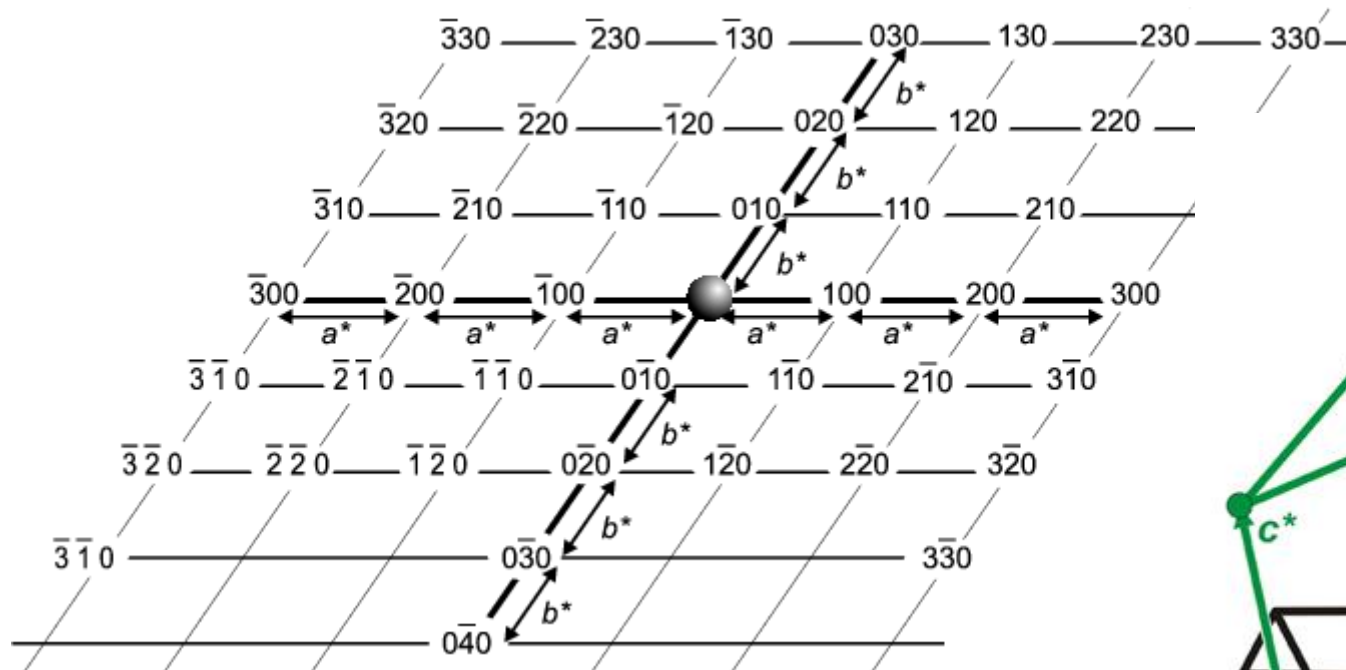


Miller indices (hkl)



Miller indices represent the lattice planes. Peaks in a diffraction pattern can be assigned to planes of the crystal

Reciprocal space



$$\mathbf{d}^* = h\mathbf{a}^* + k\mathbf{b}^* + l\mathbf{c}^*$$

$$1/d = d^*$$

$$\mathbf{a}^* = \frac{\mathbf{b} \times \mathbf{c}}{V}; \quad \mathbf{b}^* = \frac{\mathbf{c} \times \mathbf{a}}{V}; \quad \mathbf{c}^* = \frac{\mathbf{a} \times \mathbf{b}}{V};$$

Miller indices (hkl) and d-spacing

d-spacings in different crystal systems

Crystal system d_{hkl} as a function of Miller indices and lattice parameters

Cubic
$$\frac{1}{d^2} = \frac{h^2 + k^2 + l^2}{a^2}$$

Tetragonal
$$\frac{1}{d^2} = \frac{h^2 + k^2}{a^2} + \frac{l^2}{c^2}$$

Orthorhombic
$$\frac{1}{d^2} = \frac{h^2}{a^2} + \frac{k^2}{b^2} + \frac{l^2}{c^2}$$

Hexagonal
$$\frac{1}{d^2} = \frac{4}{3} \left(\frac{h^2 + hk + k^2}{a^2} \right) + \frac{l^2}{c^2}$$

Monoclinic
$$\frac{1}{d^2} = \frac{1}{\sin^2\beta} \left(\frac{h^2}{a^2} + \frac{k^2 \sin^2\beta}{b^2} + \frac{l^2}{c^2} - \frac{2hlc\cos\beta}{ac} \right)$$

Systematic absences

| Lattice Centering | Symmetry Operator(s) | Reflection Condition |
|-------------------|---|---------------------------------|
| <i>P</i> | - | None |
| <i>A</i> | $x, 1/2+y, 1/2+z$ | $hkl: k + l = 2n$ |
| <i>B</i> | $1/2+x, y, 1/2+z$ | $hkl: h + l = 2n$ |
| <i>C</i> | $1/2+x, 1/2+y, z$ | $hkl: h + k = 2n$ |
| <i>F</i> | $x, 1/2+y, 1/2+z; 1/2+x, y, 1/2+z; 1/2+x, 1/2+y, z$ | $hkl: k + l, h + l, h + k = 2n$ |
| <i>I</i> | $1/2+x, 1/2+y, 1/2+z$ | $hkl: h + k + l = 2n$ |
| <i>R</i> | $1/3+x, 2/3+y, 2/3+z; 2/3+x, 1/3+y, 1/3+z$ | $hkl: -h + k + l = 3n$ |

Rotary-Inversion Symmetry

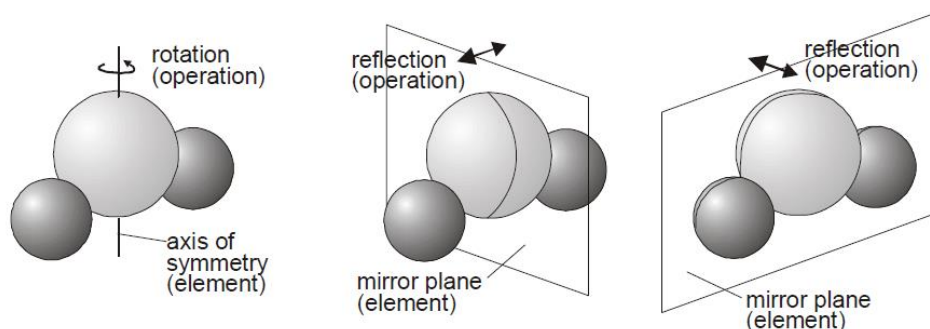
| Symmetry operation | Symmetry elements |
|---------------------------|-------------------|
| Identity | ---- |
| Rotation by $360^\circ/n$ | n-fold axis |
| Reflection | mirror plane |
| Inversion | point |



Translation
(Bravais lattice)



screw axis
glide plane

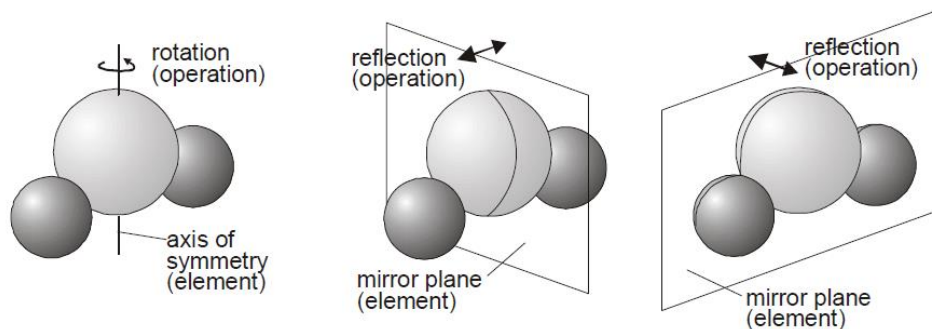


Rotary-Inversion Symmetry

| Symmetry operation | Symmetry elements |
|---------------------------|-------------------|
| Identity | ---- |
| Rotation by $360^\circ/n$ | n-fold axis |
| Reflection | mirror plane |
| Inversion | point |



Translation
(Bravais lattice)



230 space groups
e.g. *Pm3m**

*<http://img.chem.ucl.ac.uk/sgp/misc/notation.htm>

Space groups

Triclinic: e.g. $P-1$

1. An inversion center (presence or absence)

Monoclinic: e.g. $P2$, Pm , $P2/m$

1. A symmetry with respect to the unique axis direction (b or c)

Orthorhombic: e.g. $P222$, $Pmm2$ (or $Pm2m$ or $P2mm$), $Pmmm$

1. A symmetry with respect to the a axis
2. A symmetry with respect to the b axis
3. A symmetry with respect to the c axis

Tetragonal: e.g. $P4$, $P-4$, $P4/m$, $P422$, $P4mm$, $P-42m$ (or $P-4m2$), $P4/mmm$

1. The 4-fold symmetry parallel to the c axis
2. The symmetry with respect to both the x and y axes
3. The symmetry with respect to the face diagonals $[1\ 1\ 0]$

Space groups

Trigonal & Rhombohedral: e.g. $P3$, $P-3$, $P321$, $P312$, $P3m1$, $P31m$, $P-3m1$, $P-31m$

1. The 3-fold symmetry parallel to the c axis
2. The symmetry with respect to the a and b axes
3. The additional symmetry elements with respect to $[2\ 1\ 0]$

Hexagonal: e.g. $P6$, $P-6$, $P6/m$, $P622$, $P6mm$, $P-62m$ (or $P-6m2$), $P6/mmm$

1. The 6-fold symmetry parallel to the c axis
2. The symmetry with respect to the a and b axes
3. The additional symmetry elements with respect to $[2\ 1\ 0]$

Cubic: e.g. $P23$, $Pm-3$, $P432$, $P-43m$, $Pm3m$

1. The symmetry with respect to the a , b , and c axes
2. The 3-fold symmetry of the body diagonals $[1\ 1\ 1]$
3. The symmetry with respect to the face diagonals $[1\ 1\ 0]$

Tables for X-ray Crystallography

 $P4_32_12$ D_4^8

422

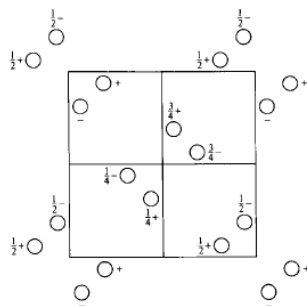
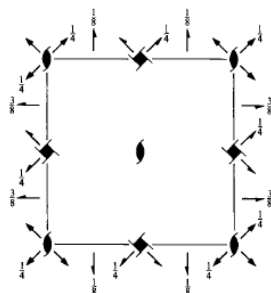
Tetragonal

CONTINUED

No. 96

 $P4_32_12$

No. 96

 $P4_32_12$ Patterson symmetry $P4/mmm$ Origin on $2[110]$ at $2, 1(1, 2)$ Asymmetric unit $0 \leq x \leq 1; 0 \leq y \leq 1; 0 \leq z \leq \frac{1}{2}$

Symmetry operations

- (1) 1 (2) $2(0, 0, \frac{1}{2})$ $0, 0, z$ (3) $4(0, 0, \frac{1}{4})$ $0, \frac{1}{2}, z$ (4) $4(0, 0, \frac{3}{4})$ $\frac{1}{2}, 0, z$
 (5) $2(0, \frac{1}{2}, 0)$ $\frac{1}{2}, y, \frac{1}{2}$ (6) $2(\frac{1}{2}, 0, 0)$ $x, \frac{1}{2}, \frac{1}{2}$ (7) 2 $x, x, 0$ (8) 2 $x, \bar{x}, \frac{1}{2}$

Generators selected (1); $t(1, 0, 0)$; $t(0, 1, 0)$; $t(0, 0, 1)$; (2); (3); (5)

Positions

Multiplicity,
Wyckoff letter,
Site symmetry

Coordinates

Reflection conditions

General:

- 8 b 1 (1) x, y, z (2) $\bar{x}, \bar{y}, z + \frac{1}{2}$ (3) $\bar{y} + \frac{1}{2}, x + \frac{1}{2}, z + \frac{1}{2}$ (4) $y + \frac{1}{2}, \bar{x} + \frac{1}{2}, z + \frac{1}{2}$ $00l : l = 4n$
 (5) $\bar{x} + \frac{1}{2}, y + \frac{1}{2}, \bar{z} + \frac{1}{2}$ (6) $x + \frac{1}{2}, \bar{y} + \frac{1}{2}, \bar{z} + \frac{1}{2}$ (7) y, x, \bar{z} (8) $\bar{y}, \bar{x}, \bar{z} + \frac{1}{2}$ $h00 : h = 2n$

Special: as above, plus

- 4 a $\cdot \cdot 2$ $x, x, 0$ $\bar{x}, \bar{x}, \frac{1}{2}$ $\bar{x} + \frac{1}{2}, x + \frac{1}{2}, \frac{1}{2}$ $x + \frac{1}{2}, \bar{x} + \frac{1}{2}, \frac{1}{2}$ $0kl : l = 2n + 1$
 or $2k + l = 4n$

Symmetry of special projections

Along $[001]$ $p4gm$ Along $[100]$ $p2gg$ Along $[110]$ $p2gm$ $\mathbf{a}' = \mathbf{a}$ $\mathbf{b}' = \mathbf{b}$ $\mathbf{a}' = \mathbf{b}$ $\mathbf{b}' = \mathbf{c}$ $\mathbf{a}' = \frac{1}{2}(-\mathbf{a} + \mathbf{b})$ $\mathbf{b}' = \mathbf{c}$ Origin at $0, \frac{1}{2}, \frac{1}{2}$ Origin at $x, \frac{1}{2}, \frac{1}{2}$ Origin at $x, x, 0$

Maximal non-isomorphic subgroups

- I [2] $P4, 11(P4, 78)$ 1; 2; 3; 4
 [2] $P2, 12(C222, 20)$ 1; 2; 7; 8
 [2] $P2, 2_1(P2, 2, 2, 19)$ 1; 2; 5; 6

IIa none

IIb none

Maximal isomorphic subgroups of lowest index

- IIc [3] $P4, 2, 2(c' = 3c)(92)$; [5] $P4, 2, 2(c' = 5c)(96)$; [9] $P4, 2, 2(a' = 3a, b' = 3b)(96)$

Minimal non-isomorphic supergroups

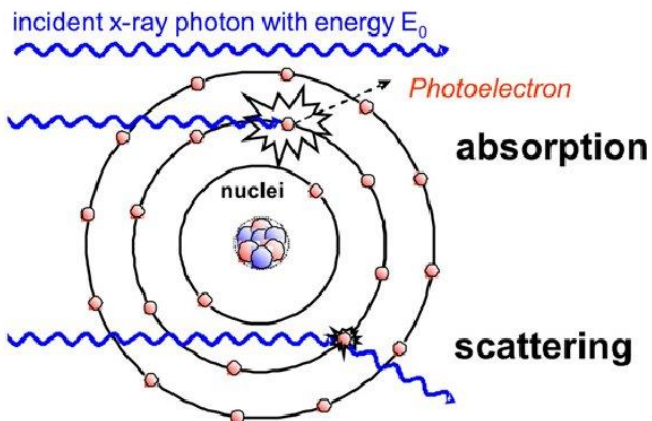
- I [3] $P4, 32(212)$
 II [2] $C4, 22(P4, 22, 95)$; [2] $I4, 22(98)$; [2] $P4, 2, 2(c' = \frac{1}{2}c)(94)$

Brief history of XRD

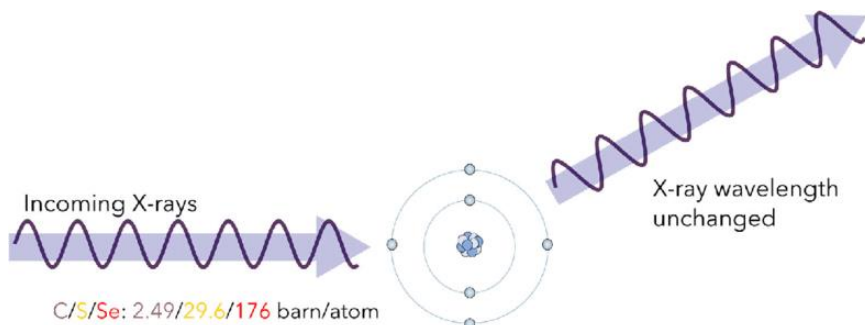
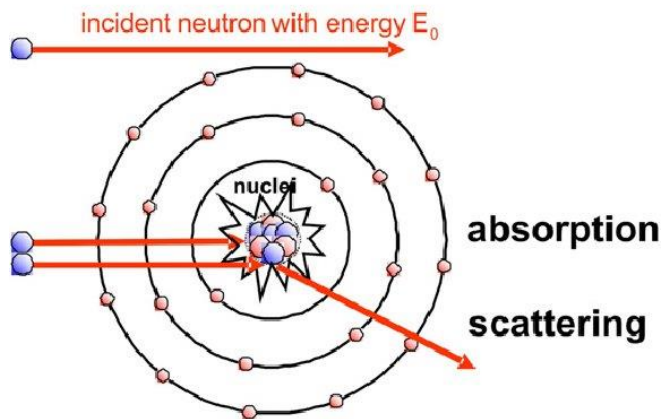
- 1895- Wilhelm Röntgen publishes the discovery of X-rays
- 1912- Maxwell von Laue observes diffraction of X-rays from a crystal
- 1913- Lawrence Bragg and William Henry Bragg solve the first crystal structure from X-ray diffraction data

Elastic scattering

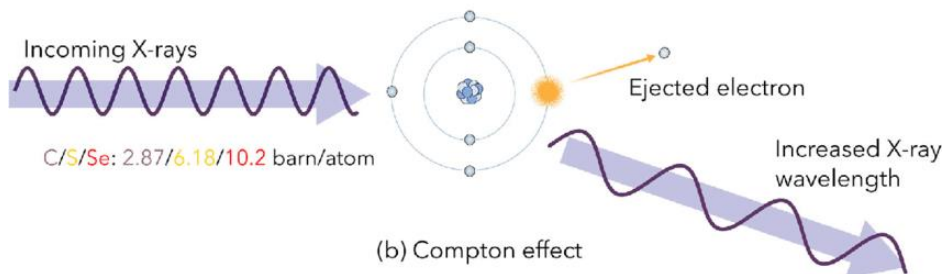
(a) X-rays



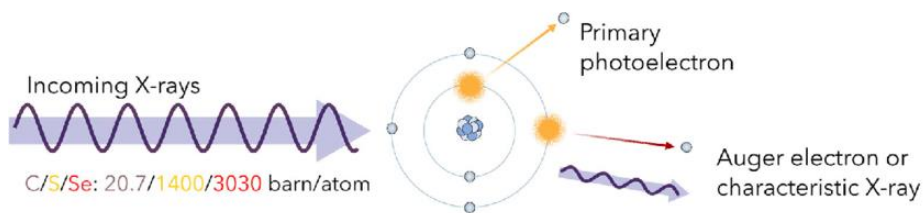
(b) neutrons



(a) Elastic scattering



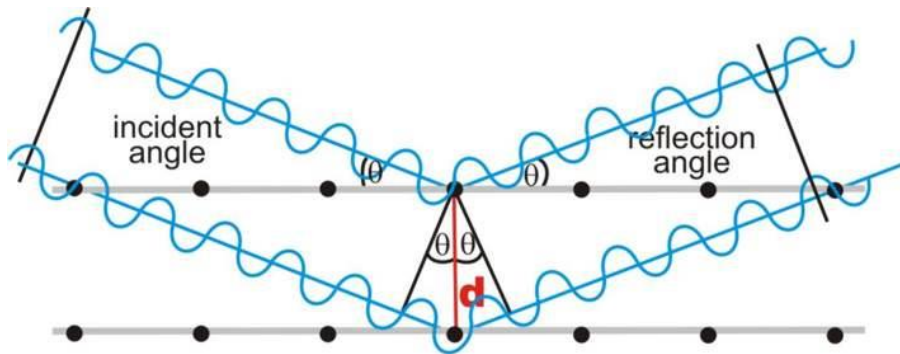
(b) Compton effect



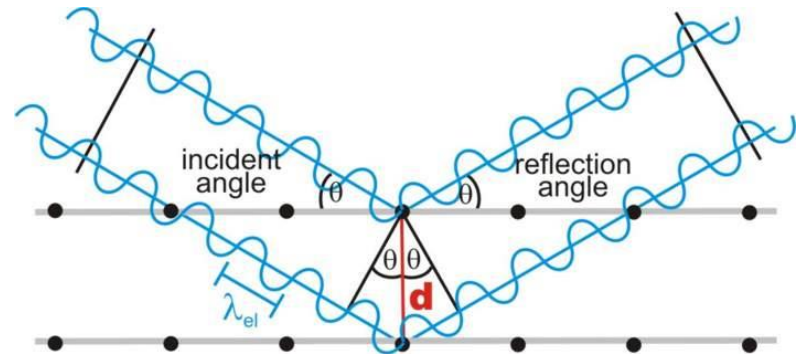
(c) Photoelectric effect

Bragg's Law

Elastic scattering phenomenon that occurs when a plane wave interacts with an obstacle or a slit whose size is approximately that of the wavelength



Destructive interference (out of phase).



Constructive interference (in phase).

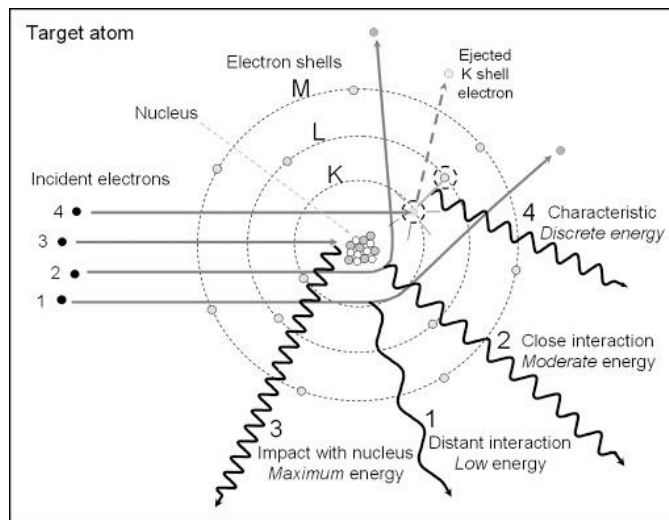
$$\text{Bragg's Law } n\lambda = 2d\sin\theta$$

X-ray light source

Particle accelerator (synchrotron source):
Electrons accelerated at velocity close to the speed of light emit electromagnetic radiation in the region of X-rays.

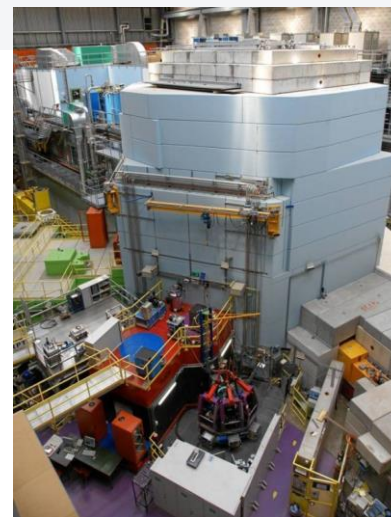
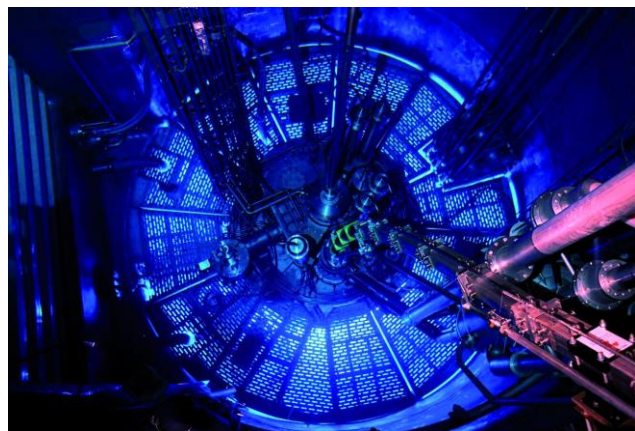
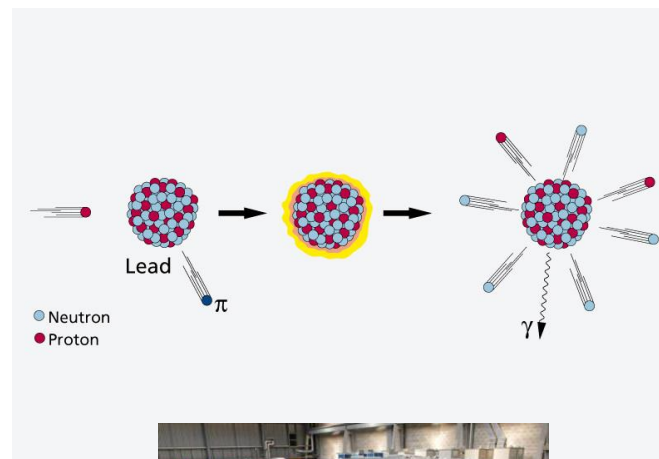
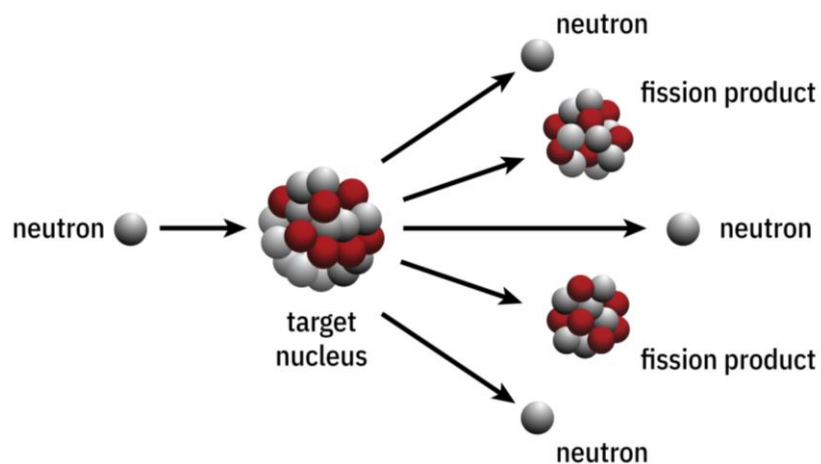
- Tunable wavelength
- High brilliance (many photons of a given wavelength and direction)
- X-rays: very high resolution

In-house diffraction: Energy released when an electron from an outer shell “fills the gap” left by an inner shell electron that has been ionized. $K\alpha$ Cu (1.5418 \AA) is the most common



Sources of neutrons

Neutrons for scattering experiments can be produced either by nuclear fission in a reactor (ILL Grenoble) or by spallation when high-energy protons strike a heavy metal target eg. W, Ta, or Pb (SINQ).

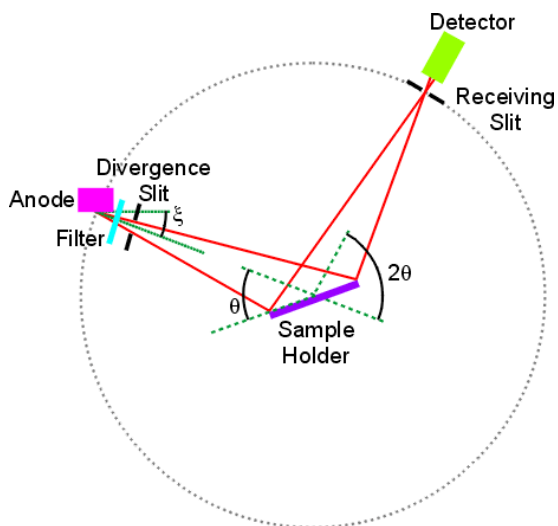


Comparison of different radiations

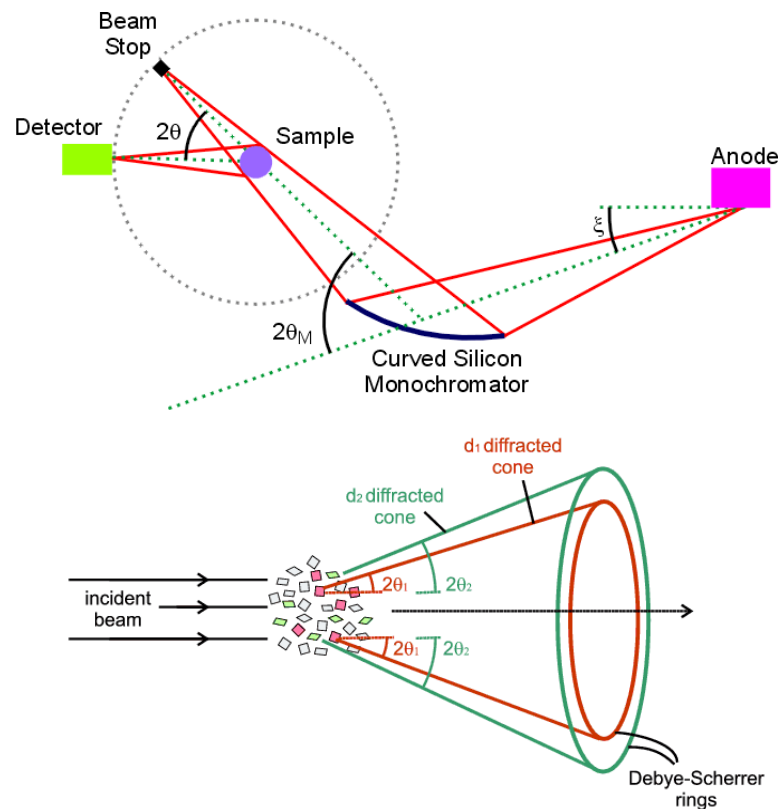
| | X-ray (powder) | Electrons | Neutrons (powder) |
|----------------------------|-------------------|-------------|----------------------|
| Data collection | easy | Less easy | difficult |
| Crystallite size | µm | nm | µm |
| Lattice parameters | precise | approximate | precise |
| Intensities | kinematical | dynamical | kinematical |
| Overlap | yes | no | yes |
| Image | no | yes | no |
| Magnetic moment | no | yes | yes |
| Scattering power against Z | smooth | smooth | irregular |

Diffraction geometry

The Bragg-Brentano (reflection) geometry needs the simultaneous, equiaxial move of the anode and the detector (2θ) to provide the constant irradiated volume from a sample



The Debye-Scherrer (transmission) geometry

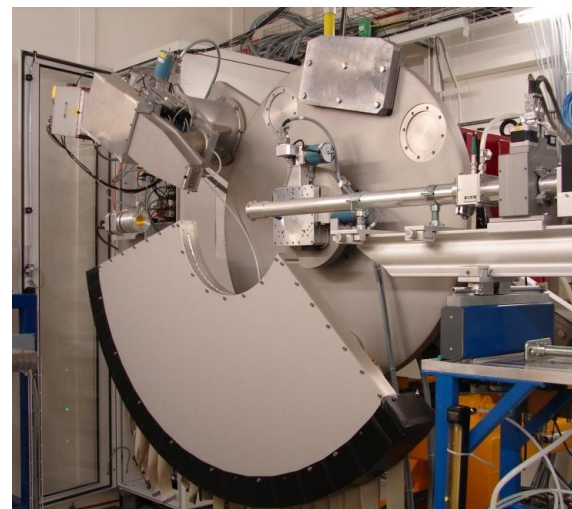


Diffraction geometry

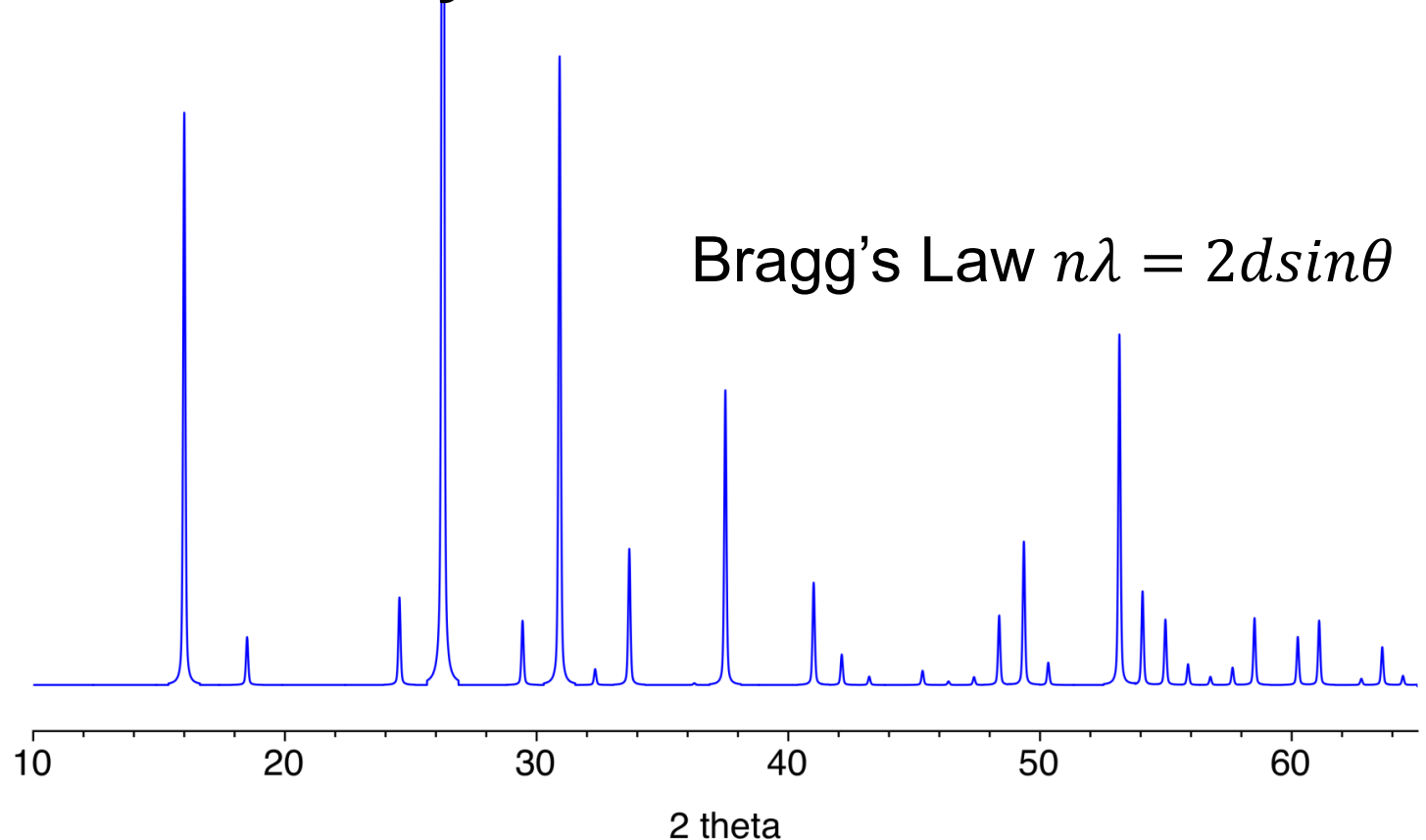
The Bragg-Brentano (reflection) geometry needs the simultaneous, equiaxial move of the anode and the detector (2θ) to provide the constant irradiated volume from a sample



The Debye-Scherrer (transmission) geometry



X-ray Powder Diffraction



Peak positions: lattice planes (unit cell, symmetry)

Peak intensities: atoms on the planes

Peak shape: microstructure (crystal size, microstrain, lattice defects)

Structure factor

$$F_{hkl} = \sum_j f_j \cdot e^{i2\pi(hx_j + ky_j + lz_j)} = |F_{hkl}| \cdot e^{i\phi_{hkl}}$$

Structure factor contains the amplitude and phase of the wave diffracted by each plane hkl

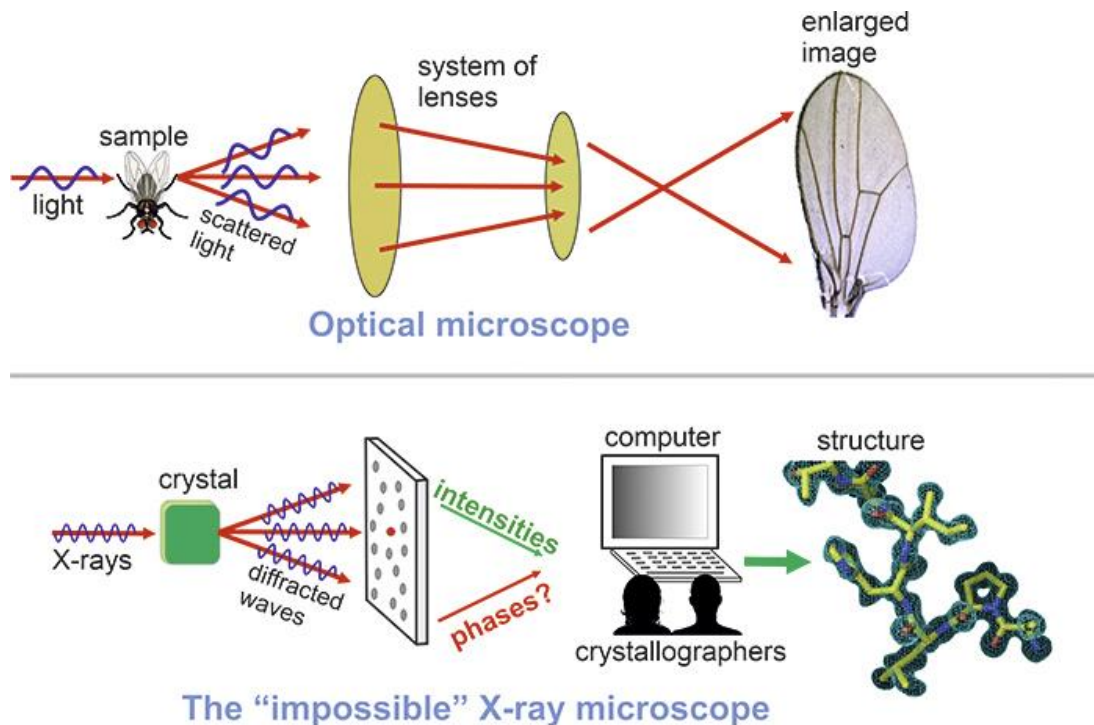
$$I_{\text{obs}}(hkl) = c j P L A |F_{\text{obs}}(hkl)|^2$$

- multiplicity, j
- the polarization factor, P
- the Lorentz factor, L
- X-ray absorption, A
- temperature

Structure factor

$$F_{hkl} = \sum_j f_j \cdot e^{i2\pi(hx_j + ky_j + lz_j)} = |F_{hkl}| \cdot e^{i\phi_{hkl}}$$

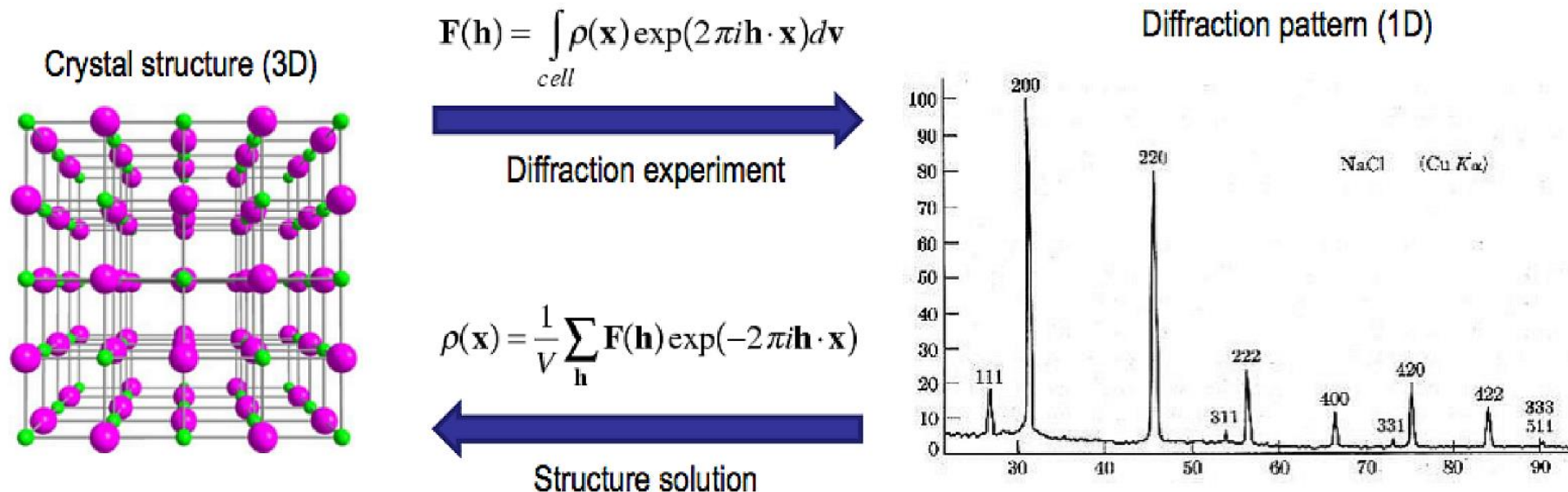
Structure factor phases are lost in diffraction data



Structure factor

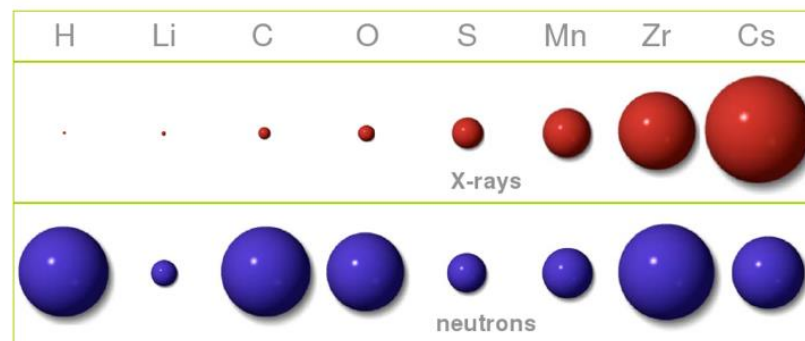
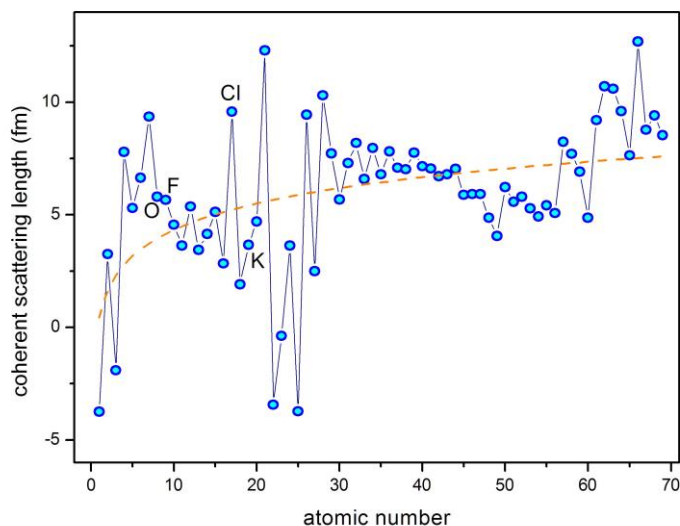
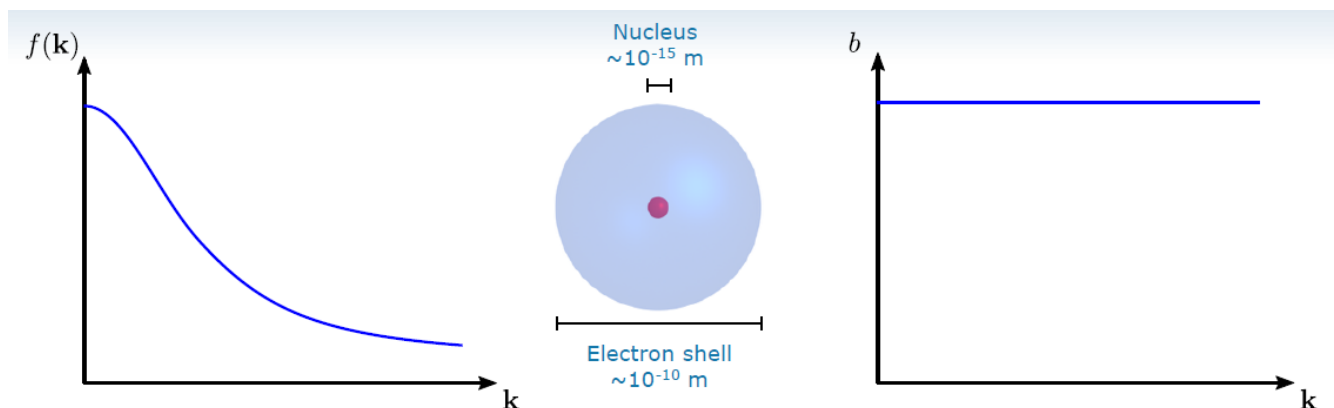
$$F_{hkl} = \sum_j f_j \cdot e^{i2\pi(hx_j + ky_j + lz_j)} = |F_{hkl}| \cdot e^{i\phi_{hkl}}$$

From the electron densities calculated from structure factor for each plane to measured intensities



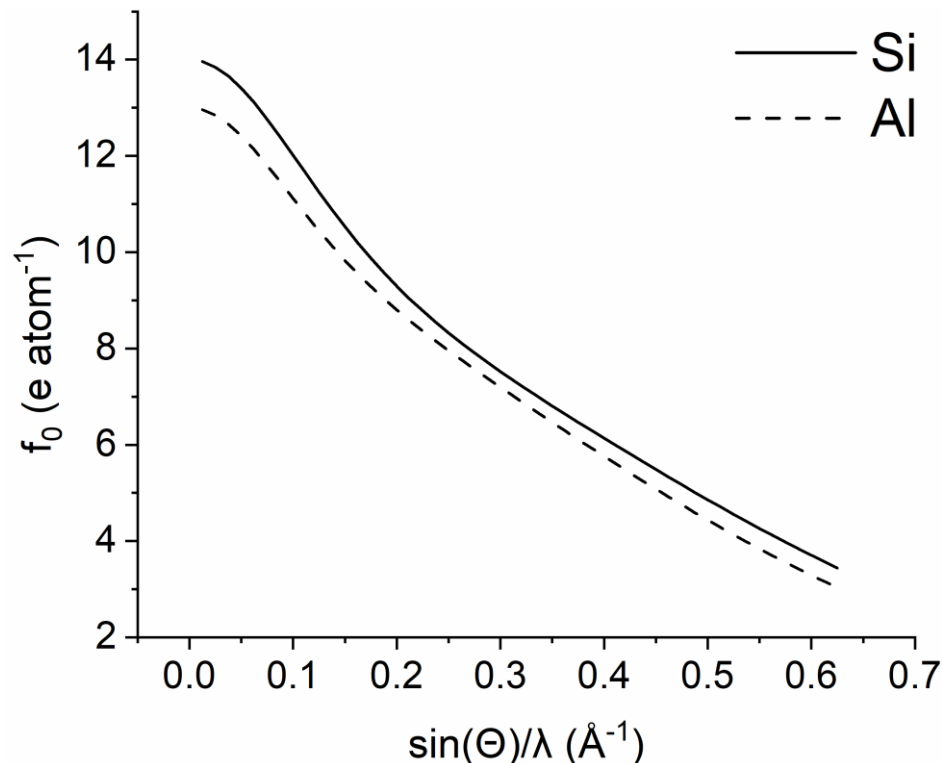
Scattering power of an element

The amplitude of the scattered wave is called the atomic form factor f (X-rays) or scattering length b (neutrons).



X-ray Atomic Form Factor

Atomic form factor represents the scattering power of specific element regardless its positioning or symmetry. It depends only on number of electrons, radiation energy and Debye-Waller factor (2Θ)



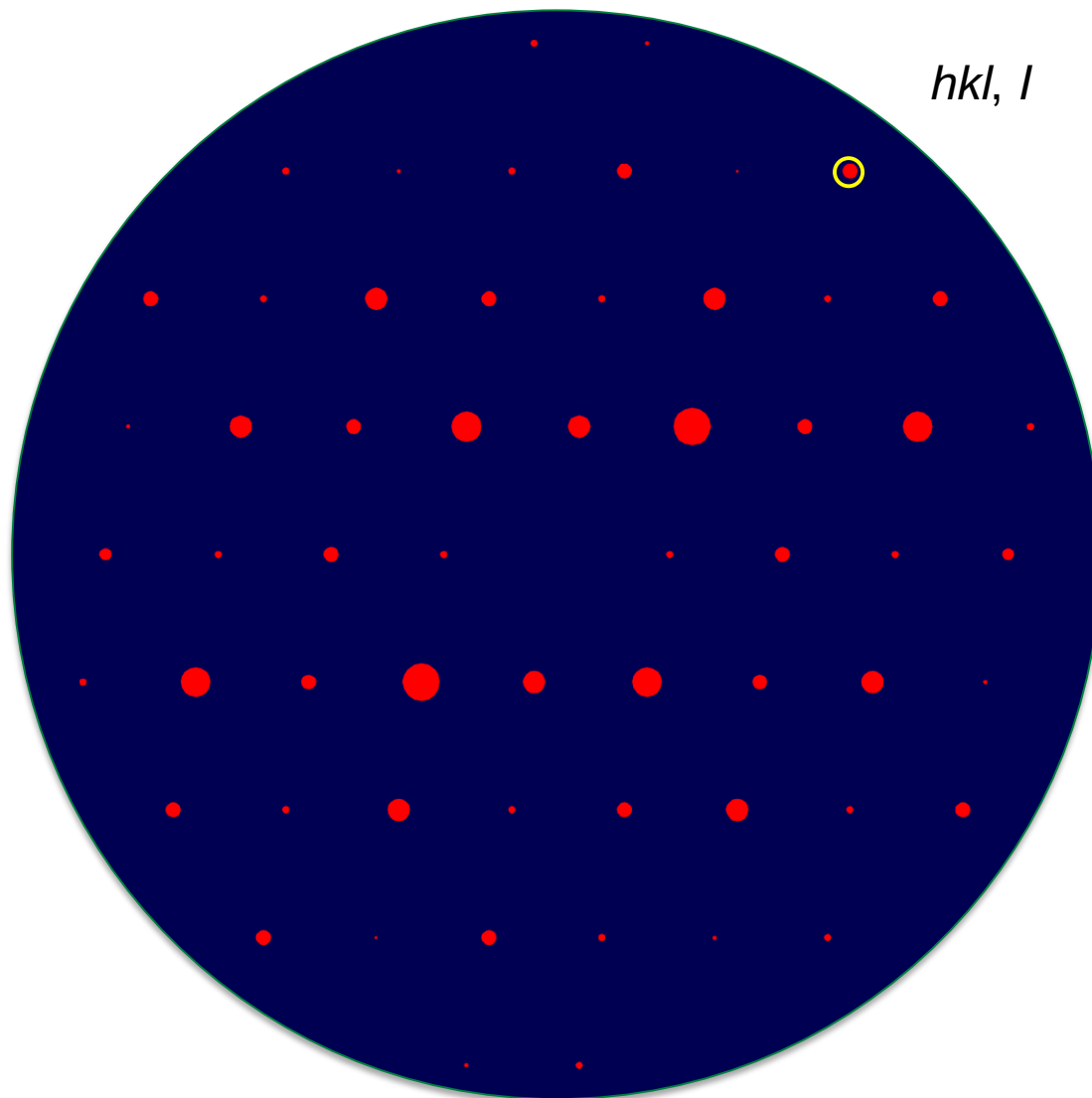
Silicon and aluminum demonstrate similar atomic number ($Z=14$ and 13) and are difficult to be distinguished

X-ray Single-crystal Diffraction

X-rays



$10^6 \mu\text{m}^3$

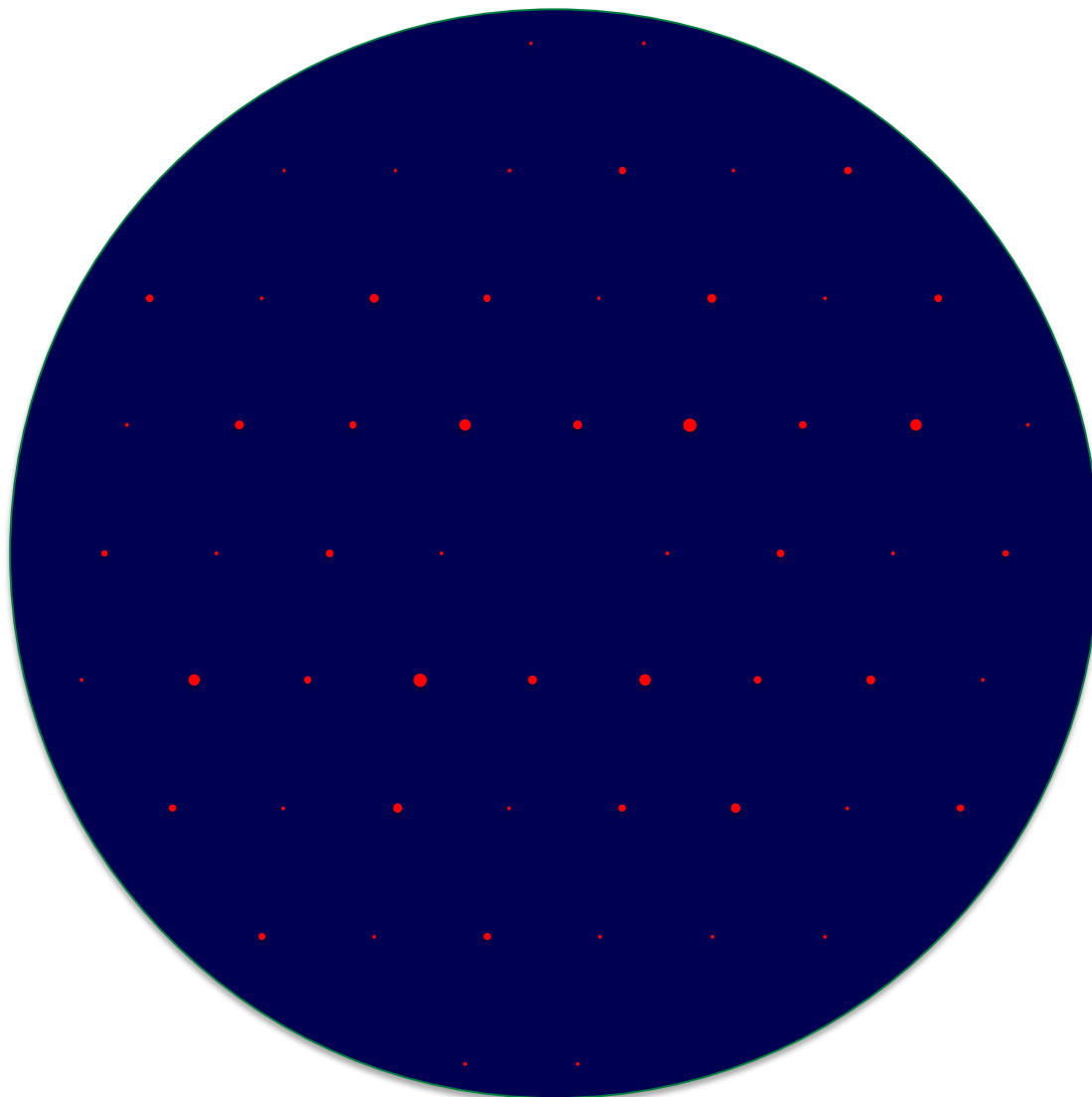


X-ray Powder Diffraction

X-rays

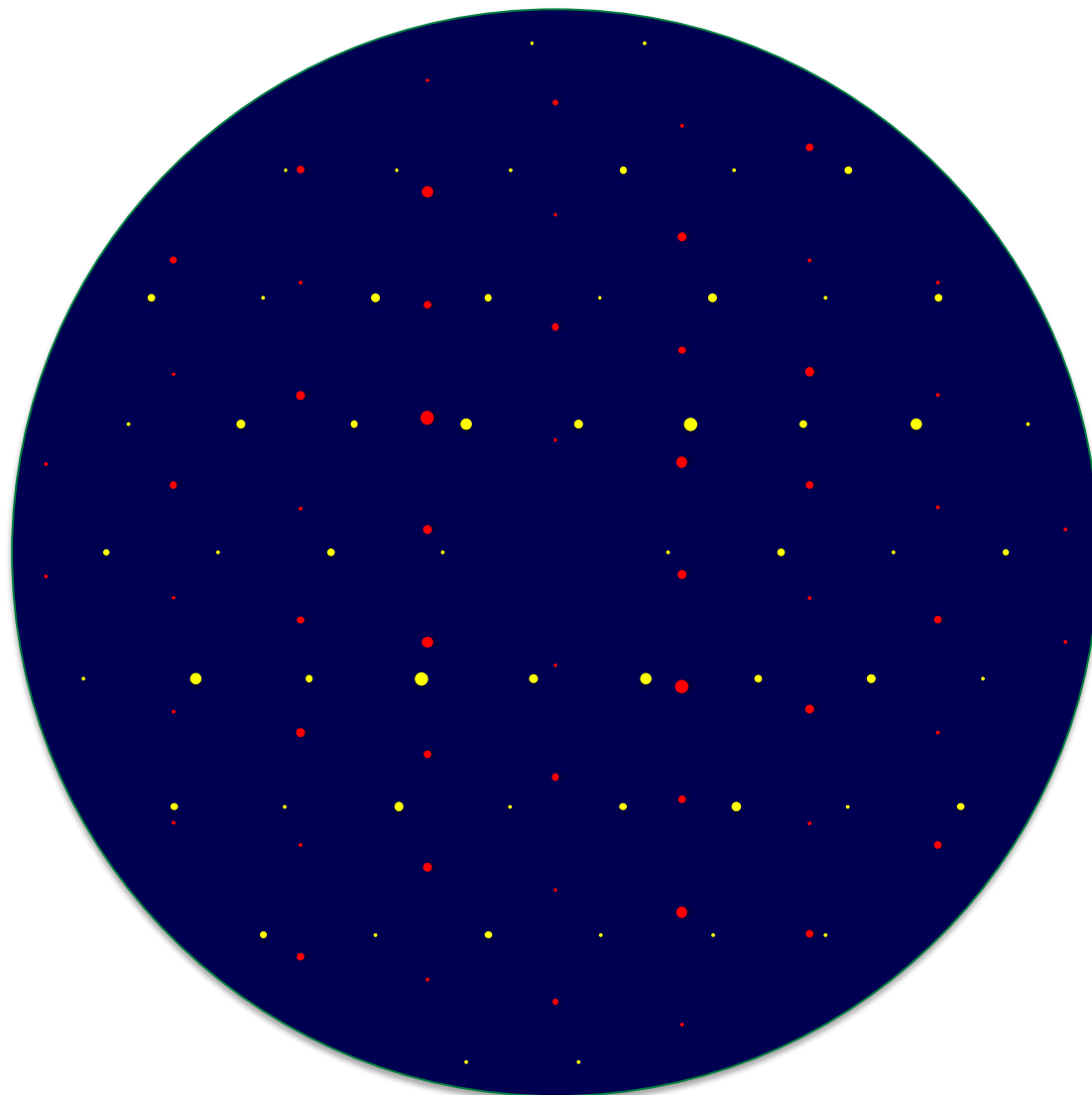


$1 \mu\text{m}^3$



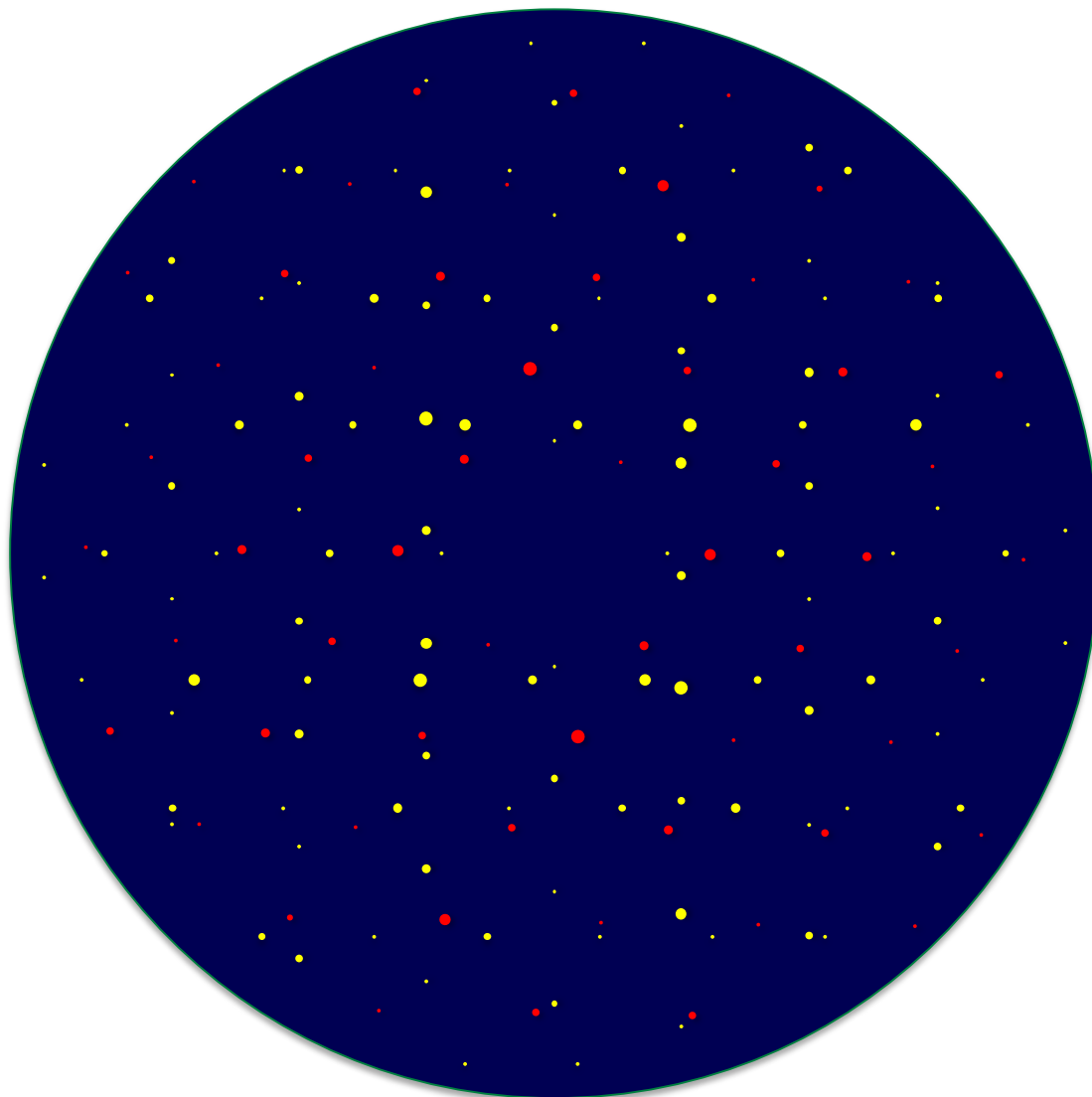
X-ray Powder Diffraction

X-rays



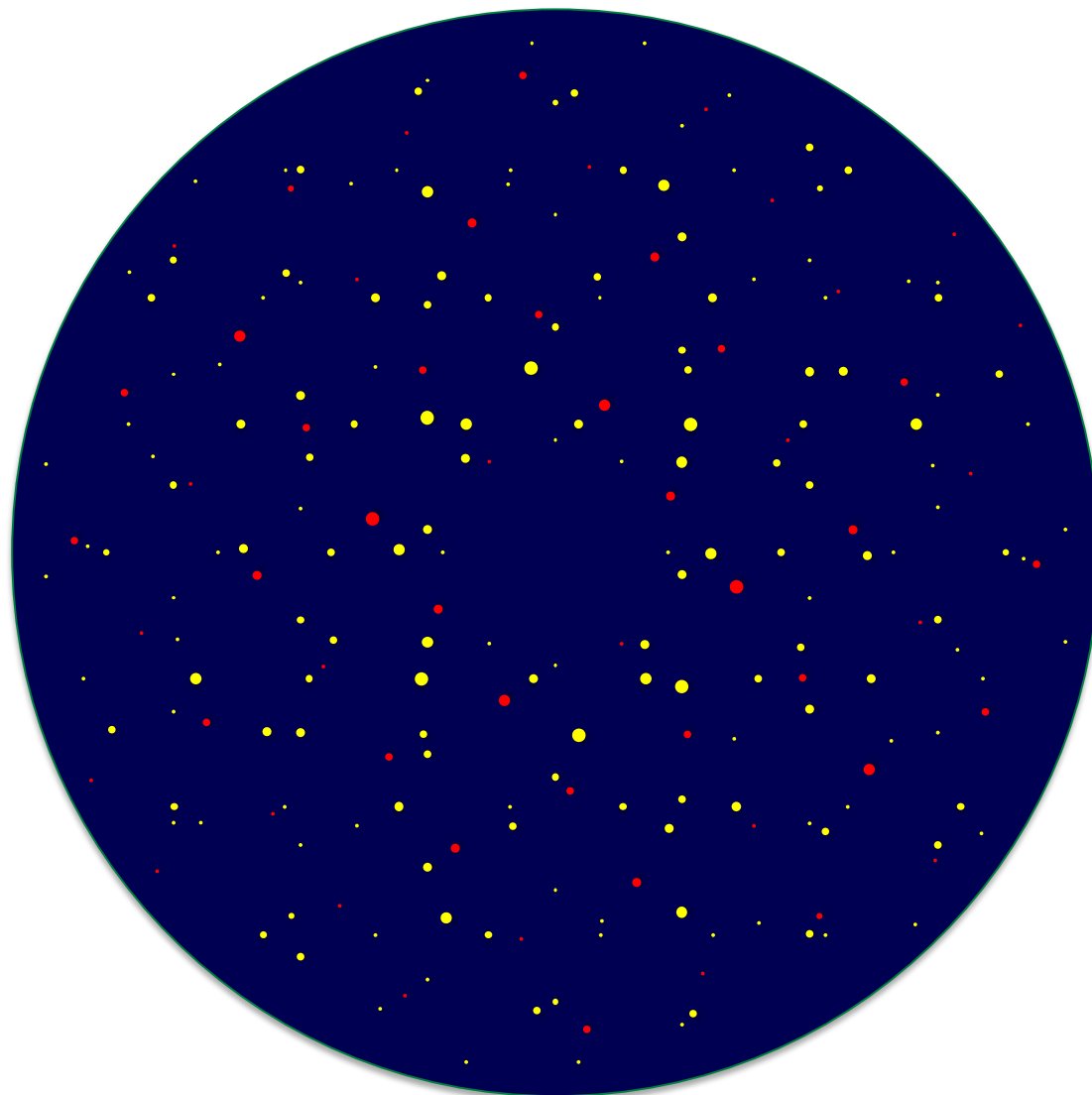
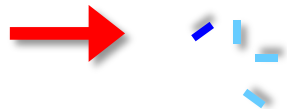
X-ray Powder Diffraction

X-rays



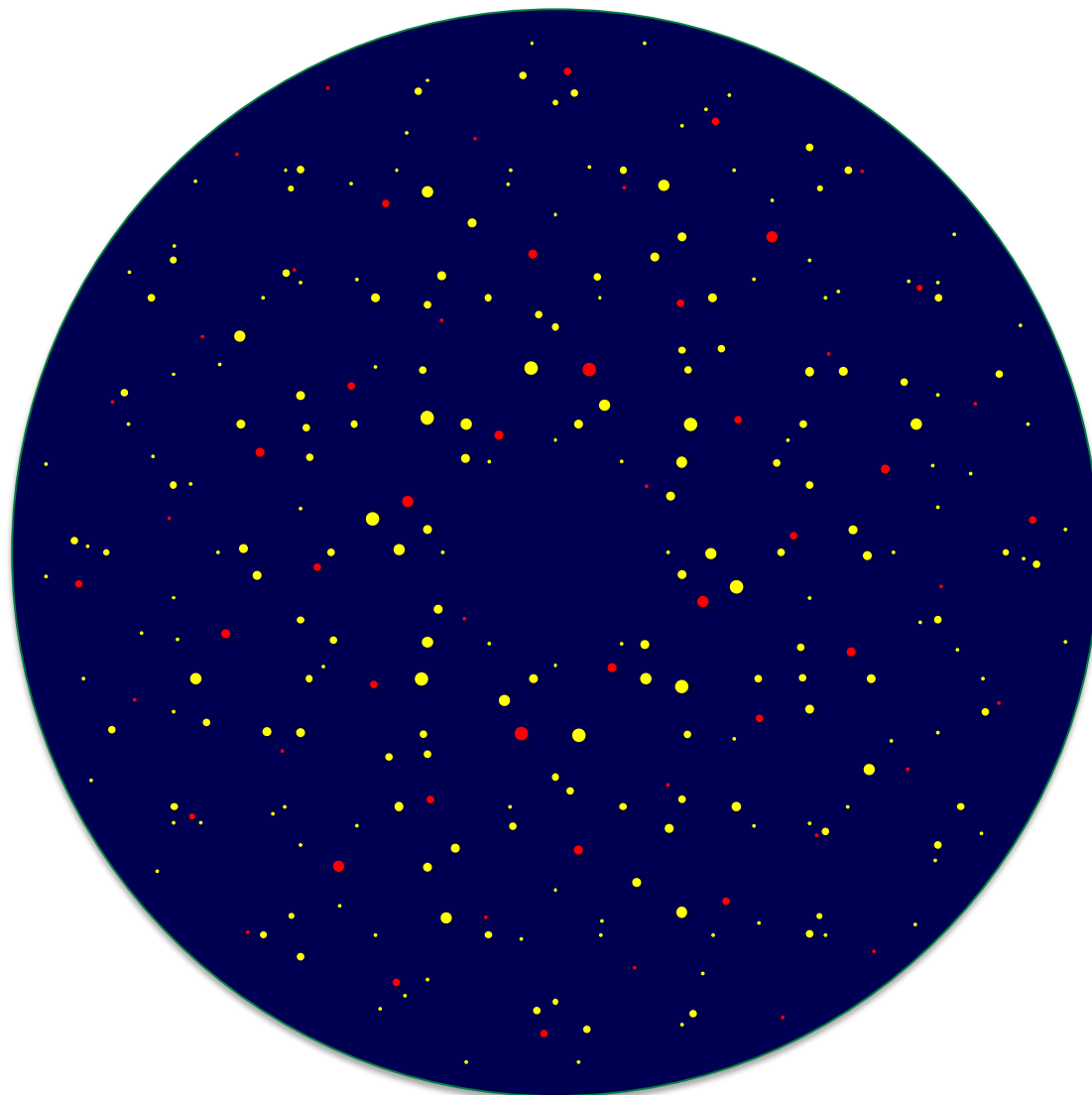
X-ray Powder Diffraction

X-rays



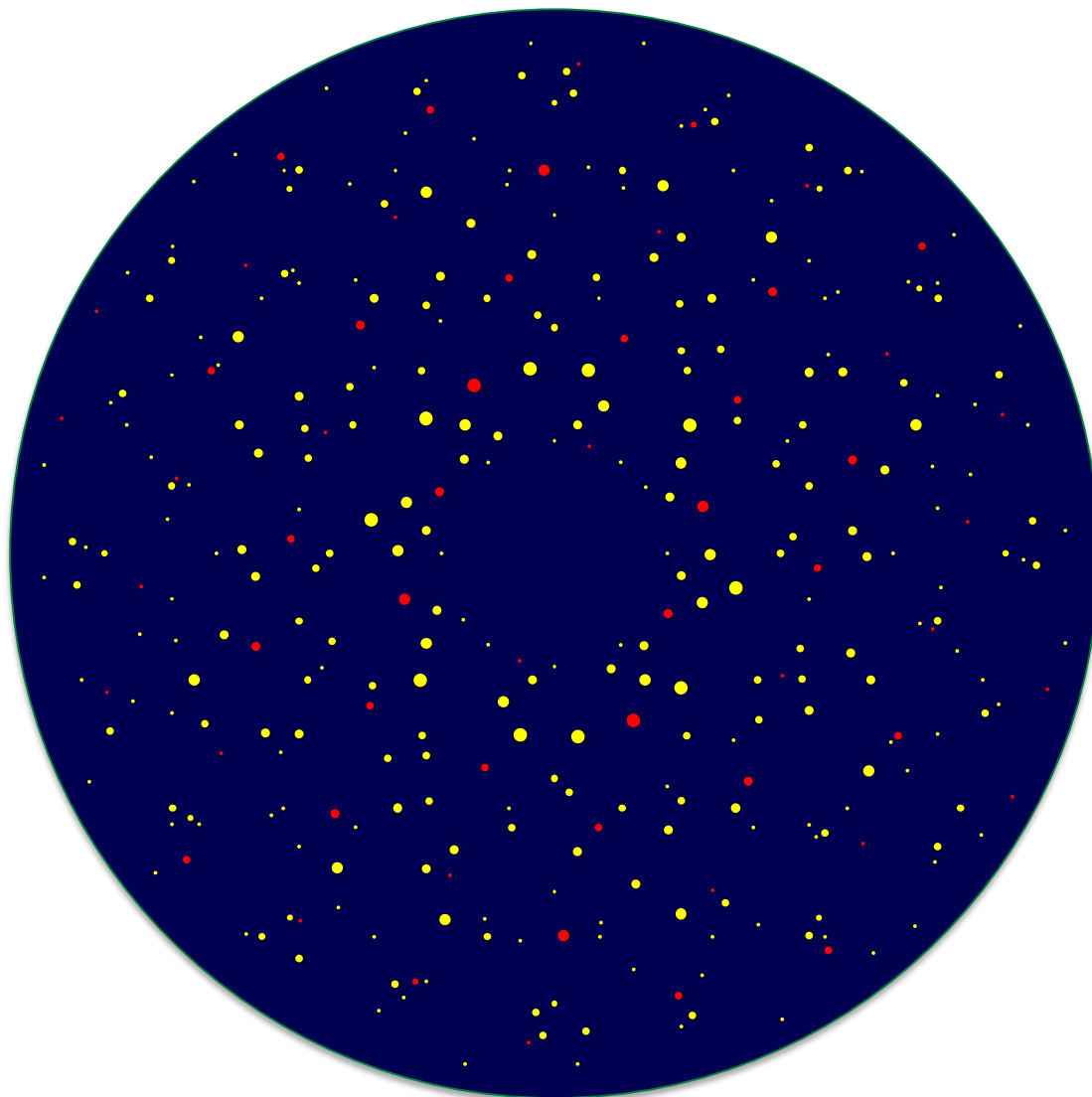
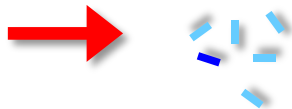
X-ray Powder Diffraction

X-rays



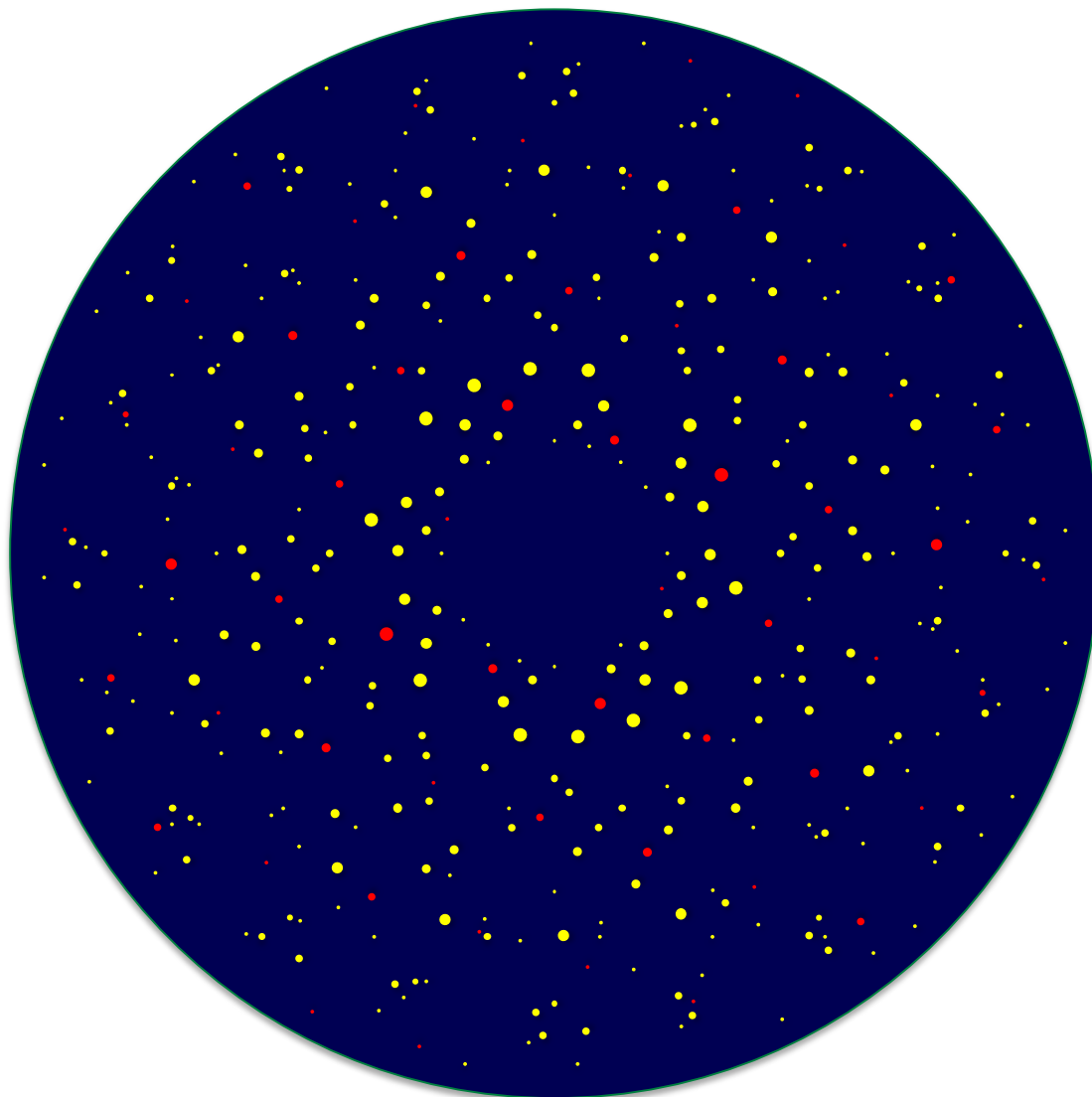
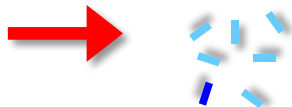
X-ray Powder Diffraction

X-rays



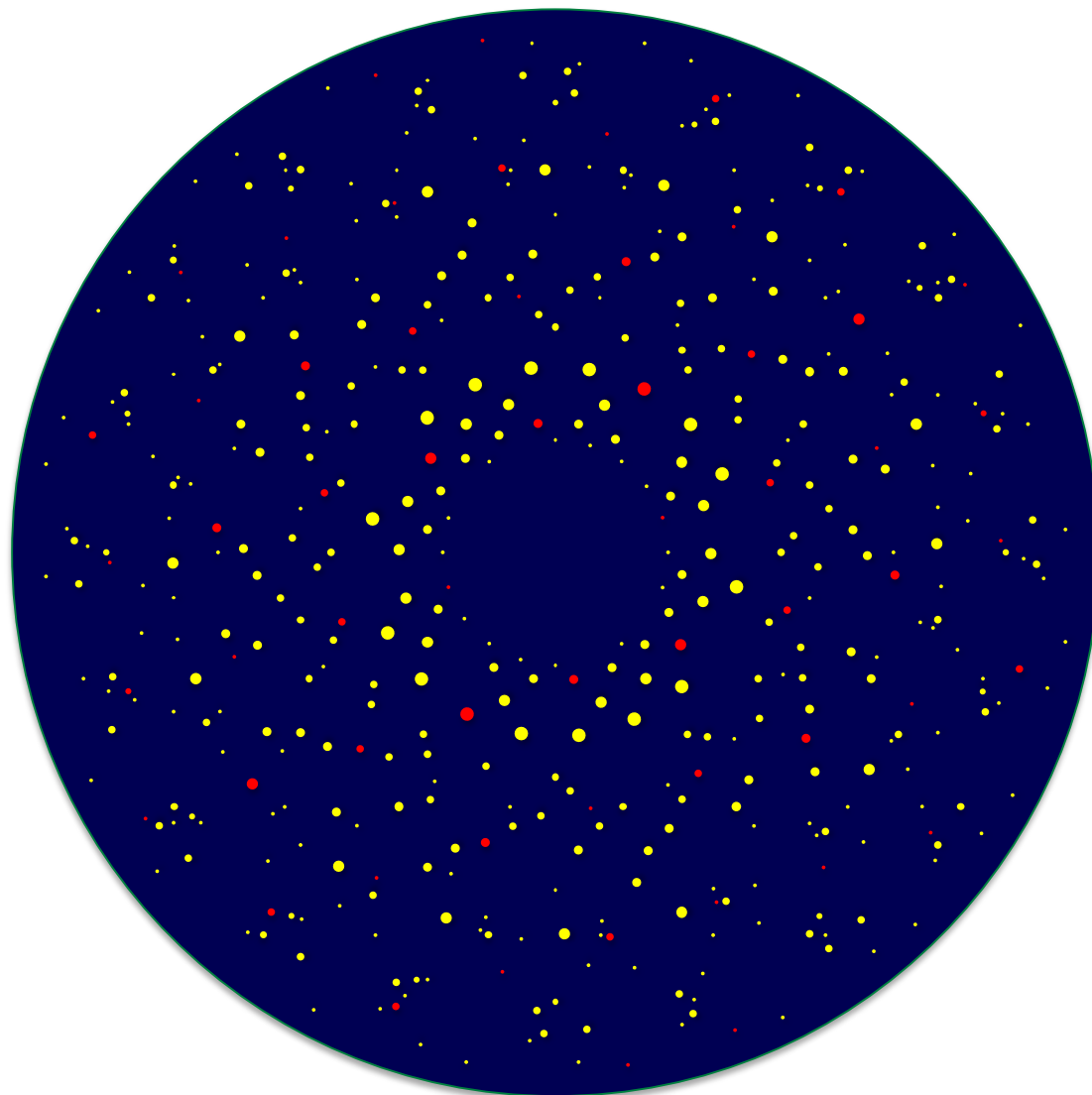
X-ray Powder Diffraction

X-rays



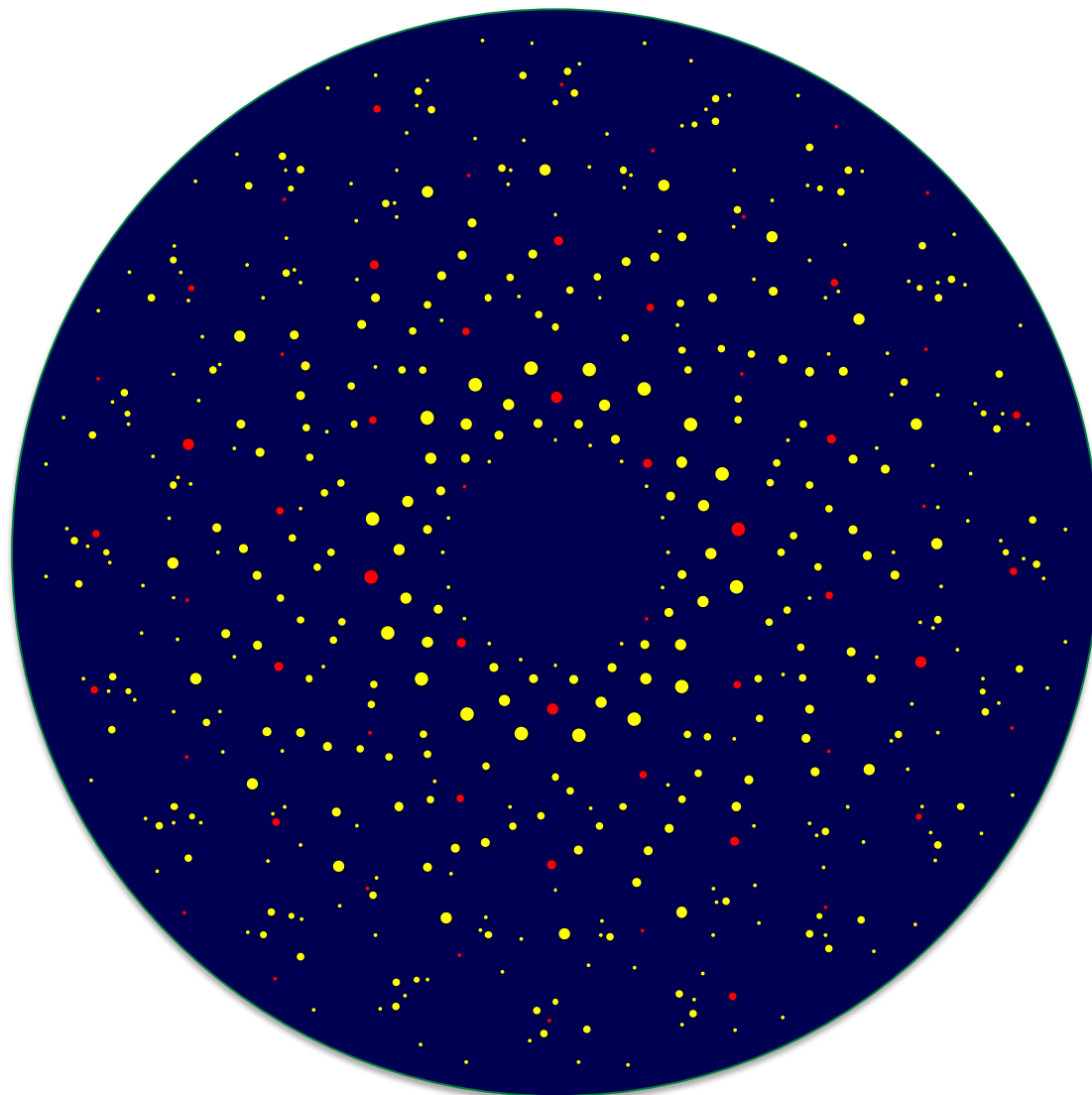
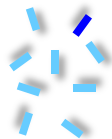
X-ray Powder Diffraction

X-rays



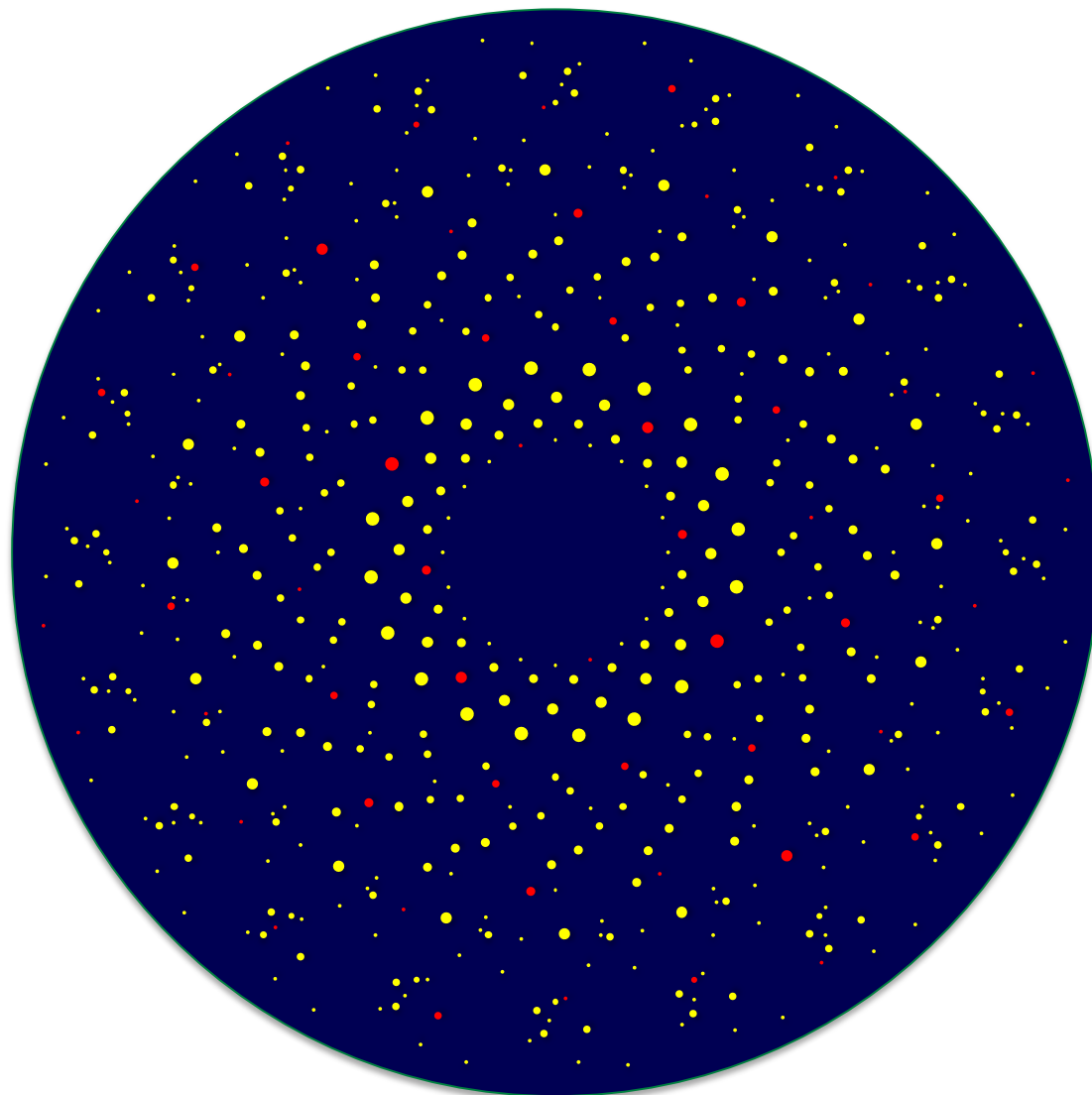
X-ray Powder Diffraction

X-rays



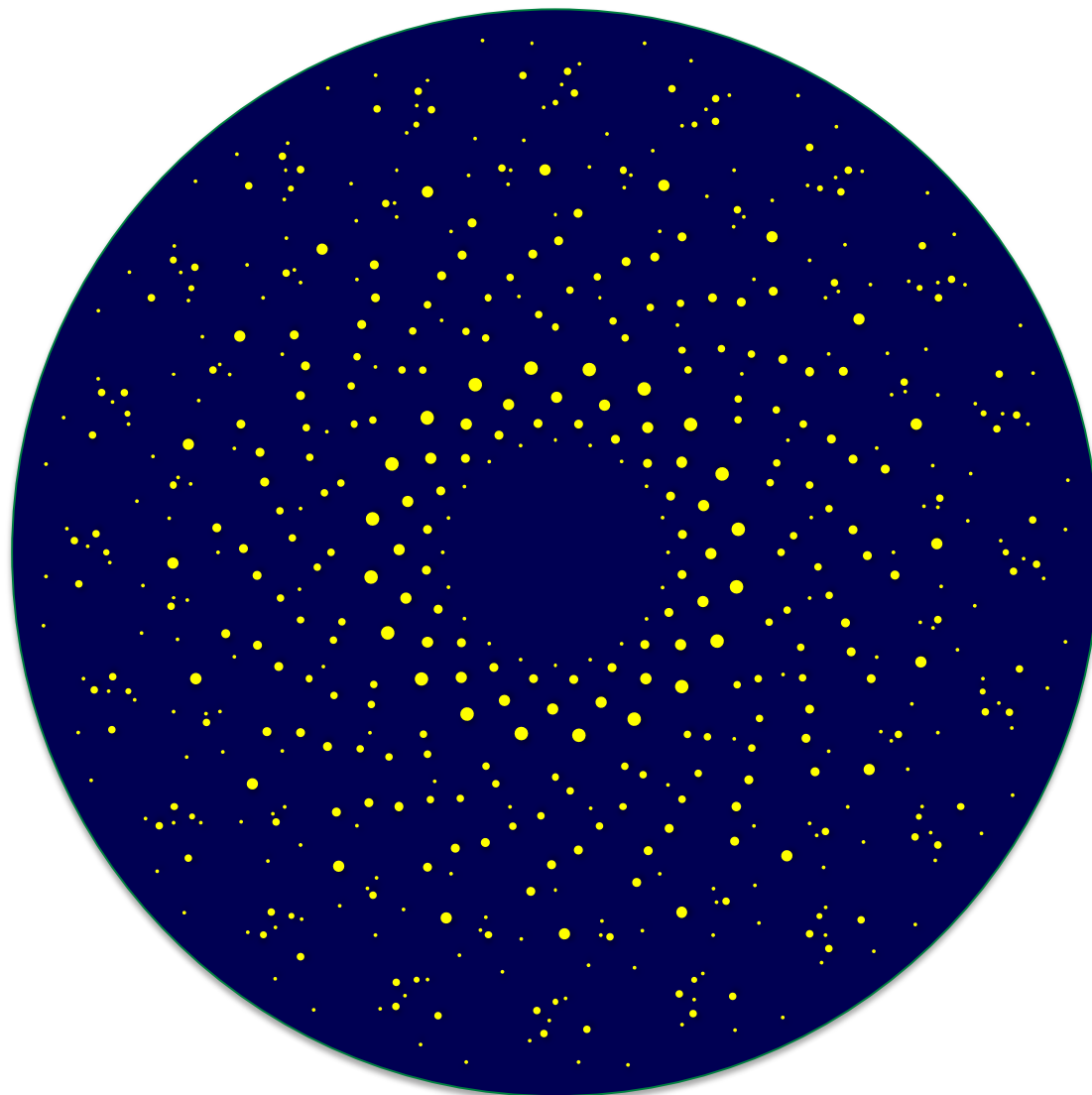
X-ray Powder Diffraction

X-rays



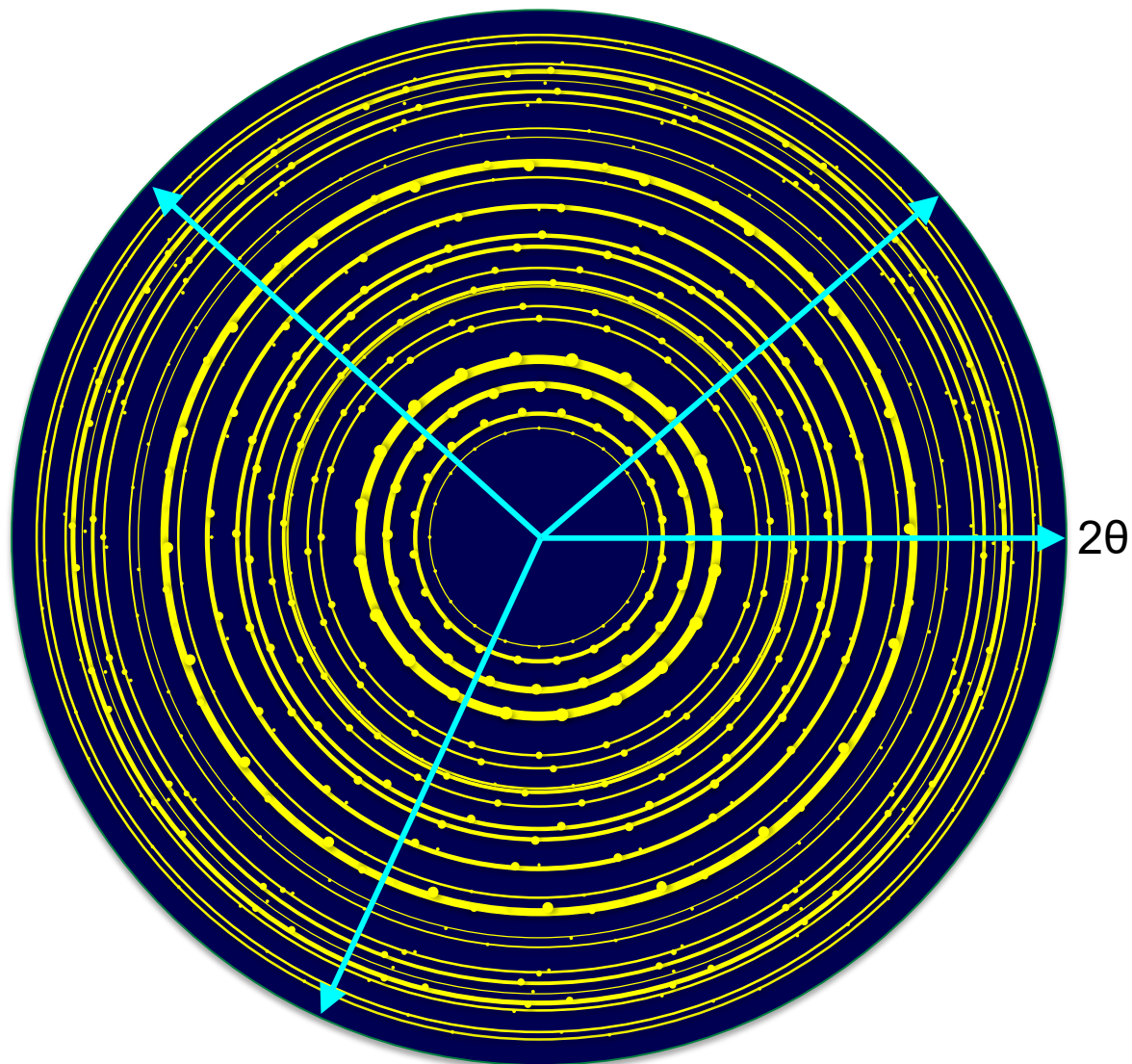
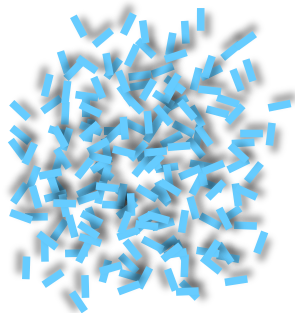
X-ray Powder Diffraction

X-rays

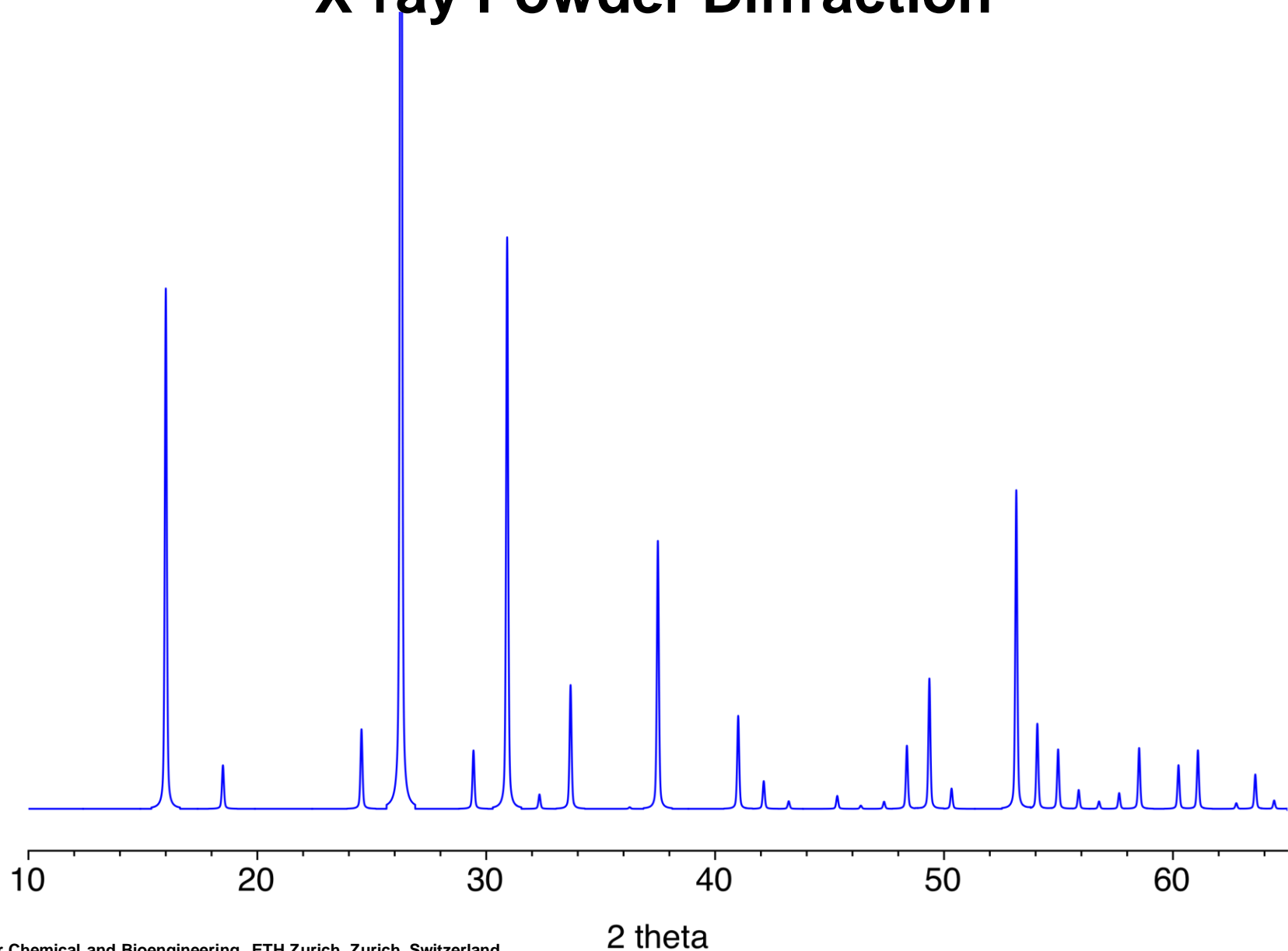


X-ray Powder Diffraction

X-rays



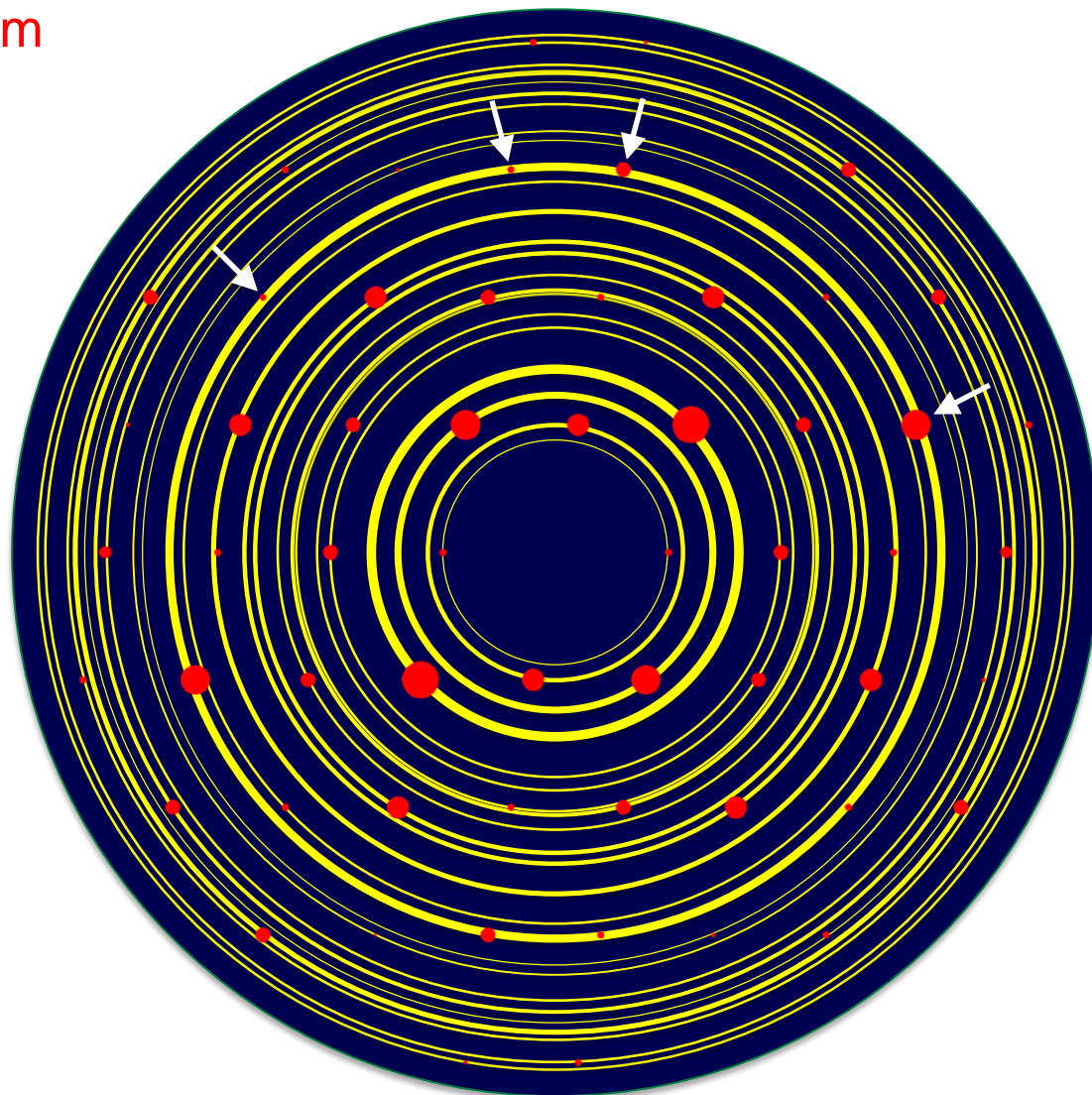
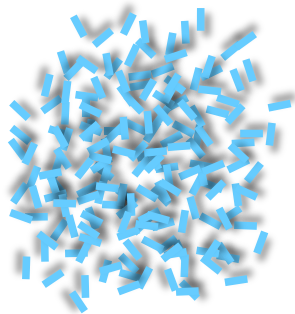
X-ray Powder Diffraction



X-ray Powder Diffraction

Reflection Overlap Problem

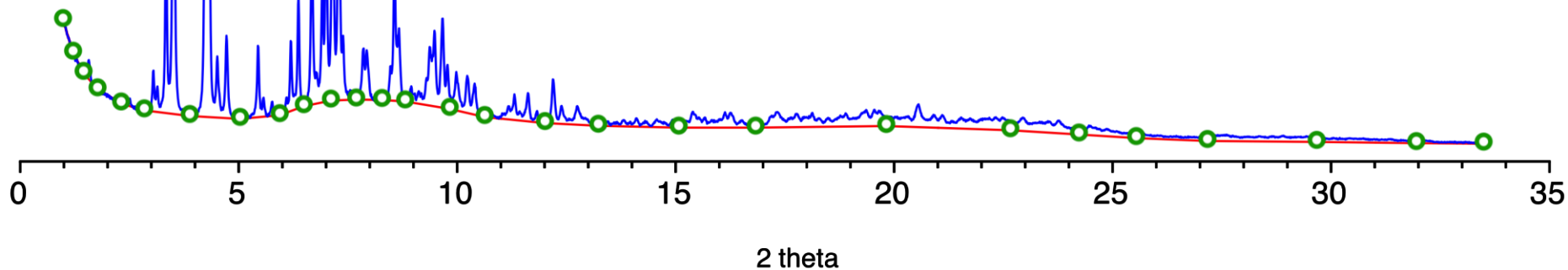
X-rays



Indexing an XPD Pattern

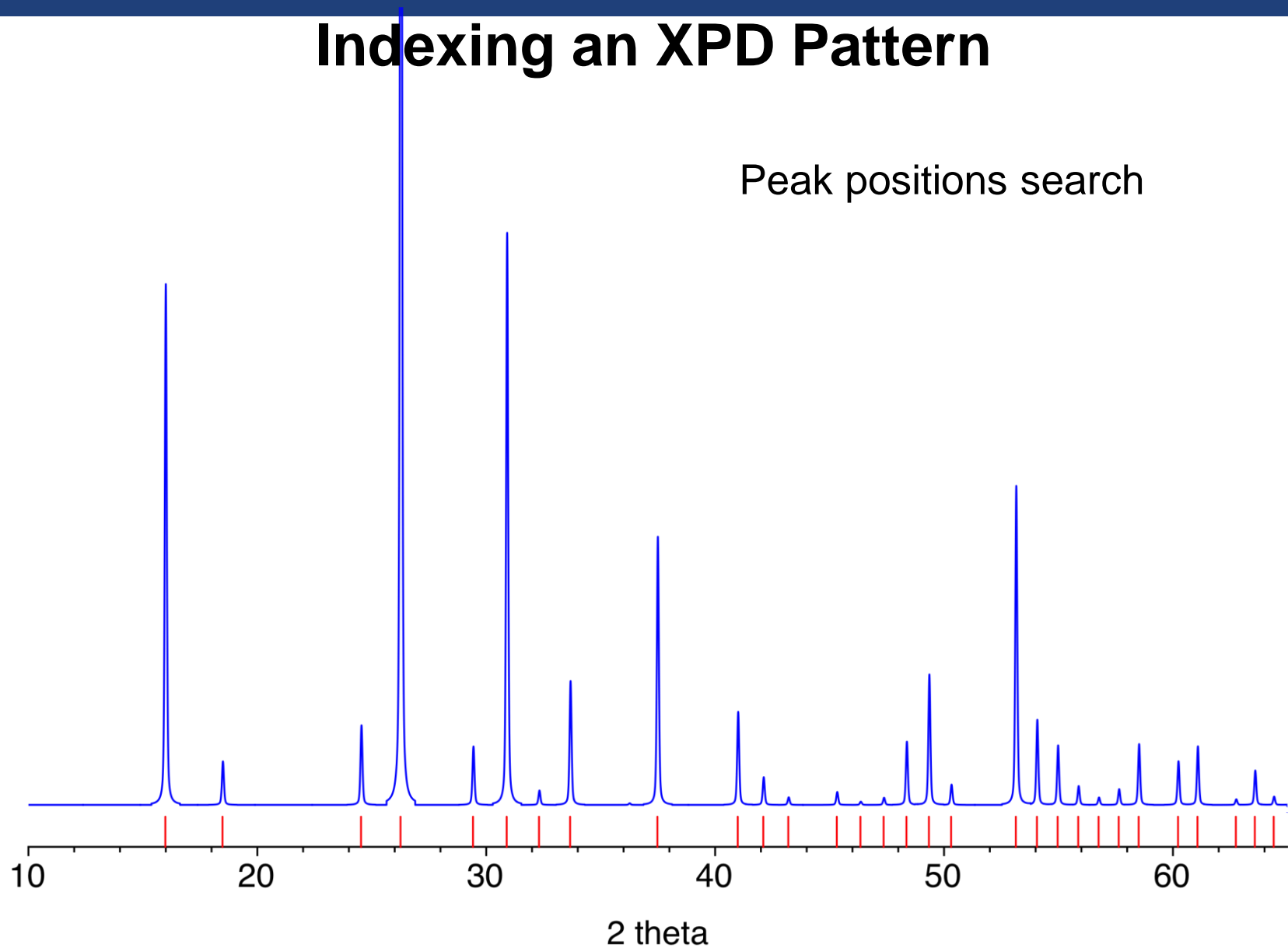
The determination of the background

- Assume flat background
- Measure an empty sample holder
- Estimate points and interpolate between them
- Fit a function



Indexing an XPD Pattern

Peak positions search



Indexing an XPD Pattern

Relationship between 2θ and d -spacing

Bragg's Law $\lambda = 2d_{hkl} \sin\theta_{hkl}$

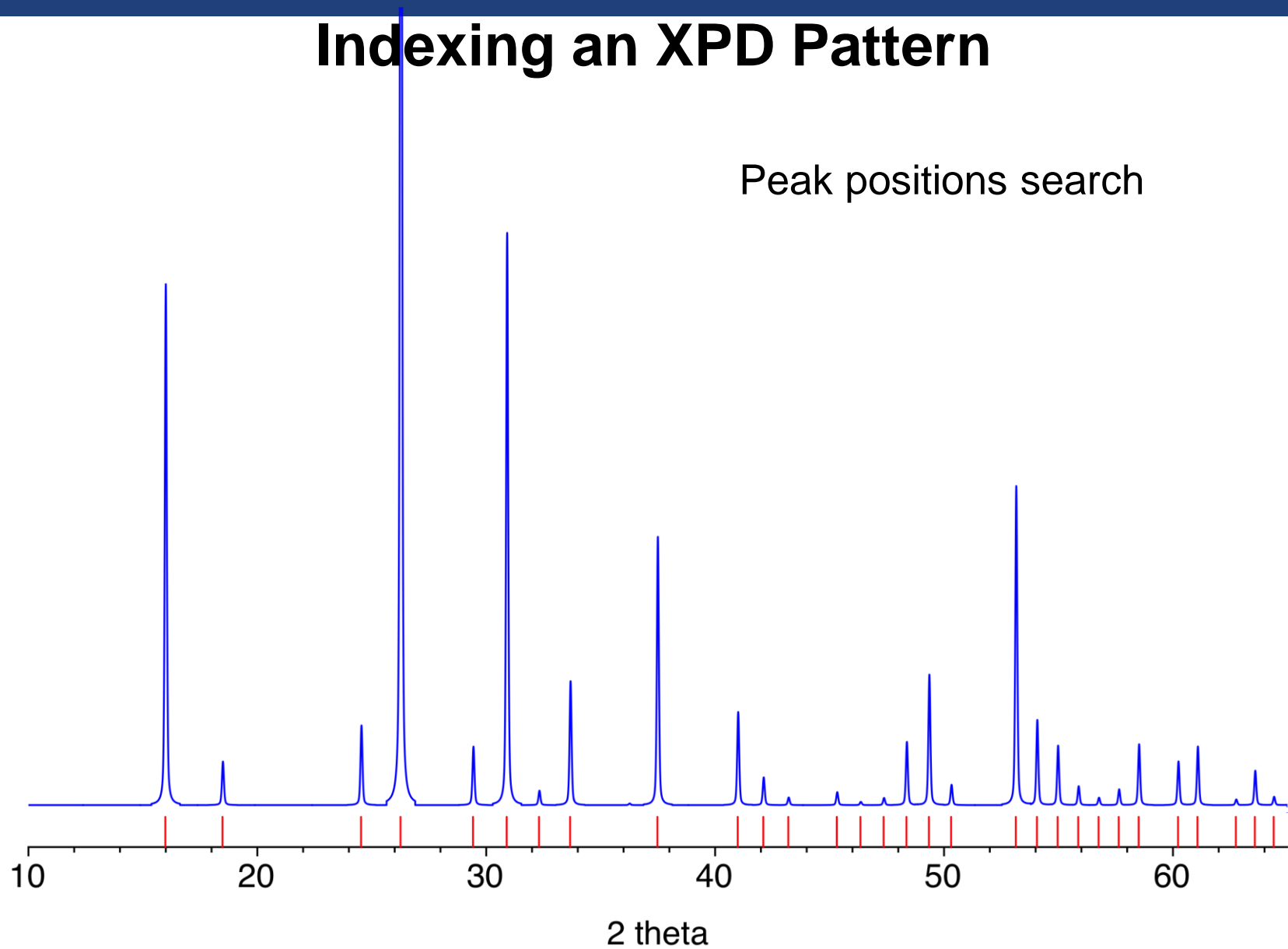
$$d_{hkl} = \frac{\lambda}{2 \sin\theta_{hkl}}$$

Relationship between d -spacing and lattice parameters

Cubic example $d_{hkl}^2 = \frac{a^2}{h^2 + k^2 + l^2}$

Indexing an XPD Pattern

Peak positions search



Indexing an XPD Pattern

$$d_{hkl}^2 = \frac{\lambda^2}{4 \sin^2 \theta_{hkl}} = \frac{a^2}{h^2 + k^2 + l^2} \quad \rightarrow \quad \sin^2 \theta_{hkl} = \left(\frac{\lambda^2}{4a^2} \right) (h^2 + k^2 + l^2)$$

Indexing an XPD Pattern

$$d_{hkl}^2 = \frac{\lambda^2}{4 \sin^2 \theta_{hkl}} = \frac{a^2}{h^2 + k^2 + l^2} \quad \rightarrow \quad \sin^2 \theta_{hkl} = \left(\frac{\lambda^2}{4a^2} \right) (h^2 + k^2 + l^2)$$

| |
|--------|
| 20 (°) |
| 16.00 |
| 18.50 |
| 24.55 |
| 26.28 |
| 29.44 |
| 30.91 |
| 32.33 |
| 33.68 |
| 37.50 |
| 41.01 |
| 42.12 |
| 43.22 |
| 45.34 |

Indexing an XPD Pattern

$$d_{hkl}^2 = \frac{\lambda^2}{4 \sin^2 \theta_{hkl}} = \frac{a^2}{h^2 + k^2 + l^2} \quad \rightarrow \quad \sin^2 \theta_{hkl} = \left(\frac{\lambda^2}{4a^2} \right) (h^2 + k^2 + l^2)$$

| 2θ (°) | $\sin^2\theta$ |
|---------------|----------------|
| 16.00 | 0.01937 |
| 18.50 | 0.02583 |
| 24.55 | 0.04520 |
| 26.28 | 0.05166 |
| 29.44 | 0.06457 |
| 30.91 | 0.07103 |
| 32.33 | 0.07749 |
| 33.68 | 0.08395 |
| 37.50 | 0.10332 |
| 41.01 | 0.12269 |
| 42.12 | 0.12915 |
| 43.22 | 0.13561 |
| 45.34 | 0.14852 |

$$\frac{\sin^2 \theta_2}{\sin^2 \theta_1} = \frac{(h_2^2 + k_2^2 + l_2^2)}{(h_1^2 + k_1^2 + l_1^2)}$$

Indexing an XPD Pattern

$$d_{hkl}^2 = \frac{\lambda^2}{4 \sin^2 \theta_{hkl}} = \frac{a^2}{h^2 + k^2 + l^2} \quad \rightarrow \quad \sin^2 \theta_{hkl} = \left(\frac{\lambda^2}{4a^2} \right) (h^2 + k^2 + l^2)$$

| 2θ (°) | $\sin^2\theta$ | ratio |
|---------------|----------------|-------|
| 16.00 | 0.01937 | 1.00 |
| 18.50 | 0.02583 | 1.33 |
| 24.55 | 0.04520 | 2.33 |
| 26.28 | 0.05166 | 2.67 |
| 29.44 | 0.06457 | 3.33 |
| 30.91 | 0.07103 | 3.66 |
| 32.33 | 0.07749 | 4.00 |
| 33.68 | 0.08395 | 4.33 |
| 37.50 | 0.10332 | 5.33 |
| 41.01 | 0.12269 | 6.33 |
| 42.12 | 0.12915 | 6.67 |
| 43.22 | 0.13561 | 7.00 |
| 45.34 | 0.14852 | 7.66 |

Indexing an XPD Pattern

$$d_{hkl}^2 = \frac{\lambda^2}{4 \sin^2 \theta_{hkl}} = \frac{a^2}{h^2 + k^2 + l^2} \quad \rightarrow \quad \sin^2 \theta_{hkl} = \left(\frac{\lambda^2}{4a^2} \right) (h^2 + k^2 + l^2)$$

| 2θ (°) | $\sin^2\theta$ | ratio | integers |
|---------------|----------------|-------|----------|
| 16.00 | 0.01937 | 1.00 | 3 |
| 18.50 | 0.02583 | 1.33 | 4 |
| 24.55 | 0.04520 | 2.33 | 7 |
| 26.28 | 0.05166 | 2.67 | 8 |
| 29.44 | 0.06457 | 3.33 | 10 |
| 30.91 | 0.07103 | 3.66 | 11 |
| 32.33 | 0.07749 | 4.00 | 12 |
| 33.68 | 0.08395 | 4.33 | 13 |
| 37.50 | 0.10332 | 5.33 | 16 |
| 41.01 | 0.12269 | 6.33 | 19 |
| 42.12 | 0.12915 | 6.67 | 20 |
| 43.22 | 0.13561 | 7.00 | 21 |
| 45.34 | 0.14852 | 7.66 | 23 |

Indexing an XPD Pattern

$$d_{hkl}^2 = \frac{\lambda^2}{4 \sin^2 \theta_{hkl}} = \frac{a^2}{h^2 + k^2 + l^2} \quad \rightarrow \quad \sin^2 \theta_{hkl} = \left(\frac{\lambda^2}{4a^2} \right) (h^2 + k^2 + l^2)$$

| 2θ (°) | $\sin^2\theta$ | ratio | integers | $h^2 + k^2 + l^2$ |
|---------------|----------------|-------|----------|-------------------|
| 16.00 | 0.01937 | 1.00 | 3 | 6 |
| 18.50 | 0.02583 | 1.33 | 4 | 8 |
| 24.55 | 0.04520 | 2.33 | 7 | 14 |
| 26.28 | 0.05166 | 2.67 | 8 | 16 |
| 29.44 | 0.06457 | 3.33 | 10 | 20 |
| 30.91 | 0.07103 | 3.66 | 11 | 22 |
| 32.33 | 0.07749 | 4.00 | 12 | 24 |
| 33.68 | 0.08395 | 4.33 | 13 | 26 |
| 37.50 | 0.10332 | 5.33 | 16 | 32 |
| 41.01 | 0.12269 | 6.33 | 19 | 38 |
| 42.12 | 0.12915 | 6.67 | 20 | 40 |
| 43.22 | 0.13561 | 7.00 | 21 | 42 |
| 45.34 | 0.14852 | 7.66 | 23 | 46 |

Indexing an XPD Pattern

$$d_{hkl}^2 = \frac{\lambda^2}{4 \sin^2 \theta_{hkl}} = \frac{a^2}{h^2 + k^2 + l^2} \quad \rightarrow \quad \sin^2 \theta_{hkl} = \left(\frac{\lambda^2}{4a^2} \right) (h^2 + k^2 + l^2)$$

| 2θ (°) | $\sin^2\theta$ | ratio | integers | $h^2 + k^2 + l^2$ | hkl |
|---------------|----------------|-------|----------|-------------------|----------|
| 16.00 | 0.01937 | 1.00 | 3 | 6 | 211 |
| 18.50 | 0.02583 | 1.33 | 4 | 8 | 220 |
| 24.55 | 0.04520 | 2.33 | 7 | 14 | 321 |
| 26.28 | 0.05166 | 2.67 | 8 | 16 | 400 |
| 29.44 | 0.06457 | 3.33 | 10 | 20 | 420 |
| 30.91 | 0.07103 | 3.66 | 11 | 22 | 332 |
| 32.33 | 0.07749 | 4.00 | 12 | 24 | 422 |
| 33.68 | 0.08395 | 4.33 | 13 | 26 | 431 |
| 37.50 | 0.10332 | 5.33 | 16 | 32 | 440 |
| 41.01 | 0.12269 | 6.33 | 19 | 38 | 532, 611 |
| 42.12 | 0.12915 | 6.67 | 20 | 40 | 620 |
| 43.22 | 0.13561 | 7.00 | 21 | 42 | 541 |
| 45.34 | 0.14852 | 7.66 | 23 | 46 | 631 |

Indexing an XPD Pattern

$$d_{hkl}^2 = \frac{\lambda^2}{4 \sin^2 \theta_{hkl}} = \frac{a^2}{h^2 + k^2 + l^2} \quad \rightarrow \quad \sin^2 \theta_{hkl} = \left(\frac{\lambda^2}{4a^2} \right) (h^2 + k^2 + l^2)$$

| 2θ (°) | $\sin^2\theta$ | ratio | integers | $h^2 + k^2 + l^2$ | hkl | a (Å) |
|---------------|----------------|-------|----------|-------------------|----------|---------|
| 16.00 | 0.01937 | 1.00 | 3 | 6 | 211 | 13.5567 |
| 18.50 | 0.02583 | 1.33 | 4 | 8 | 220 | 13.5564 |
| 24.55 | 0.04520 | 2.33 | 7 | 14 | 321 | 13.5567 |
| 26.28 | 0.05166 | 2.67 | 8 | 16 | 400 | 13.5563 |
| 29.44 | 0.06457 | 3.33 | 10 | 20 | 420 | 13.5566 |
| 30.91 | 0.07103 | 3.66 | 11 | 22 | 332 | 13.5566 |
| 32.33 | 0.07749 | 4.00 | 12 | 24 | 422 | 13.5563 |
| 33.68 | 0.08395 | 4.33 | 13 | 26 | 431 | 13.5565 |
| 37.50 | 0.10332 | 5.33 | 16 | 32 | 440 | 13.5565 |
| 41.01 | 0.12269 | 6.33 | 19 | 38 | 532, 611 | 13.5564 |
| 42.12 | 0.12915 | 6.67 | 20 | 40 | 620 | 13.5565 |
| 43.22 | 0.13561 | 7.00 | 21 | 42 | 541 | 13.5565 |
| 45.34 | 0.14852 | 7.66 | 23 | 46 | 631 | 13.5565 |

Indexing an XPD Pattern

$$d_{hkl}^2 = \frac{\lambda^2}{4 \sin^2 \theta_{hkl}} = \frac{a^2}{h^2 + k^2 + l^2} \quad \rightarrow \quad \sin^2 \theta_{hkl} = \left(\frac{\lambda^2}{4a^2} \right) (h^2 + k^2 + l^2)$$

| 2θ (°) | hkl |
|---------------|----------|
| 16.00 | 211 |
| 18.50 | 220 |
| 24.55 | 321 |
| 26.28 | 400 |
| 29.44 | 420 |
| 30.91 | 332 |
| 32.33 | 422 |
| 33.68 | 431 |
| 37.50 | 440 |
| 41.01 | 532, 611 |
| 42.12 | 620 |
| 43.22 | 541 |
| 45.34 | 631 |

Lattice parameter

$$a = 13.5565 \text{ \AA}$$

Centered?

P: no conditions on hkl

I: $h + k + l = 2n$

F: $\left. \begin{array}{l} h + k = 2n \\ h + l = 2n \\ k + l = 2n \end{array} \right\} \begin{array}{l} hkl \text{ all} \\ \text{even or all} \\ \text{odd} \end{array}$

Indexing an XPD Pattern

$$d_{hkl}^2 = \frac{\lambda^2}{4 \sin^2 \theta_{hkl}} = \frac{a^2}{h^2 + k^2 + l^2} \quad \rightarrow \quad \sin^2 \theta_{hkl} = \left(\frac{\lambda^2}{4a^2} \right) (h^2 + k^2 + l^2)$$

| 2θ (°) | hkl |
|---------------|----------|
| 16.00 | 211 |
| 18.50 | 220 |
| 24.55 | 321 |
| 26.28 | 400 |
| 29.44 | 420 |
| 30.91 | 332 |
| 32.33 | 422 |
| 33.68 | 431 |
| 37.50 | 440 |
| 41.01 | 532, 611 |
| 42.12 | 620 |
| 43.22 | 541 |
| 45.34 | 631 |

Lattice parameter

$$a = 13.5565 \text{ \AA}$$

Centered?

P: no conditions on hkl

\rightarrow *I*: $h + k + l = 2n$

F: $\left. \begin{array}{l} h + k = 2n \\ h + l = 2n \\ k + l = 2n \end{array} \right\} \begin{array}{l} hkl \text{ all} \\ \text{even or all} \\ \text{odd} \end{array}$

Indexing an XPD Pattern

$$d_{hkl}^2 = \frac{\lambda^2}{4 \sin^2 \theta_{hkl}} = \frac{a^2}{h^2 + k^2 + l^2} \quad \rightarrow \quad \sin^2 \theta_{hkl} = \left(\frac{\lambda^2}{4a^2} \right) (h^2 + k^2 + l^2)$$

| |
|--------|
| 2θ (°) |
| 38.46 |
| 55.54 |
| 69.58 |
| 82.46 |
| 94.94 |
| 107.64 |
| 121.36 |

Exercise 1 (send answers to przepka@ethz.ch):

1. Index listed peaks if you know the structure is cubic
2. What is lattice parameter a if $\lambda=1.54\text{\AA}$?
3. What is centering?

Reflection position

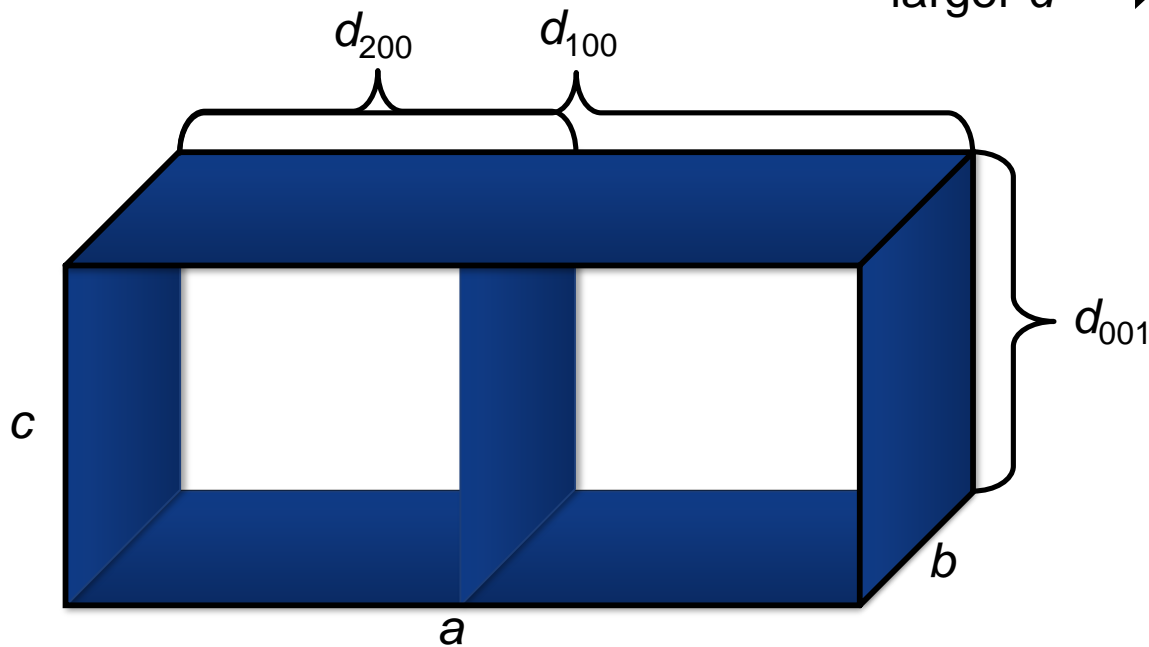
Parameters affecting reflection positions

- unit cell parameters
- zero point of the detector
- sample displacement

$$\frac{1}{d} = 2d_{hkl} \sin \theta_{hkl}$$

smaller $d \Rightarrow$ larger 2θ

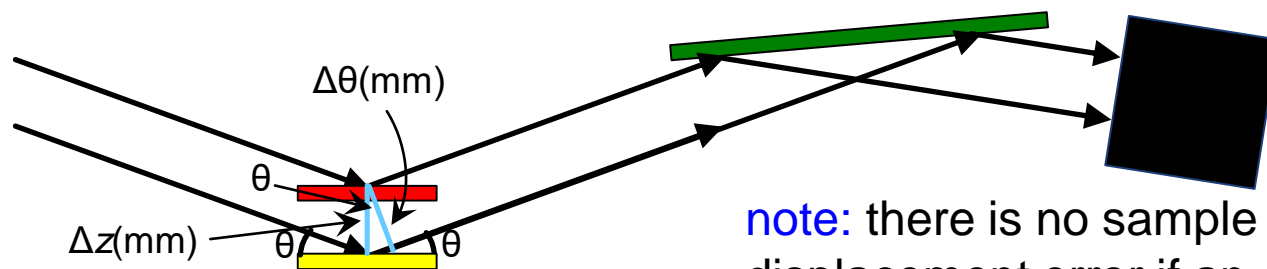
larger $d \Rightarrow$ smaller 2θ



Reflection position

Parameters affecting reflection positions

- unit cell parameters
- zero point of the detector
- **sample displacement (Bragg-Brentano)**



note: there is no sample displacement error if an analyzer crystal is used

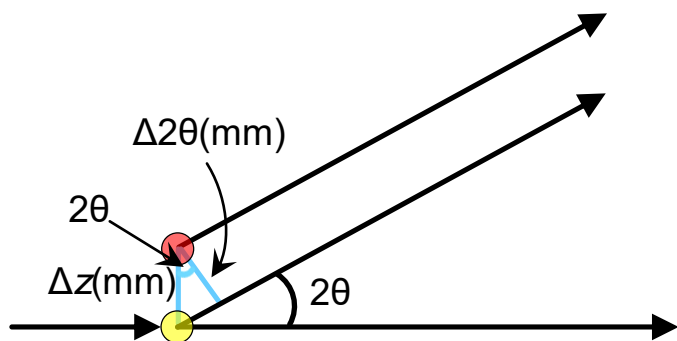
$$\cos(2\theta) = \Delta 2\theta / \Delta z$$

$$\Delta\theta = \Delta z \cos(\theta)$$

Reflection position

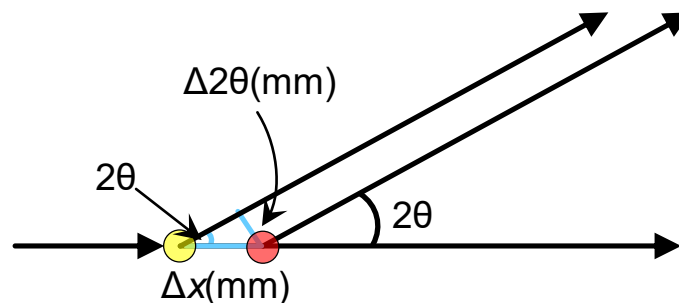
Parameters affecting reflection positions

- unit cell parameters
- zero point of the detector
- **sample displacement (Debye-Scherrer)**



$$\cos(2\theta) = \Delta 2\theta / \Delta z$$

$$\Delta 2\theta = \Delta z \cos(2\theta)$$



$$\sin(2\theta) = \Delta 2\theta / \Delta x$$

$$\Delta 2\theta = \Delta x \sin(2\theta)$$

Crystalline size

Peak width (B) is inversely proportional to crystallite size (L)

Scherrer equation
$$D = \frac{K\lambda}{FWHM \cos\theta}$$

D – crystalline size, K=0.9 - shape factor, λ – wavelength, FWHM – the line broadening at half the maximum intensity, θ – Bragg angle

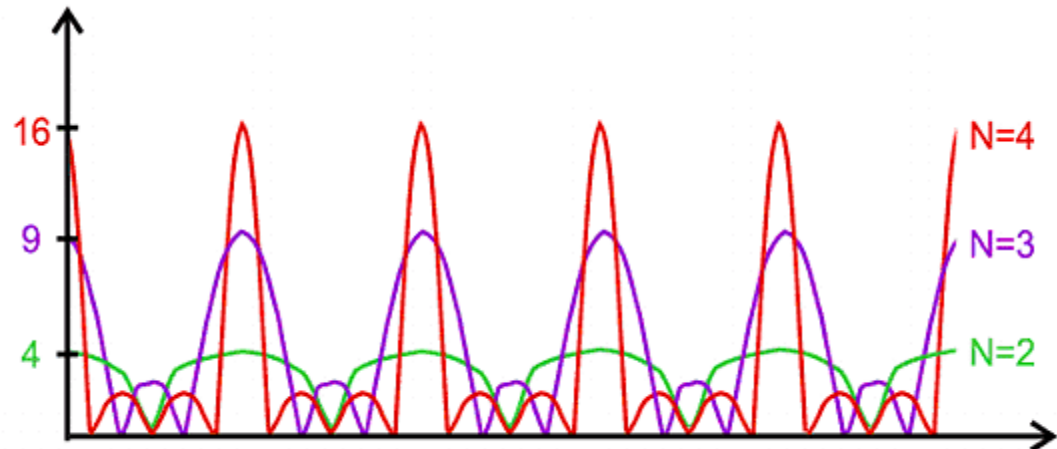
The Laue Equations describe the intensity of a diffracted peak from an **infinitely large (> 1um)** and **perfectly ordered** crystal. Deviations from the ideal (nano-sizing) create peak broadening

Crystalline size

Peak width (B) is inversely proportional to crystallite size (L)

$$\text{Scherrer equation } D = \frac{K\lambda}{FWHM \cos\theta}$$

D – crystalline size, K=0.9 - shape factor, λ – wavelength, FWHM – the line broadening at half the maximum intensity, θ – Bragg angle



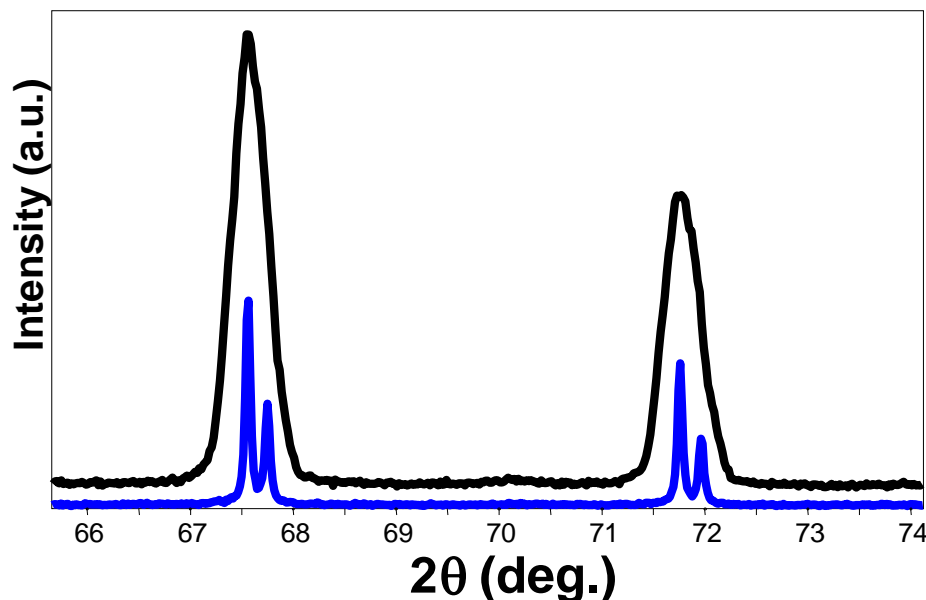
The interference from $n = 2, 3, 4$ scattering centers

Crystalline size

Peak width (B) is inversely proportional to crystallite size (L)

$$\text{Scherrer equation } D = \frac{K\lambda}{FWHM \cos\theta}$$

D – crystalline size, K=0.9 - shape factor, λ – wavelength, FWHM – the line broadening at half the maximum intensity, θ – Bragg angle



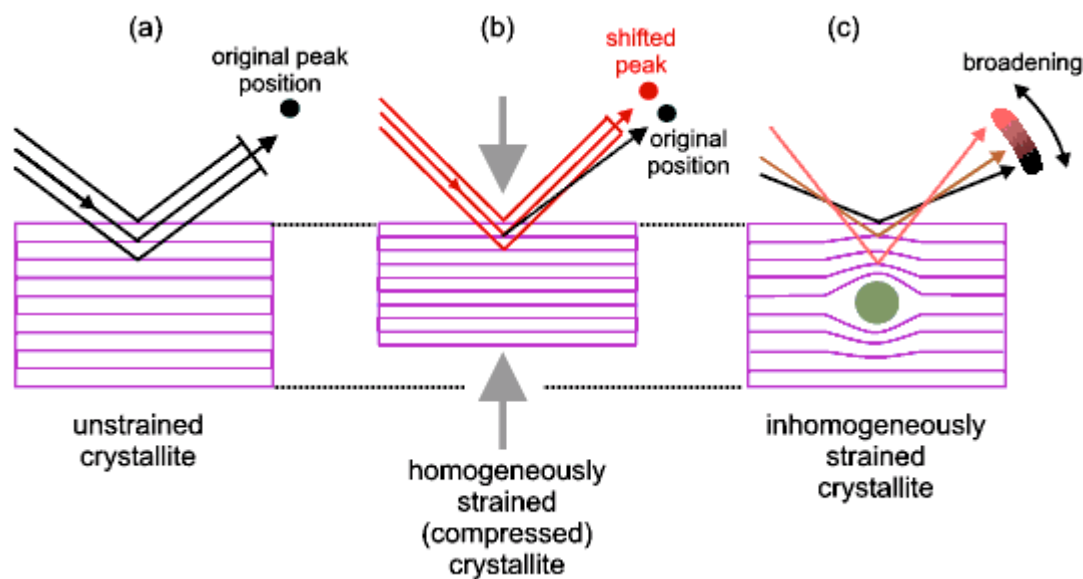
Note the instrumental contribution. Left: the same sample, different instruments

Crystalline size

Peak width (B) is inversely proportional to crystallite size (L)

$$\text{Scherrer equation } D = \frac{K\lambda}{FWHM \cos\theta}$$

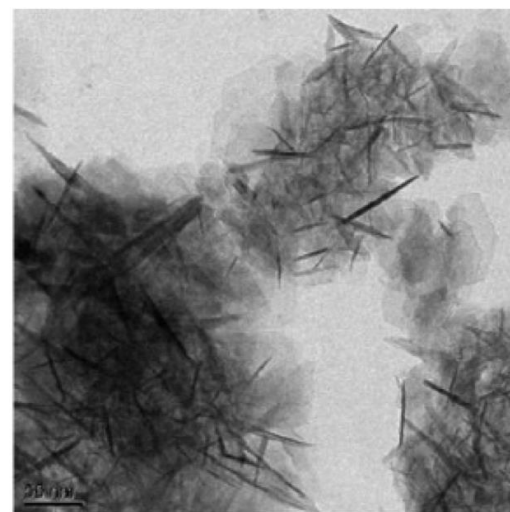
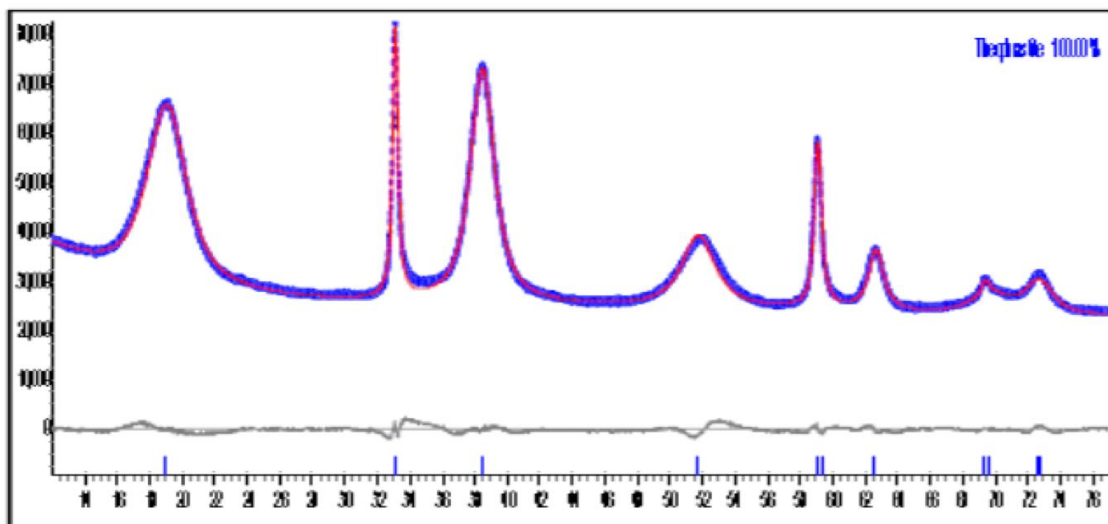
Microstrain (ϵ) analysis



$$FWHM = C \epsilon \tan\theta$$

Anisotropic Size Broadening

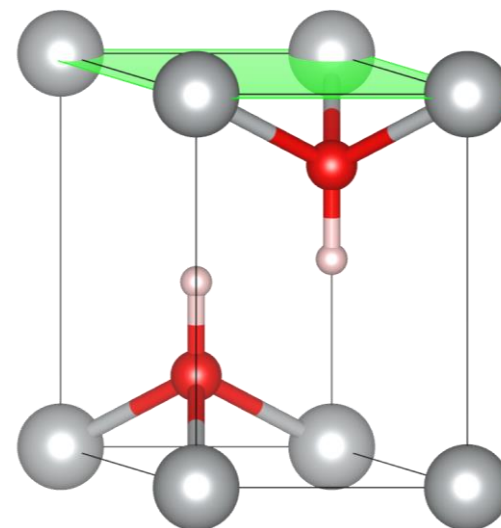
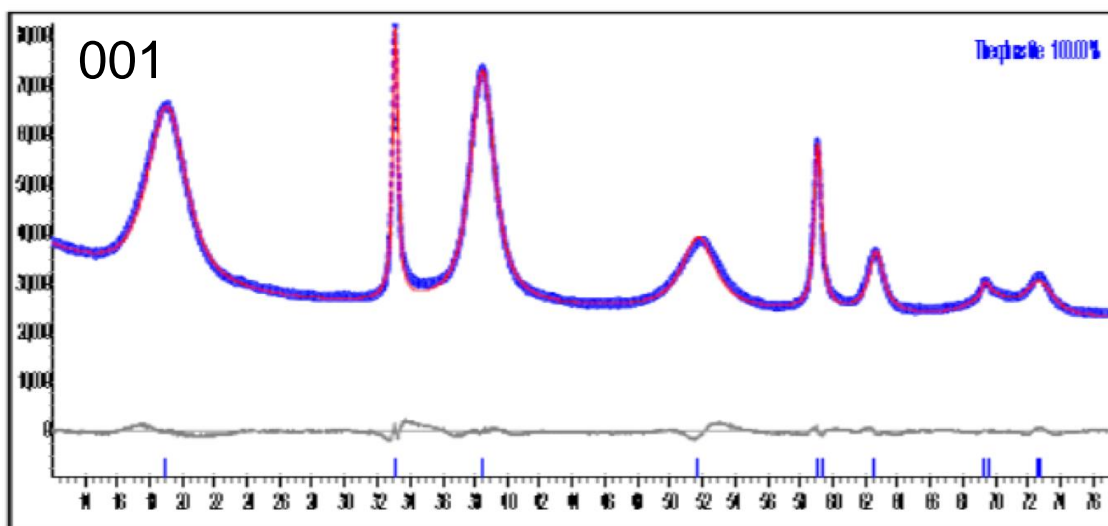
The broadening of a single diffraction peak is the product of the crystallite dimensions in the direction perpendicular to the planes that produced the diffraction peak



Anisotropic broadening in the PXRD pattern of Ni(OH)₂

Anisotropic Size Broadening

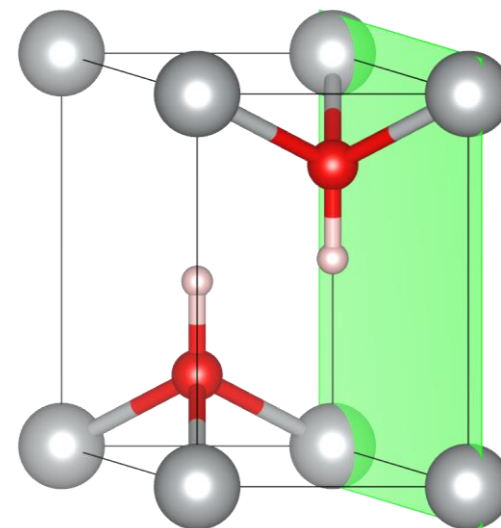
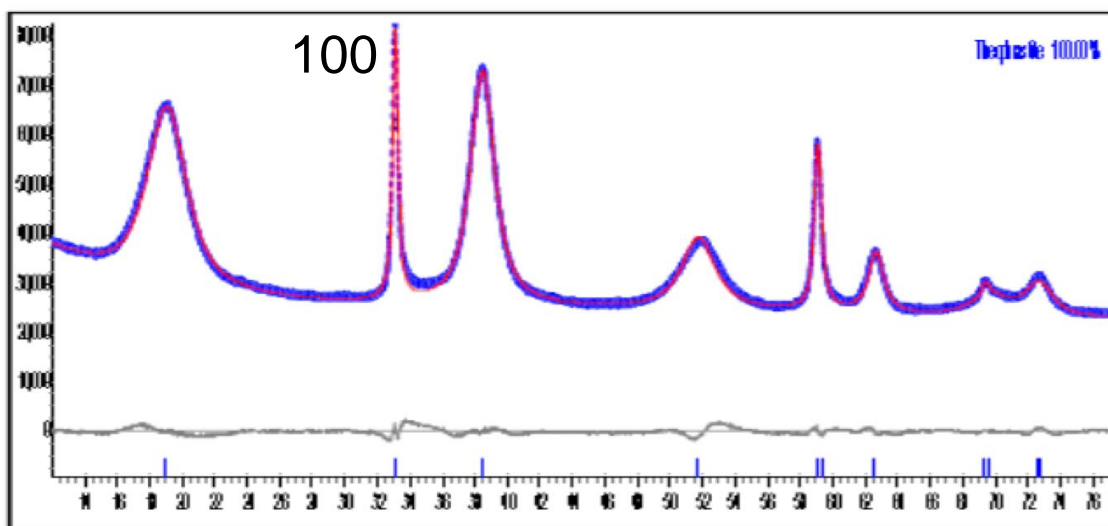
The broadening of a single diffraction peak is the product of the crystallite dimensions in the direction perpendicular to the planes that produced the diffraction peak



Anisotropic broadening in the PXRD pattern of Ni(OH)₂

Anisotropic Size Broadening

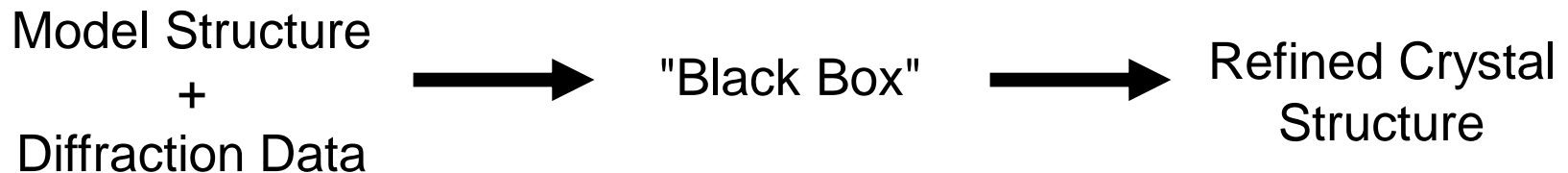
The broadening of a single diffraction peak is the product of the crystallite dimensions in the direction perpendicular to the planes that produced the diffraction peak



Anisotropic broadening in the PXRD pattern of Ni(OH)₂

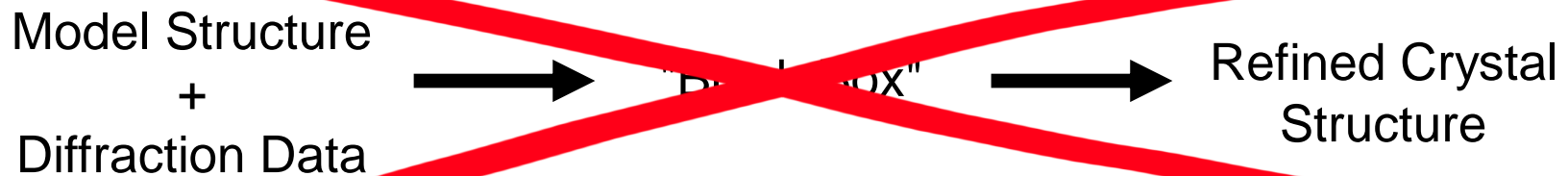
The Rietveld analysis

The Rietveld method refines user-selected parameters to minimize the difference between an experimental pattern (observed data) and a model based on the hypothesized crystal structure and instrumental parameters (calculated pattern)



The Rietveld analysis

The Rietveld method refines user-selected parameters to minimize the difference between an experimental pattern (observed data) and a model based on the hypothesized crystal structure and instrumental parameters (calculated pattern)



From intensities to structural parameters

$$\Delta = \sum_{n=1}^N \{ I_n(\text{obs}) - I_n(\text{calc}) \}^2$$

$$I(\text{calc}) = c j_{hkl} L(2\theta) P(2\theta) A(2\theta) F^2(hkl)$$

where L, P, A are the Lorentz, polarization, and absorption corrections, respectively. j is the multiplicity factor (symmetry), c is a scale factor and F is a structure factor.

$$F_{hkl} = \sum_j f_j \exp[2\pi i(hx_j + hy_j + hz_j)]$$

where f_j is atomic form factor.

bkg @ 0 0 0 0

R-Factors

$$R_{wp} = \left\{ \sum_i w_i \{y_i(obs) - y_i(calc)\}^2 / \sum_i w_i y_i(obs)^2 \right\}^{1/2}$$

$$w_i^2 = 1/\sigma(y_i(obs))^2$$

$$R_{exp} = \left\{ (M - P) / \sum_i w_i y_i(obs)^2 \right\}^{1/2}$$

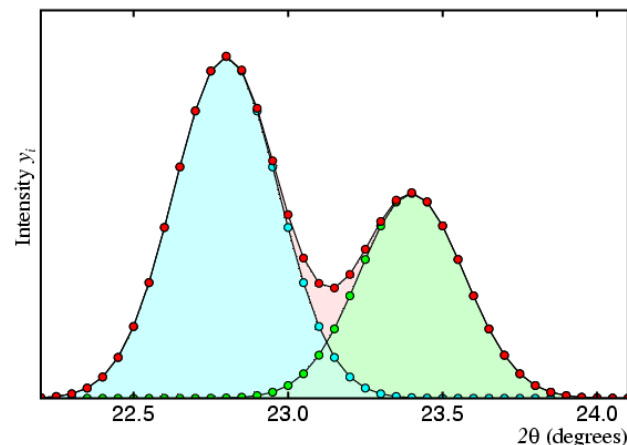
$$\chi^2 = (R_{wp}/R_{exp})^2 \text{ (goodness-of-fit)}$$

where w_i is weighting related to uncertainty σ . M – the number of data points, P – the number of parameters

Pawley and LeBail profile fitting

Parameters:

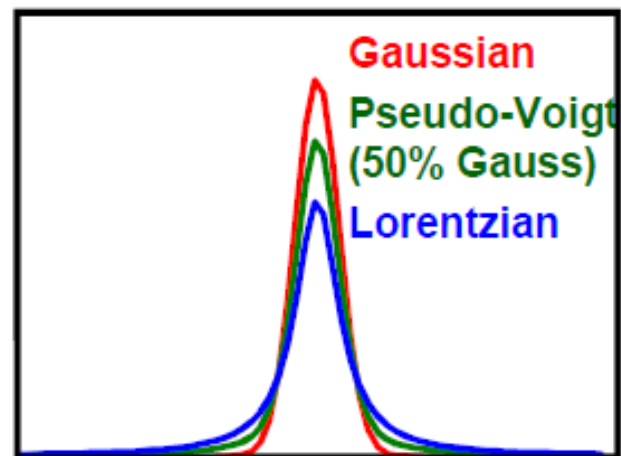
- $I(hkl)$ - Intensity of each reflection with indices hkl (only Pawley);
- $a, b, c, \alpha, \beta, \gamma$ - Unit-cell metric tensor parameters;
- $2\theta_{\text{zero}}$ - Instrumental zero error;
- U, V, W - Peak-width parameters;
- η , etc. - Other peak-shape parameters



Pseudo-Voigt peak shape function:

$$I(2\theta) = I_{hkl} [\eta \mathbf{L} (2\theta - 2\theta_0) + (1 - \eta) \mathbf{G} (2\theta - 2\theta_0)]$$

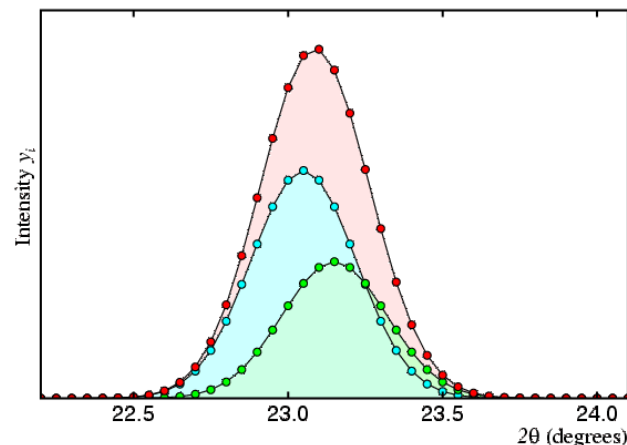
where $\mathbf{L} (2\theta - 2\theta_0)$ and $\mathbf{G} (2\theta - 2\theta_0)$ represent Lorentz and Gaussian functions, and η - the "Lorentz fraction"



Pawley and LeBail profile fitting

Parameters:

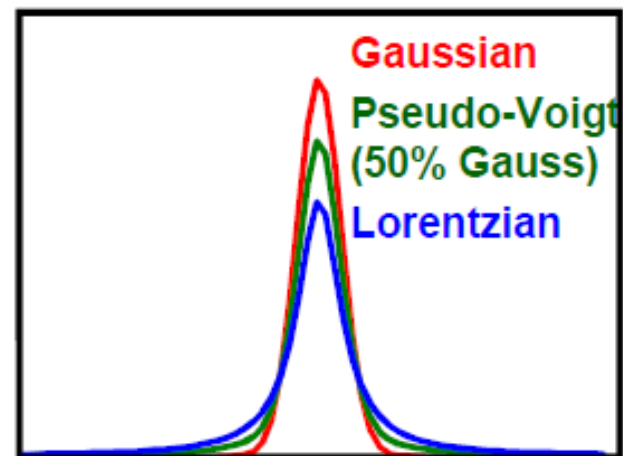
- $I(hkl)$ - Intensity of each reflection with indices hkl (only Pawley);
- $a, b, c, \alpha, \beta, \gamma$ - Unit-cell metric tensor parameters;
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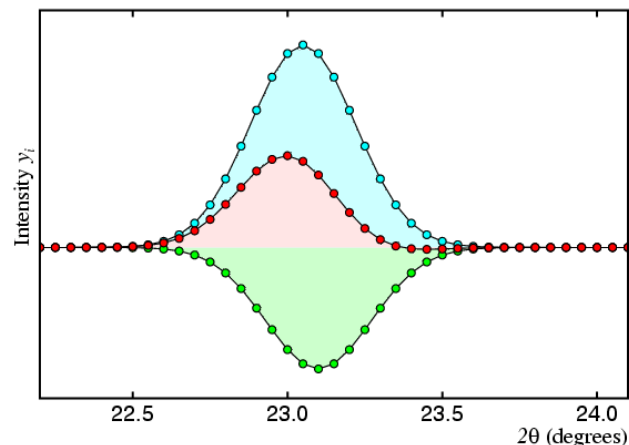
where $\mathbf{L} (2\theta - 2\theta_0)$ and $\mathbf{G} (2\theta - 2\theta_0)$ represent Lorentz and Gaussian functions, and η - the "Lorentz fraction"



Pawley and LeBail profile fitting

Parameters:

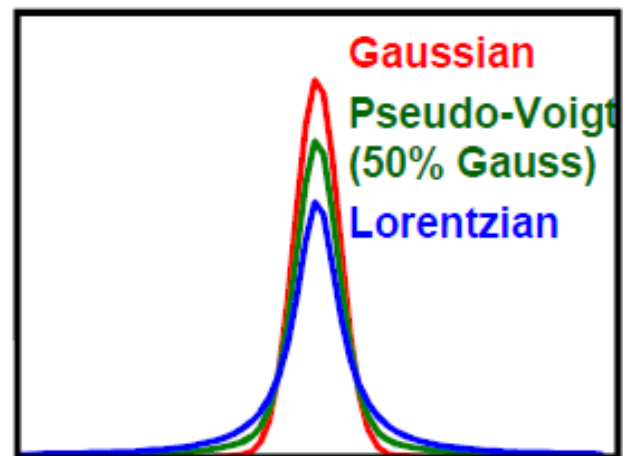
- $I(hkl)$ - Intensity of each reflection with indices hkl (only Pawley);
- $a, b, c, \alpha, \beta, \gamma$ - Unit-cell metric tensor parameters;
- $2\theta_{\text{zero}}$ - Instrumental zero error;
- U, V, W - Peak-width parameters;
- η , etc. - Other peak-shape parameters



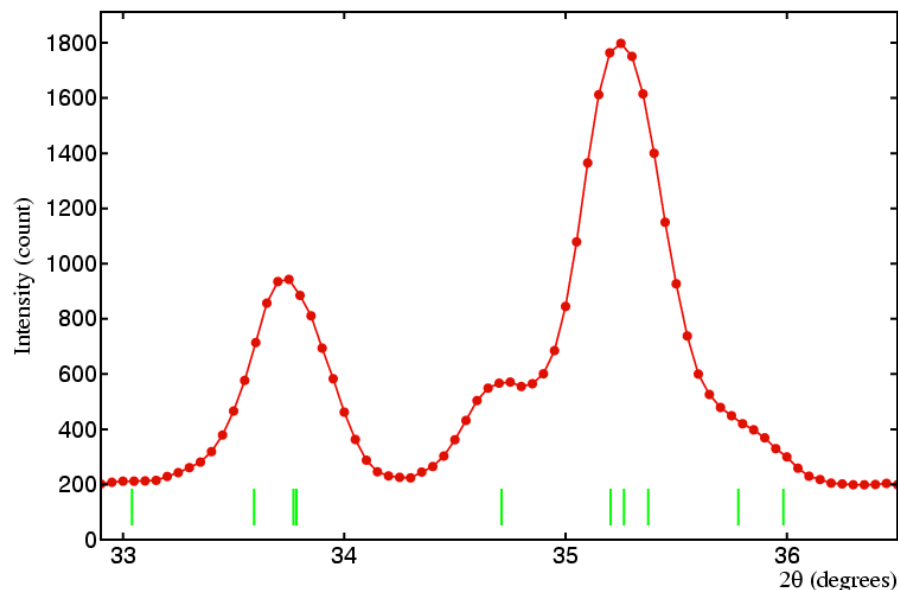
Pseudo-Voigt peak shape function:

$$I(2\theta) = I_{hkl} [\eta \mathbf{L} (2\theta - 2\theta_0) + (1 - \eta) \mathbf{G} (2\theta - 2\theta_0)]$$

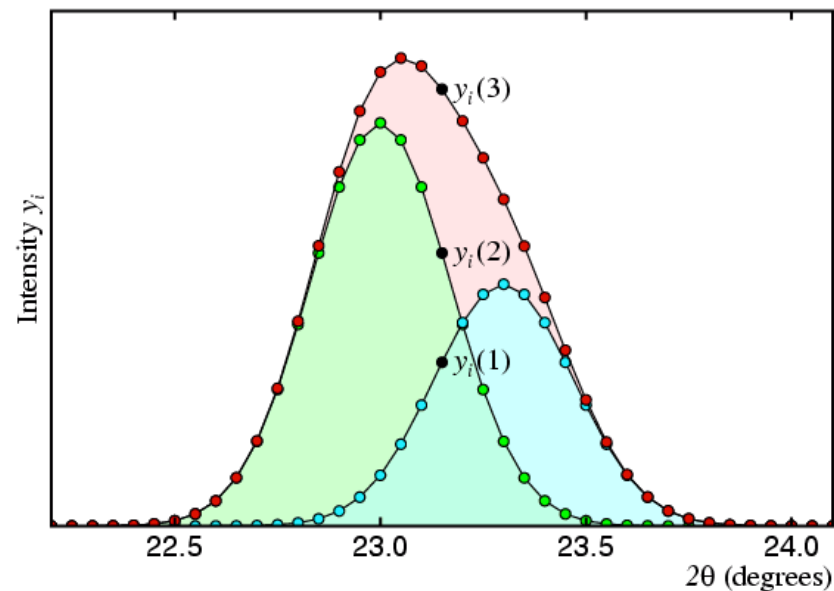
where $\mathbf{L} (2\theta - 2\theta_0)$ and $\mathbf{G} (2\theta - 2\theta_0)$ represent Lorentz and Gaussian functions, and η - the "Lorentz fraction"



Rietveld profile fitting



The detailed diffraction profile contained a lot more information than the extracted intensities of composite peaks



The detailed profile can be fitted on a point by point basis as the summation of the contribution of the profiles of all reflections to that point:

$$y_i(3) = y_i(1) + y_i(2)$$

Instrumental function

Refinement in TOPAS

```
xdd {
```

```
!      Lam profile (wavelength)
```

```
@      SD()
```

```
@      PV_Peak_Type()
```

```
@      Simple_Axial_Model()
```

```
@      @ Scale
```

```
}
```

Structure parameters

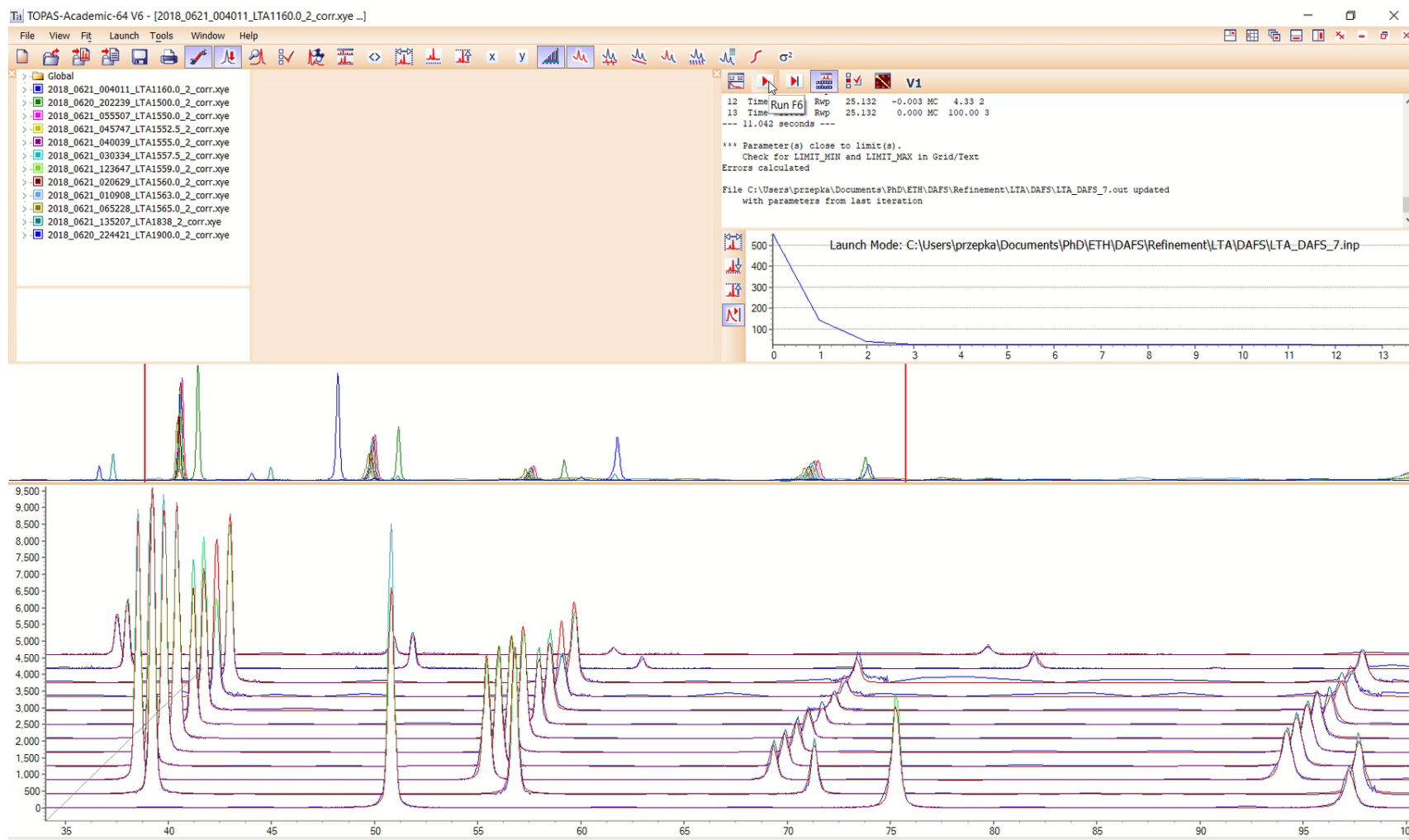
```
str {
```

```
@ Unit cell parameters
```

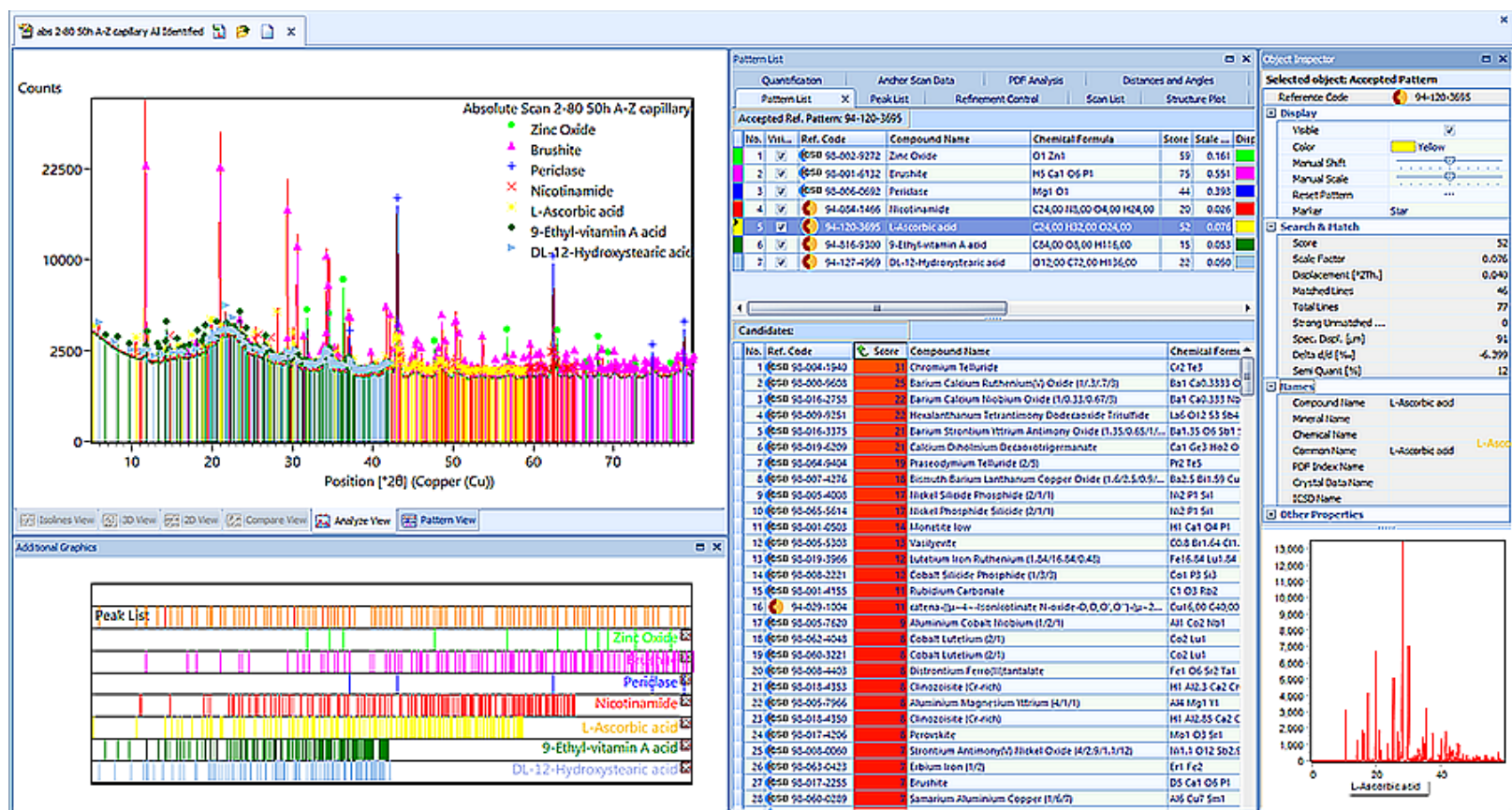
| | | | | | | | Site | | | | |
|------------|-----------|----|---|---------|---|---------|-------------------------------|---------|--------|-----|-------|
| | | | | | | | Occup. | Therm. | | | |
| | | | | | | | Factor | Factor | | | |
| | | | | | | | Fractional atomic coordinates | | | | |
| site Si(1) | num_posns | 16 | x | 0.32281 | y | 0.19961 | z | 0.20804 | occ Si | 1.0 | beq 1 |
| site Si(2) | num_posns | 8 | x | 0.08670 | y | 0.20129 | z | 0.00000 | occ Si | 1.0 | beq 1 |
| site Si(3) | num_posns | 8 | x | 0.27374 | y | 0.00000 | z | 0.29371 | occ Si | 1.0 | beq 1 |
| site Si(4) | num_posns | 4 | x | 0.15538 | y | 0.00000 | z | 0.00000 | occ Si | 1.0 | beq 1 |
| site O(8) | num_posns | 4 | x | 0.25169 | y | 0.00000 | z | 0.50000 | occ O | 1.0 | beq 1 |
| site O(7) | num_posns | 8 | x | 0.20342 | y | 0.00000 | z | 0.18745 | occ O | 1.0 | beq 2 |
| site O(5) | num_posns | 8 | x | 0.10707 | y | 0.09088 | z | 0.00000 | occ O | 1.0 | beq 2 |
| site O(3) | num_posns | 8 | x | 0.34246 | y | 0.21404 | z | 0.00000 | occ O | 1.0 | beq 2 |
| site O(6) | num_posns | 4 | x | 0.00000 | y | 0.20890 | z | 0.00000 | occ O | 1.0 | beq 2 |
| site O(4) | num_posns | 8 | x | 0.25000 | y | 0.25000 | z | 0.25000 | occ O | 1.0 | beq 2 |
| site O(2) | num_posns | 16 | x | 0.38070 | y | 0.24571 | z | 0.32000 | occ O | 1.0 | beq 2 |
| site O(1) | num_posns | 16 | x | 0.31646 | y | 0.09052 | z | 0.24720 | occ O | 1.0 | beq 2 |

```
}
```

The Rietveld analysis



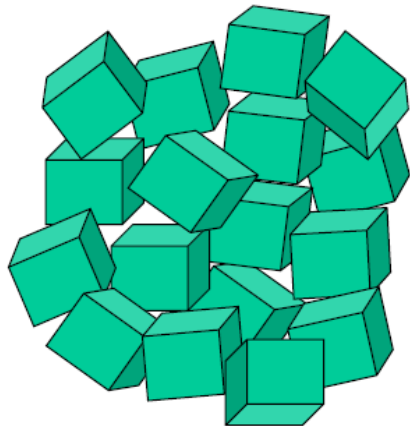
Phase identification



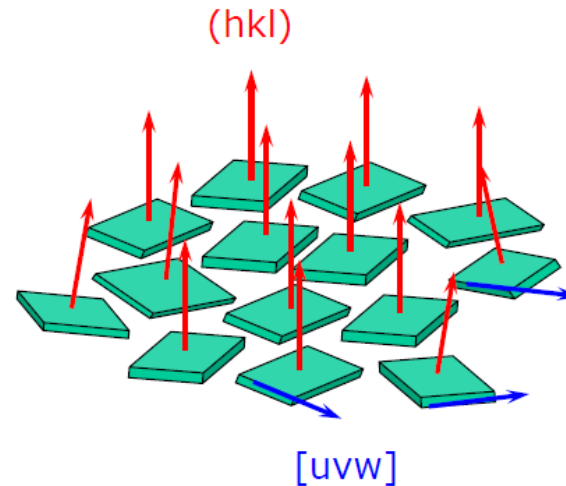
HighScore matches the peaks from collected data with database records

Sample preparation. What happens when wrong?

1. Not all crystal lattice planes present (graininess)
2. Relative intensities distribution different from expected (preferred orientation)



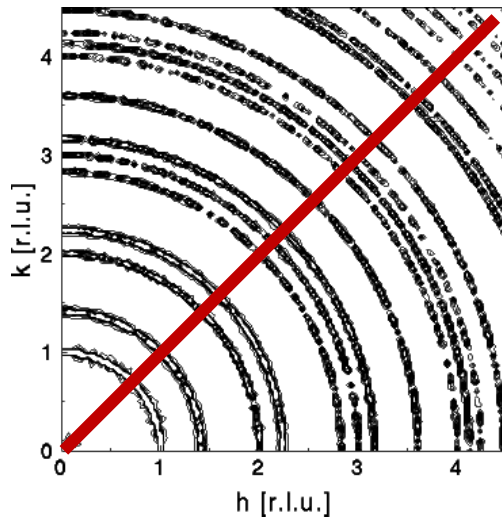
Random orientation of crystallites (e.g. isotropic powder)



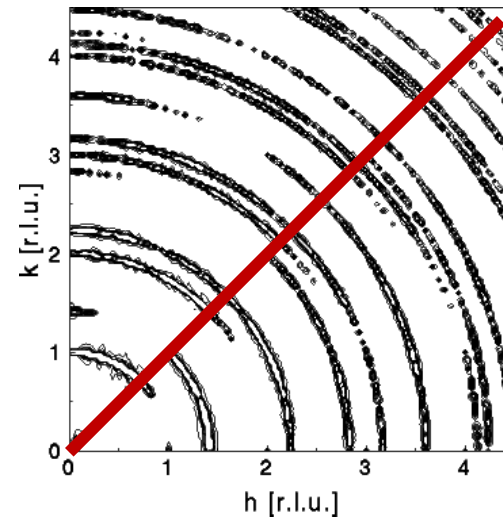
Preferred orientation of crystallites (typical for plate-like crystallites)

Sample preparation. What happens when wrong?

1. Not all crystal lattice planes present (graininess)
2. Relative intensities distribution different from expected (preferred orientation)



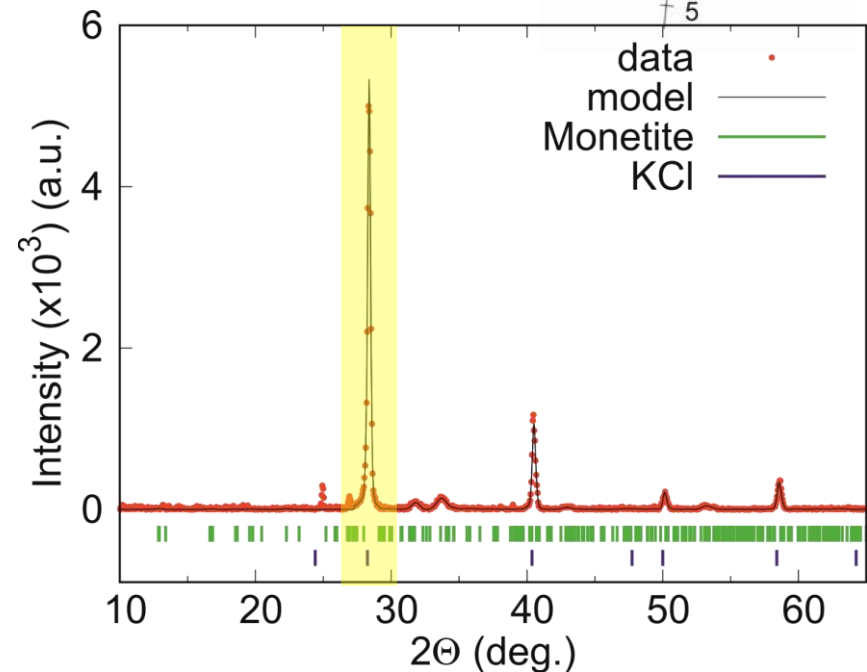
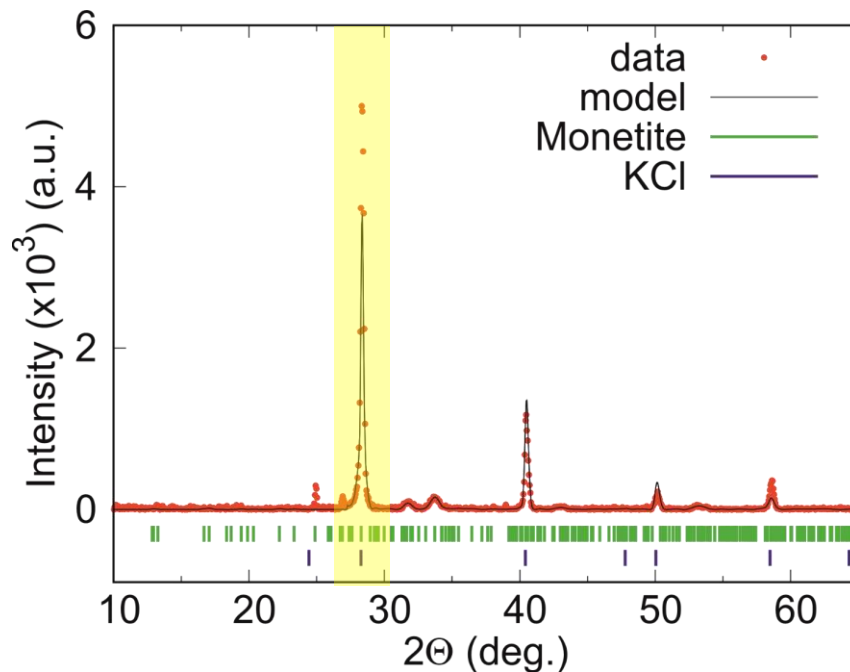
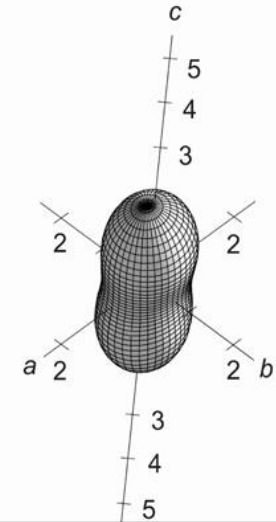
Random orientation of crystallites (e.g. isotropic powder)



Preferred orientation of crystallites (typical for plate-like crystallites)

Sample preparation

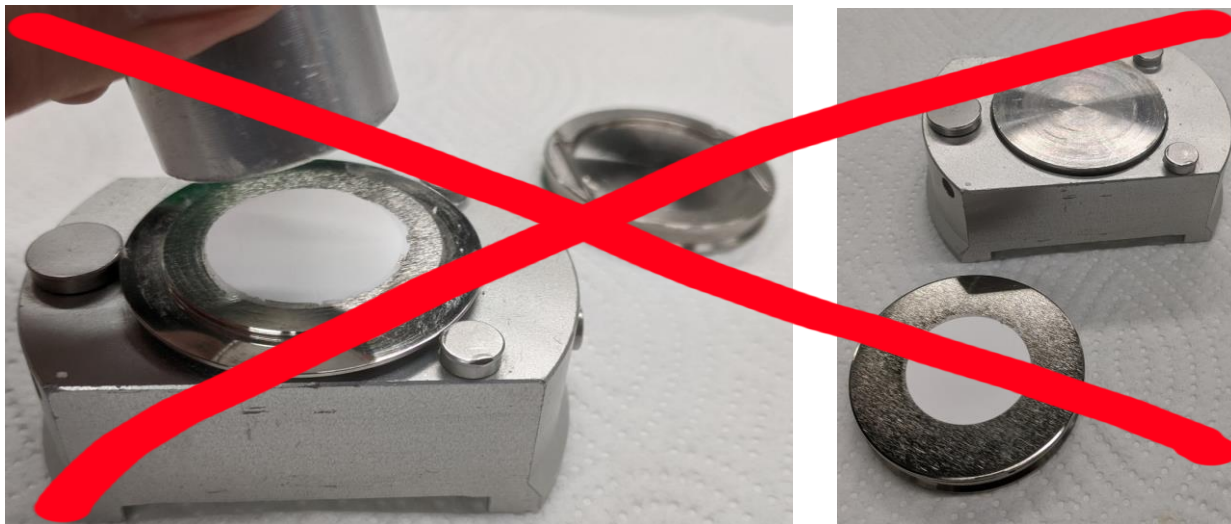
Preferred orientation may be corrected by spherical harmonics function. It compromises however the structure refinement or quantitative phase identification



Sample preparation for reflection XRD



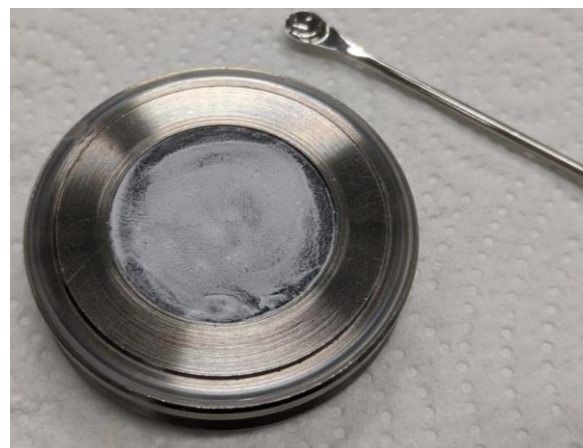
Sample preparation for reflection XRD



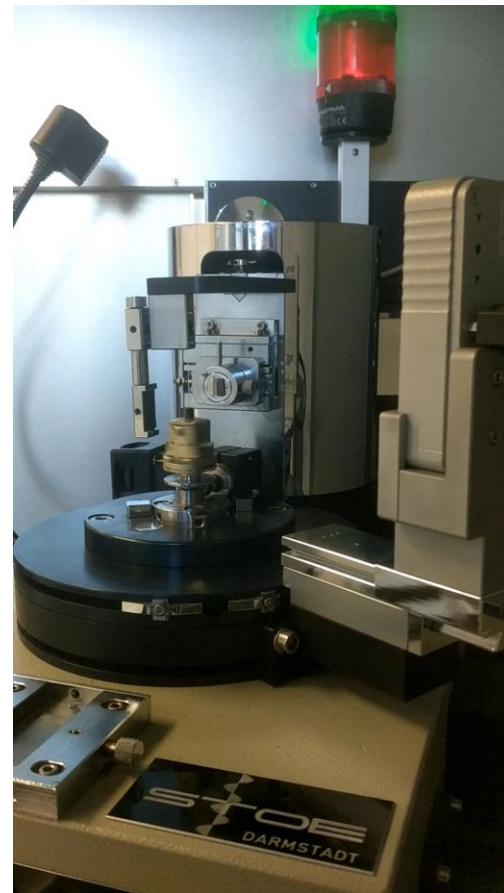
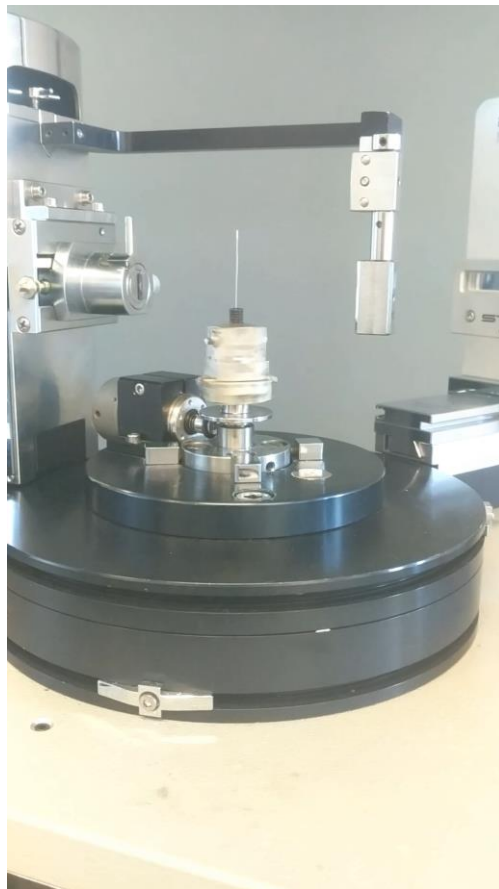
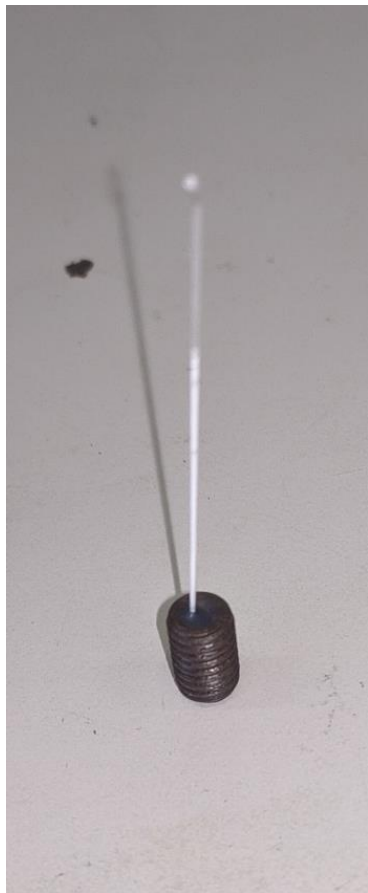
$$I/I_0 = e^{-(\mu_{\text{tot}}/\rho)x} < 1\% \text{ if } x > 0.5\text{mm}$$

I_0 (ph/s) – incident photon flux for Cu anode;
 μ_{tot} – total absorption coefficient for a zeolite;
 ρ – density of a zeolite;

Sample preparation for reflection XRD



Sample preparation for transmission XRD

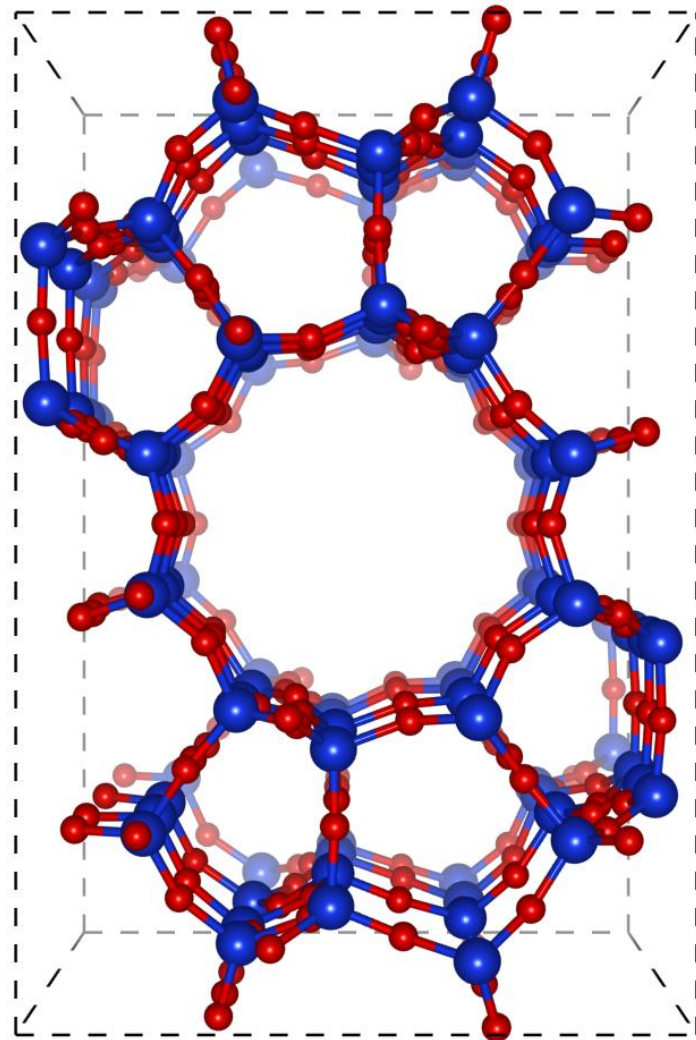
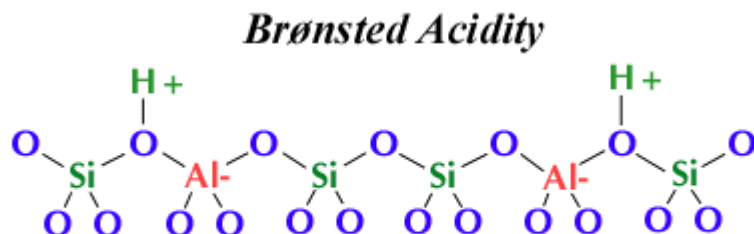


Stoe STADIP diffractometer working in Transmission-/Debye-Scherrer-geometry available for ex situ capillaries measurements

Si:Al distribution in zeolite framework

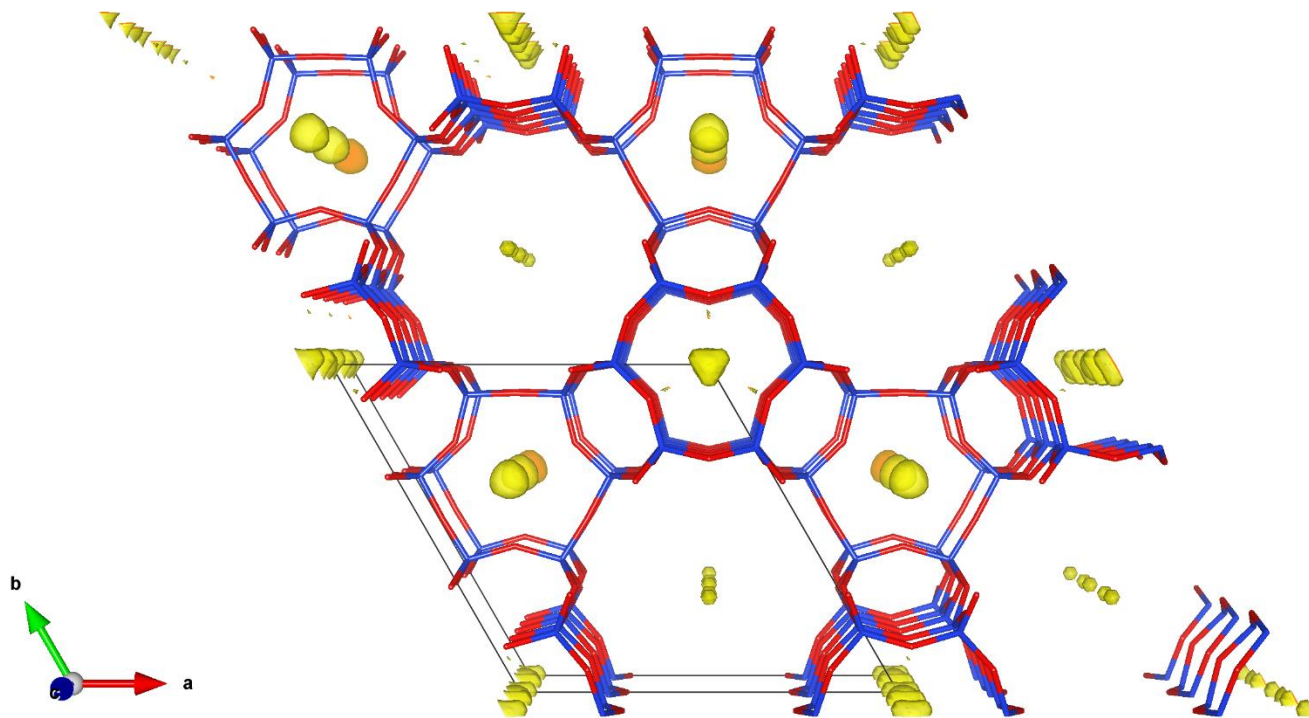
Protons and other light elements are poor scatterers and cannot be detected directly by X-ray diffraction methods

Brønsted acid sites or hydroxyl groups are balanced by framework charge associated to aluminum. Hence determination of Al positions allows on situating extra-framework entities



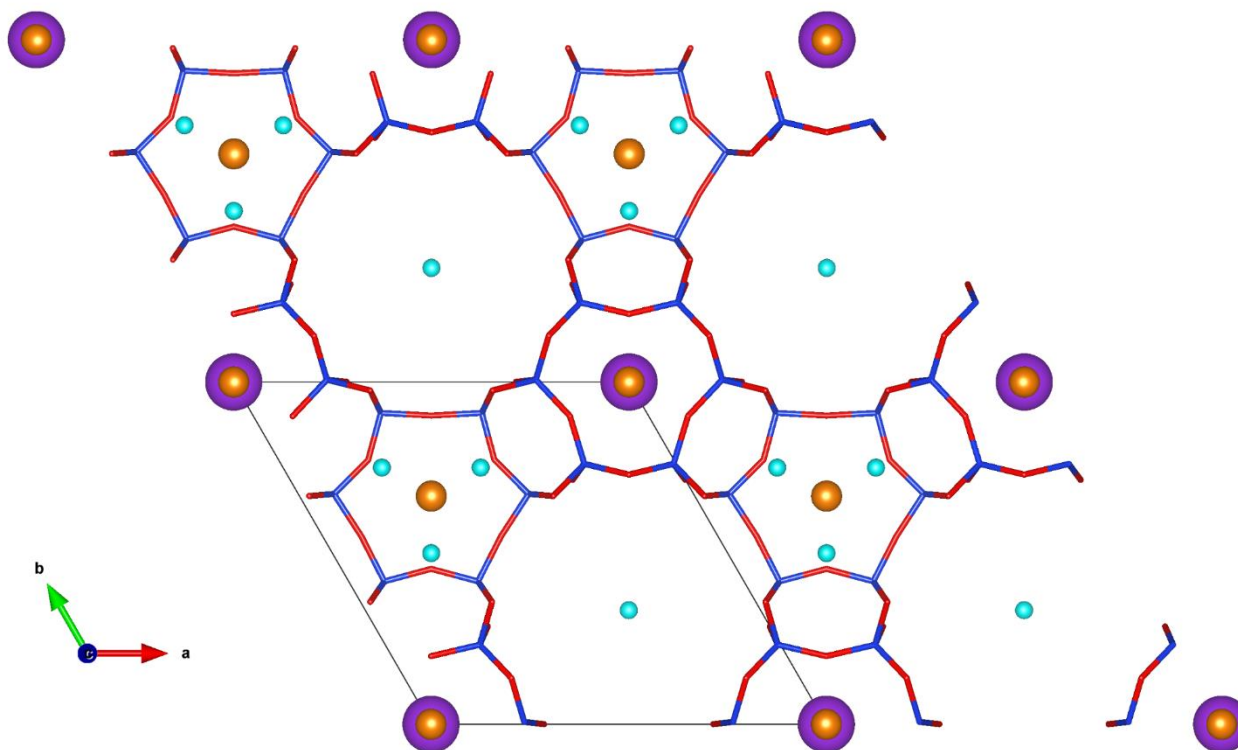
Difference density maps

`fourier_map_formula=Fobs-Fcalc(model);`



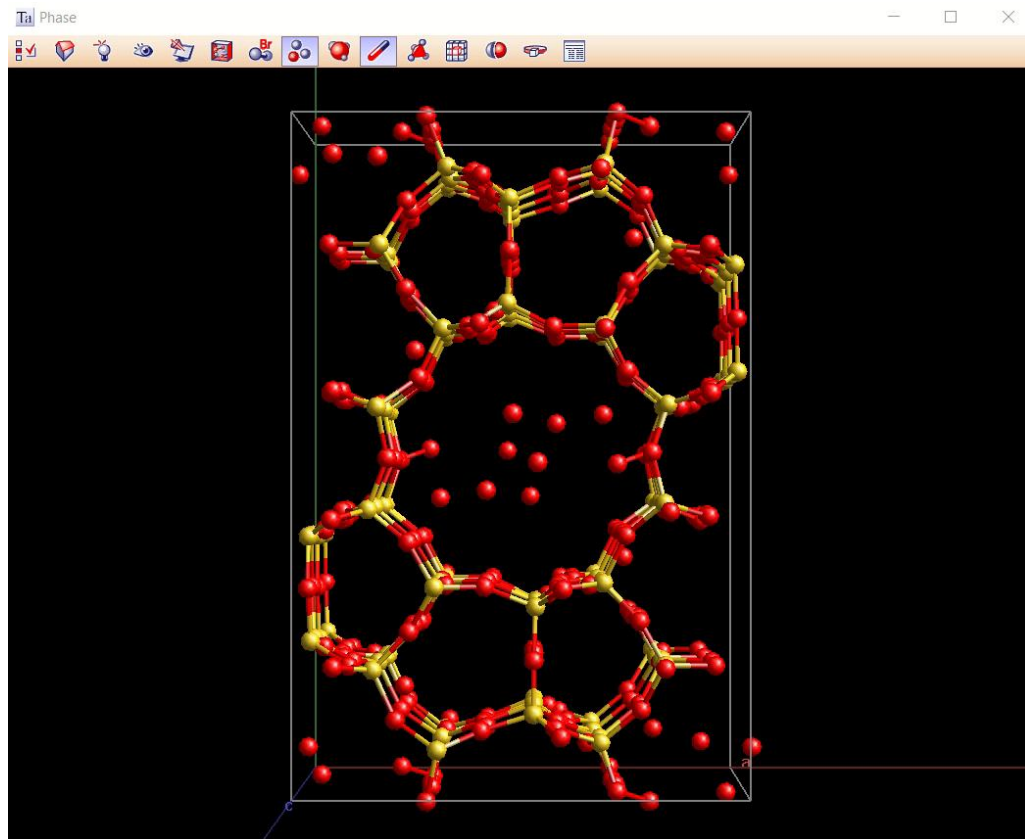
To investigate the positioning of the cations in Cu-OFF zeolite, the structure model containing only the framework atoms was subtracted from observed PXRD data

The refinement of extraframework cations



The structure of Cu-OFF with input positions of the extra-framework cations adopted from DDM was refined using Rietveld analysis

Structure Determination by Simulated Annealing



rigid

```
load z_matrix {
  O1
  H2 1 0.9687
  H3 1 0.9687 2 104
}
```

translate

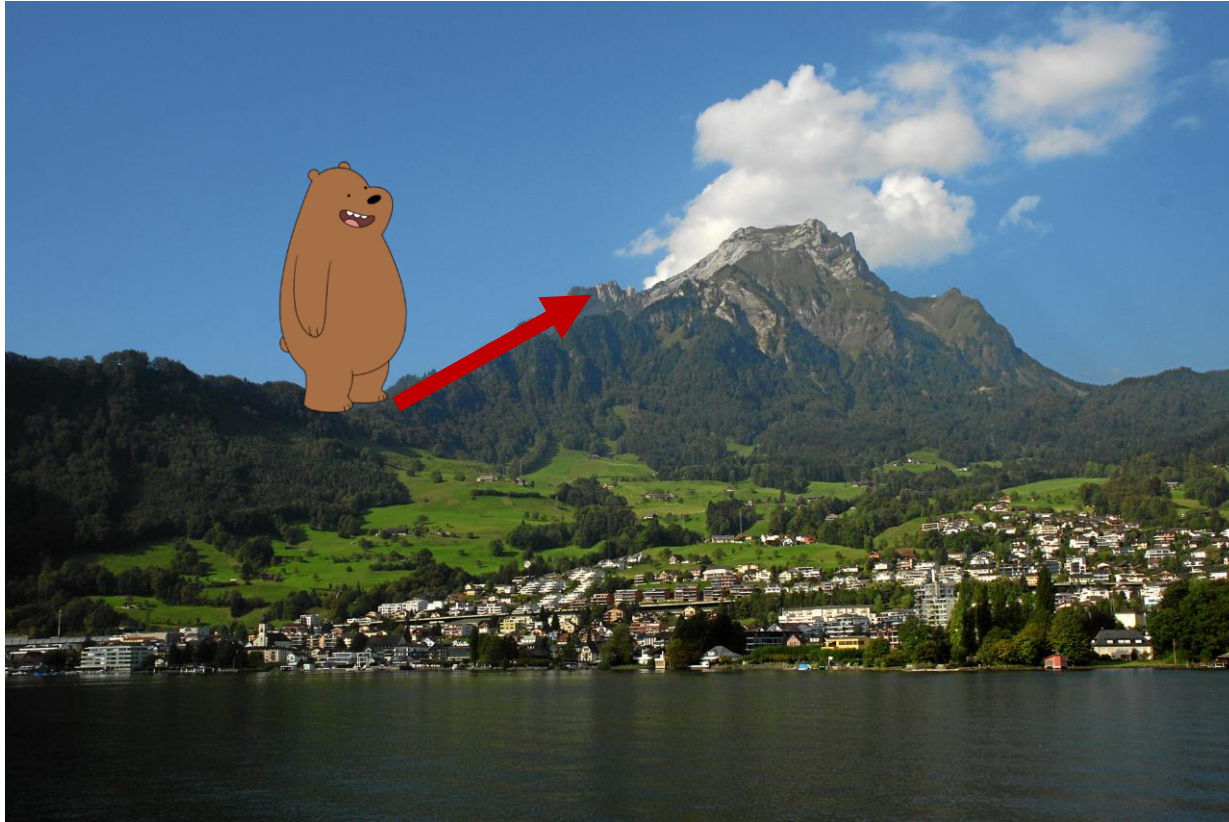
```
tx @ 0 ty @ 0 tz @ 0
```

rotate

```
qa @ 0 qb @ 0 qc @ 0
```

The simulated annealing algorithm approximates the global optimum of a given parameter in an environment of a large number of local optima whereas least square methods are local optimization only

Simulated annealing vs least squares methods (Rietveld refinement)



The simulated annealing algorithm approximates the global optimum of a given parameter in an environment of a large number of local optima whereas least square methods are local optimization only

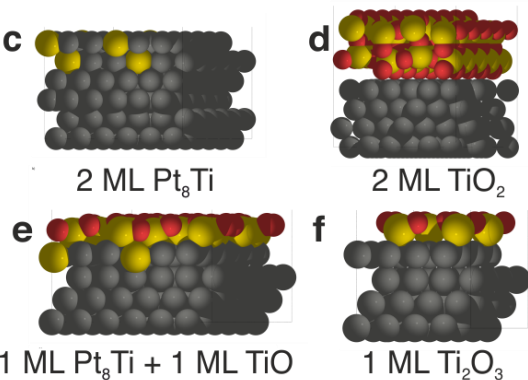
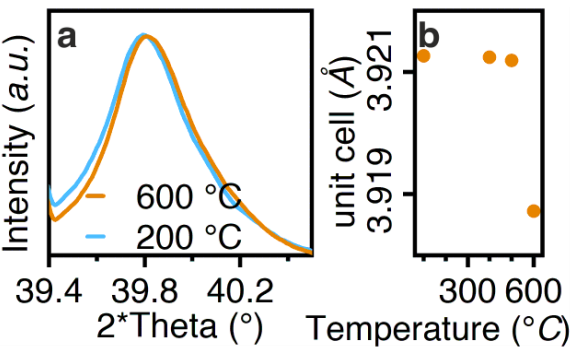
Simulated annealing vs least squares methods (Rietveld refinement)



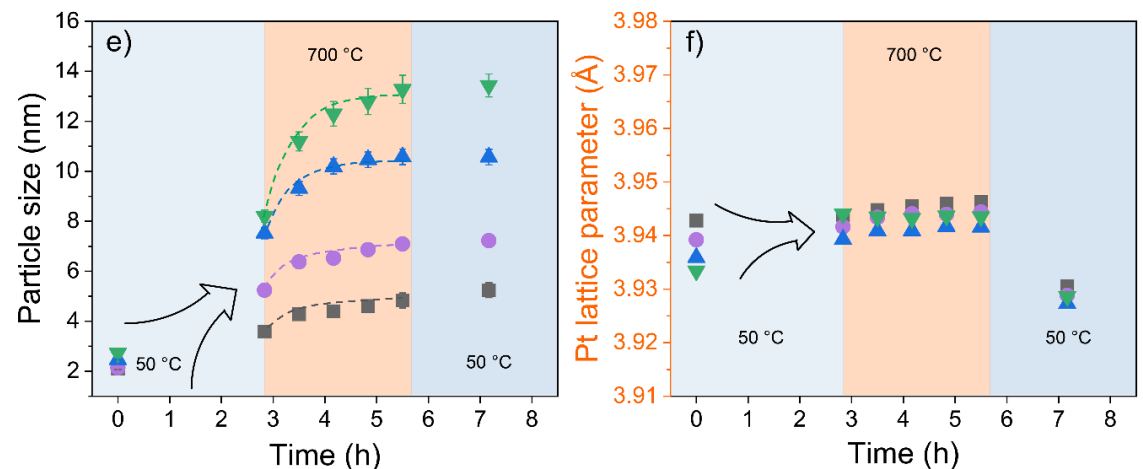
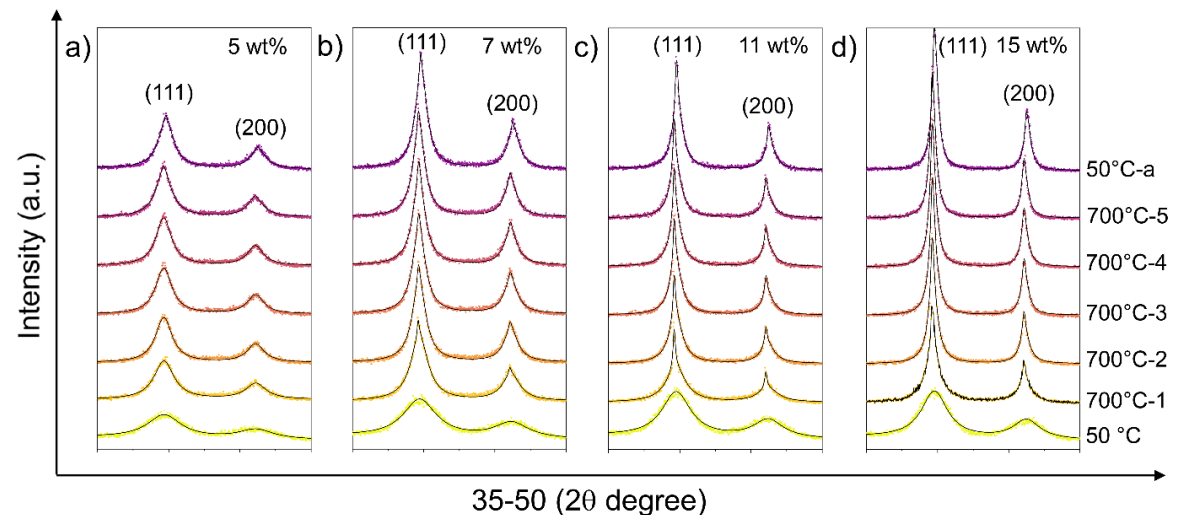
The simulated annealing algorithm approximates the global optimum of a given parameter in an environment of a large number of local optima whereas least square methods are local optimization only

Lattice parameters and particle size analysis

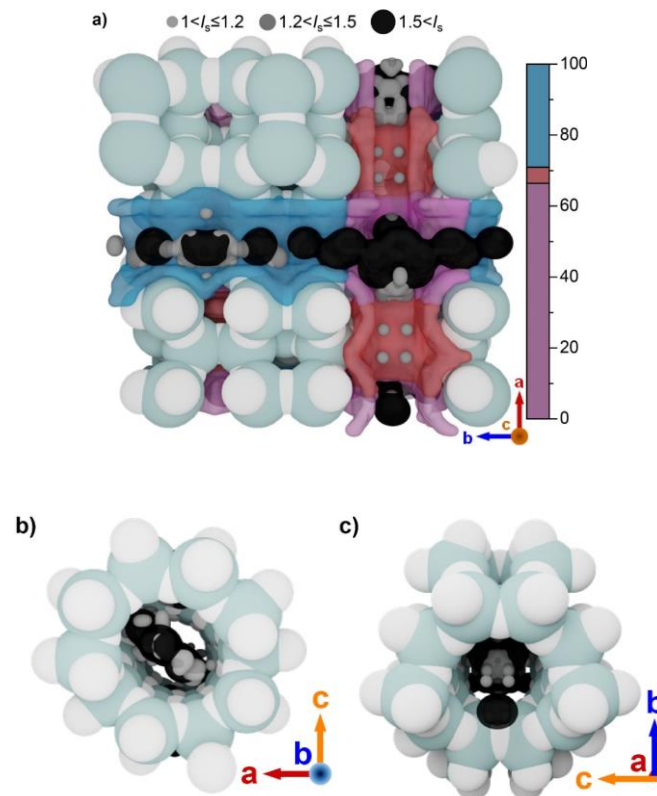
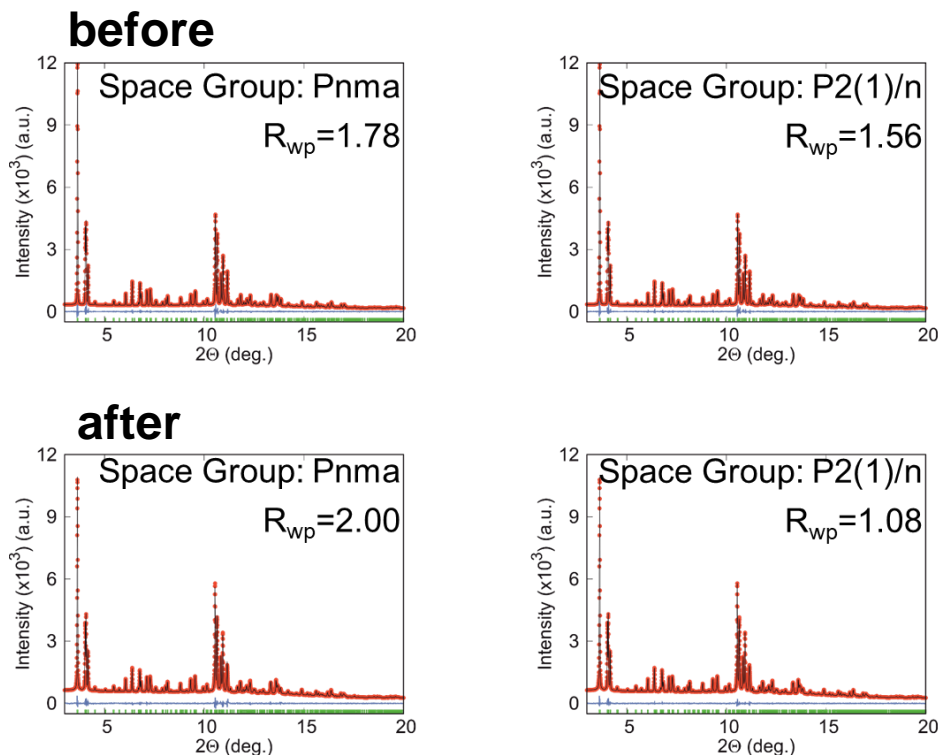
Formation of the strong metal support interaction (SMSI). Pt-Ti alloying



The annealing of carbon-supported Pt nanoparticles. The evolution of diffraction peaks

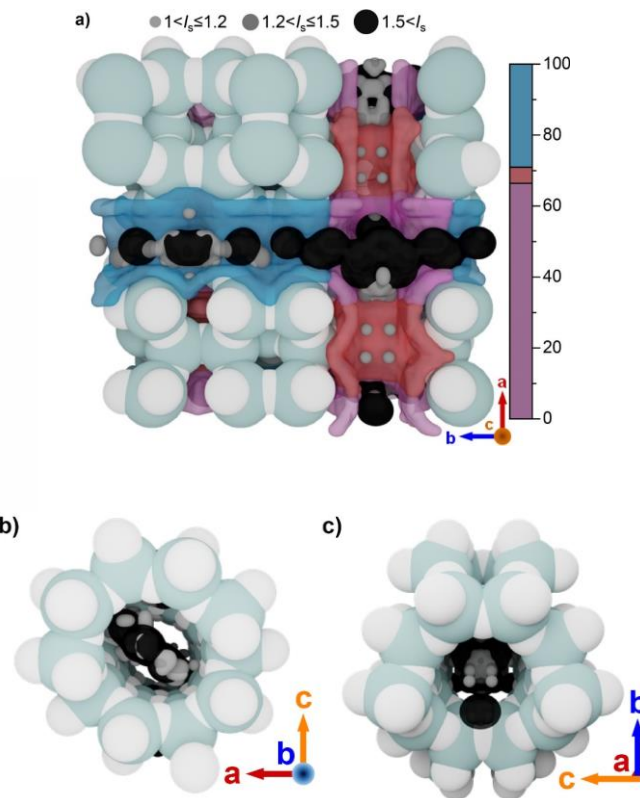
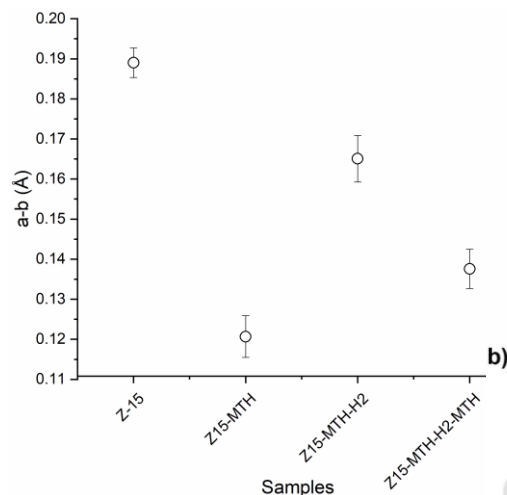
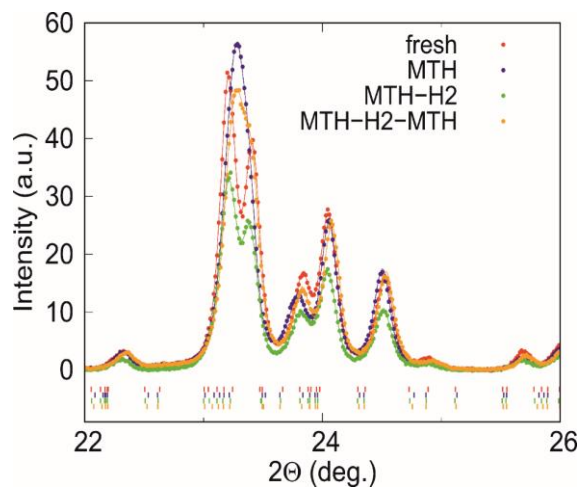


ZSM5 structure upon MTH conversion



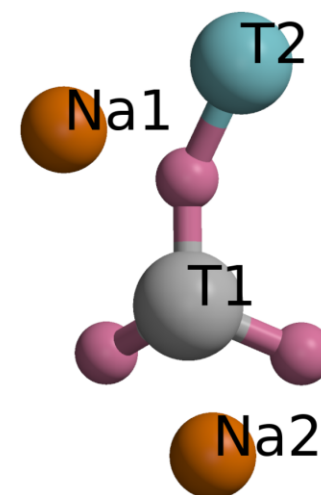
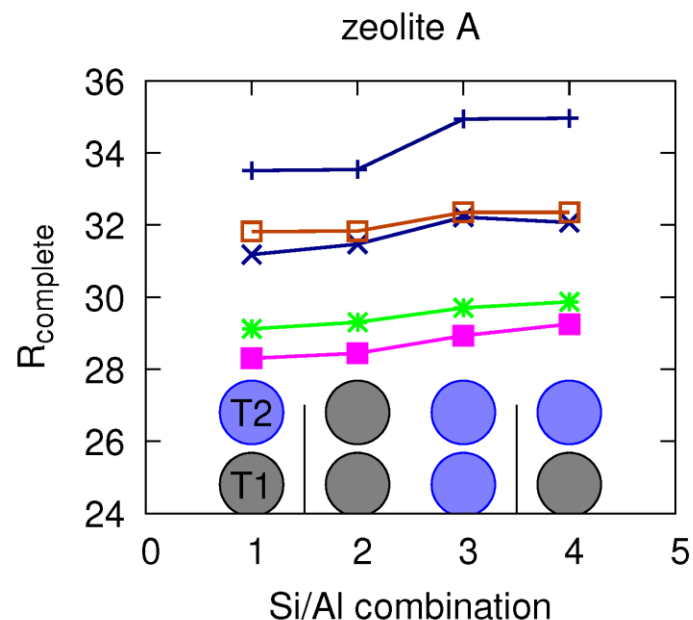
Clustering of coke in the intersection of ZSM-5 channels during methanol-to-hydrocarbons conversion (MTH) leads to lowering of the structure symmetry

ZSM5 structure upon MTH conversion



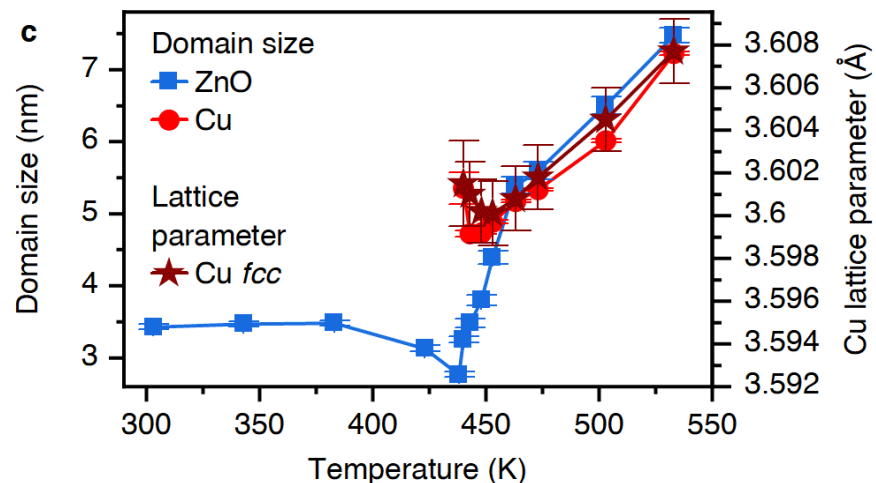
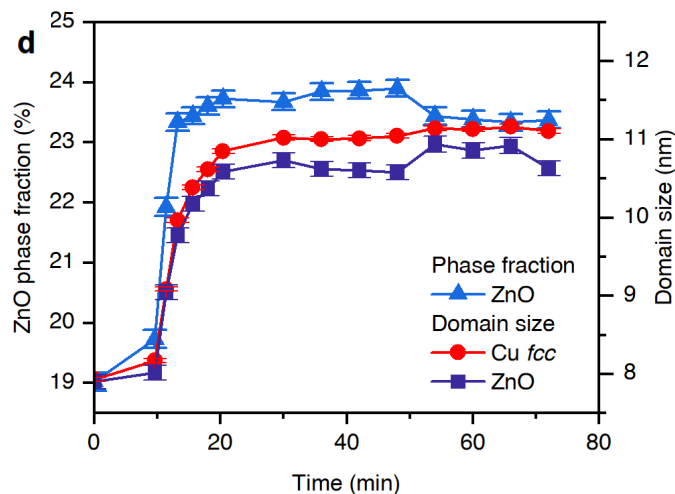
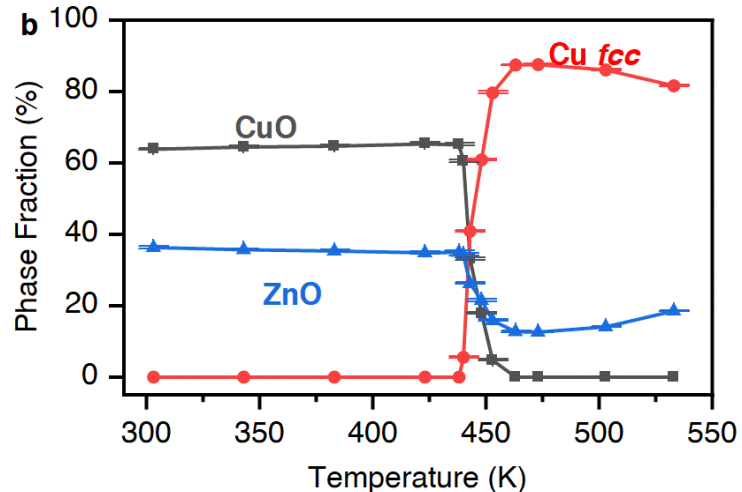
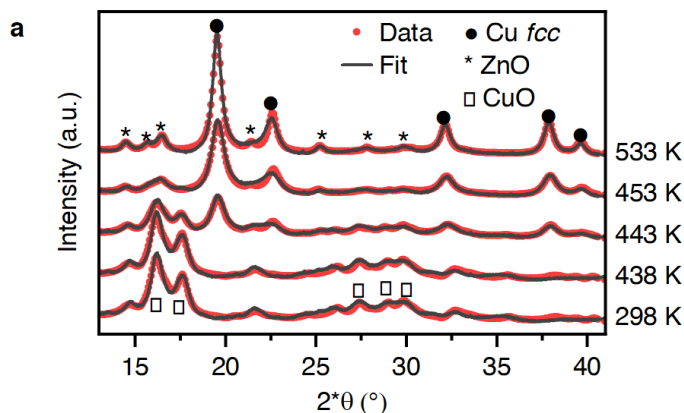
Clustering of coke in the intersection of ZSM-5 channels during methanol-to-hydrocarbons conversion (MTH) is correlated by a-b lattice parameters change

Symmetry lowering with T-atoms alternations

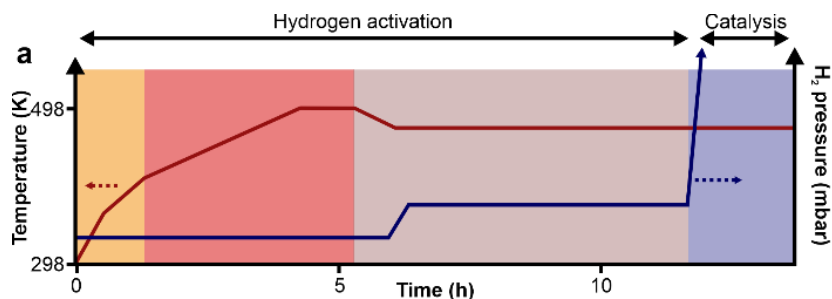


Electron diffraction demonstrates capability of energy discrimination to suppress noise and enables distinguishing between silicon and aluminum

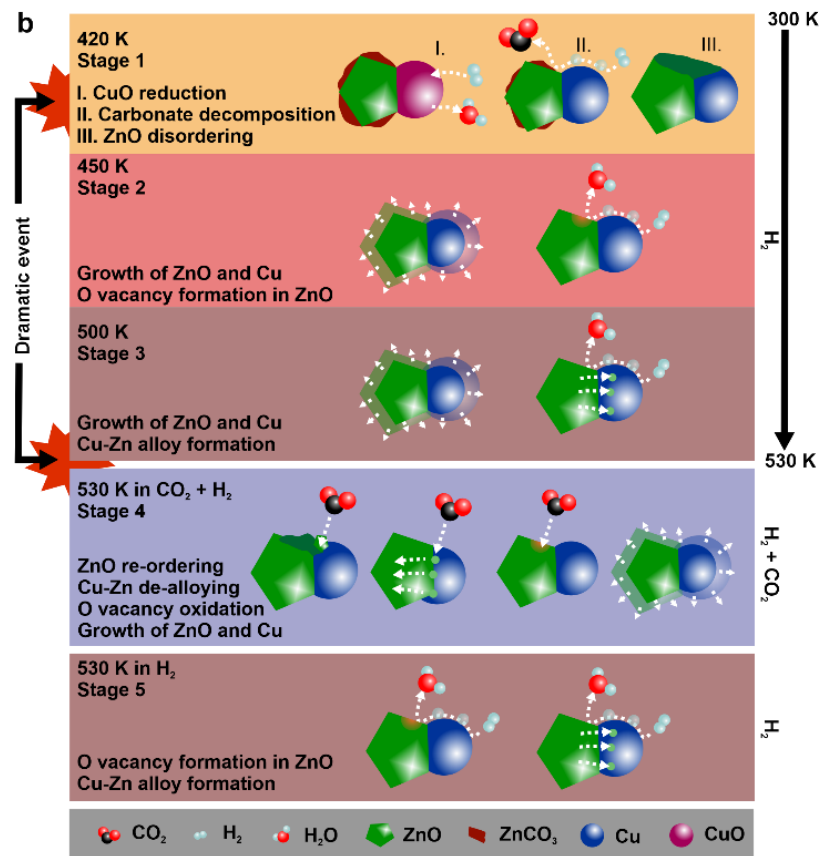
In situ TPR of CZA catalyst



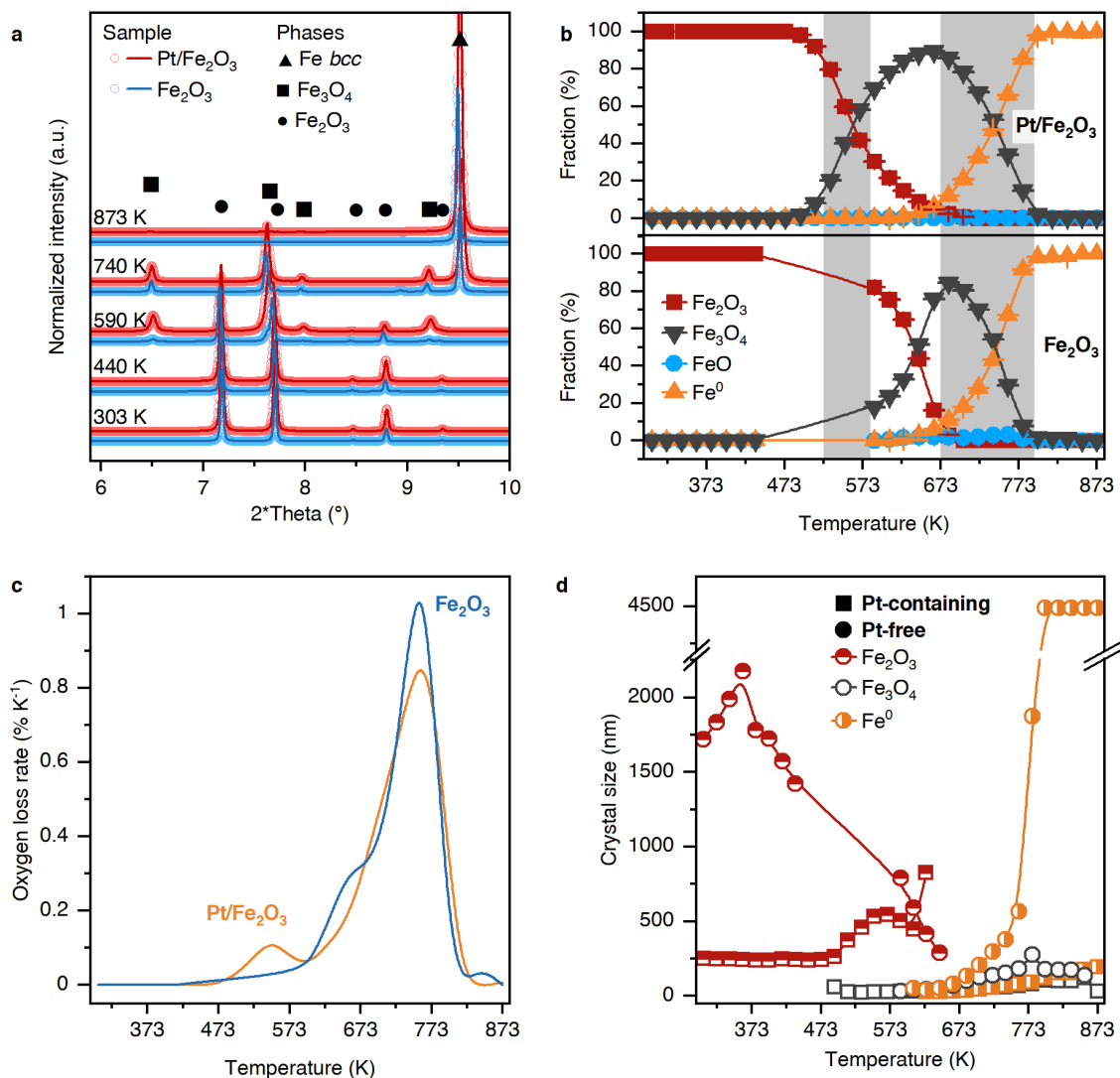
In situ TPR of CZA catalyst



Genesis and transformation of the CZA precursor to the working catalyst upon typical reported industrial activation protocol.

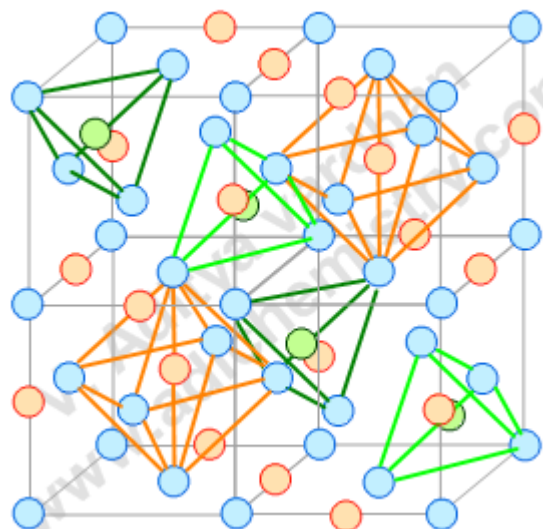


Phase transition

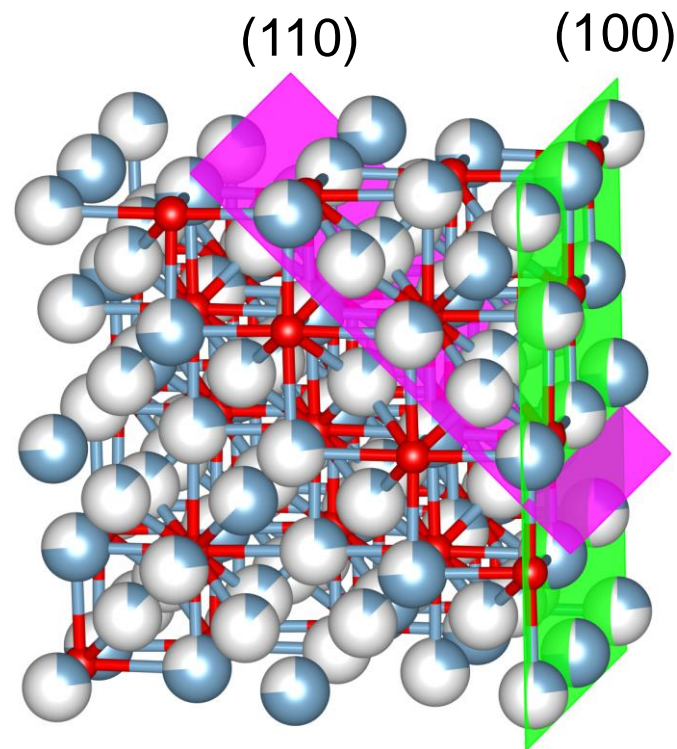


Iron oxides phase transition upon hydrogen in the presence and absence of platinum

Spinel structure of $\gamma\text{-Al}_2\text{O}_3$

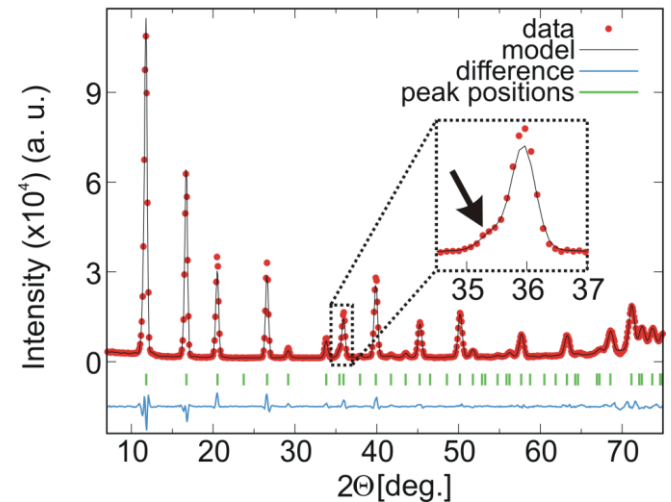
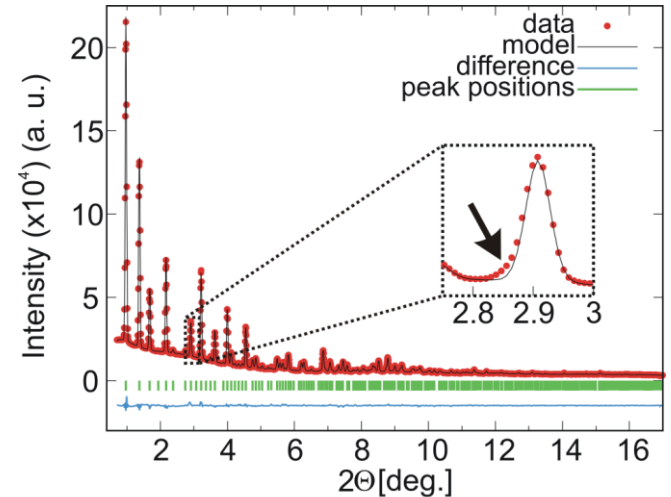
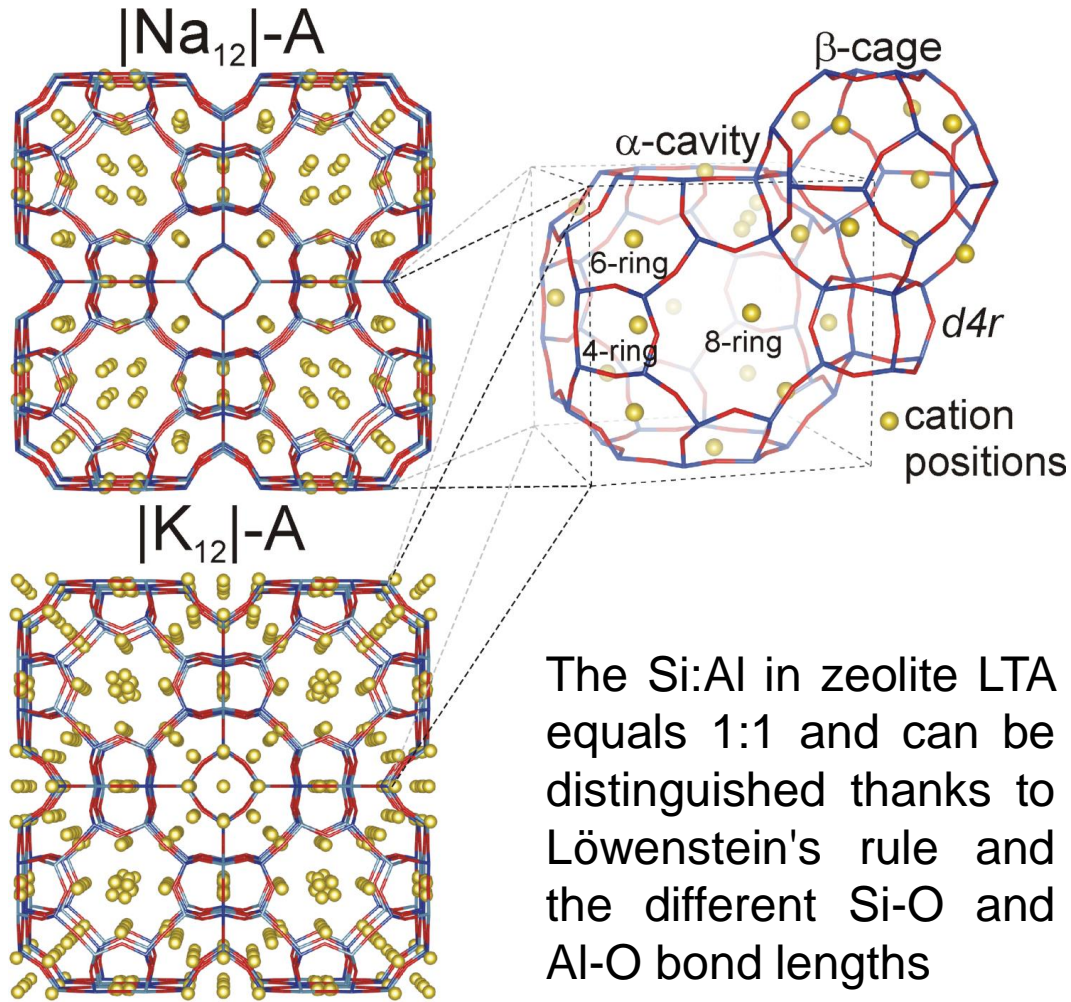


Al cations are distributed over the octahedral ($16d$) and tetrahedral ($8a$) site



$\{100\}$ set of planes is specific for octahedral aluminum

Structure of zeolite LTA

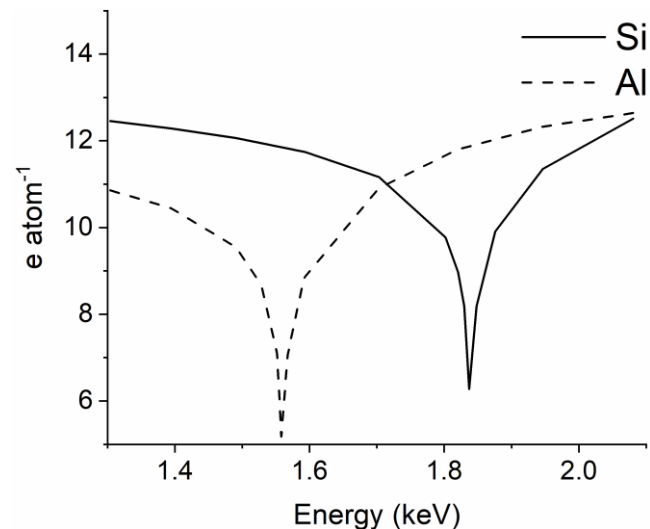
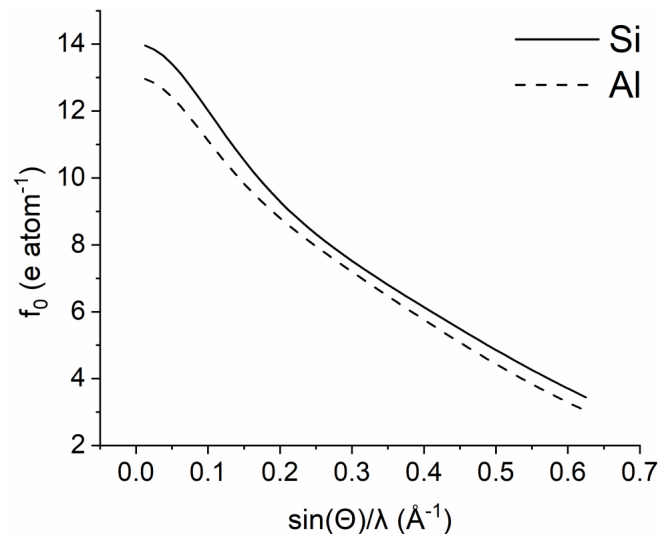


X-ray Anomalous Form Factor

Silicon and aluminum have similar atomic numbers ($Z=14$ and 13) and are difficult to be distinguished

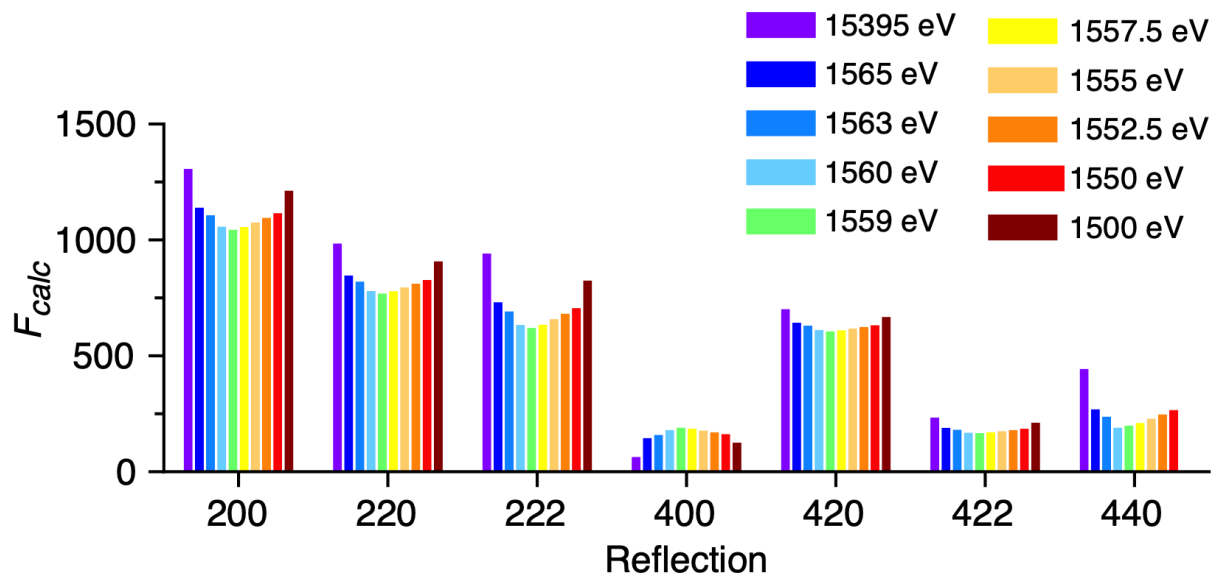
At X-ray absorption energy level, the f' and f'' contributions become significant and the scattering power of an element changes

$$f = f_0 + f' + i \cdot f''$$

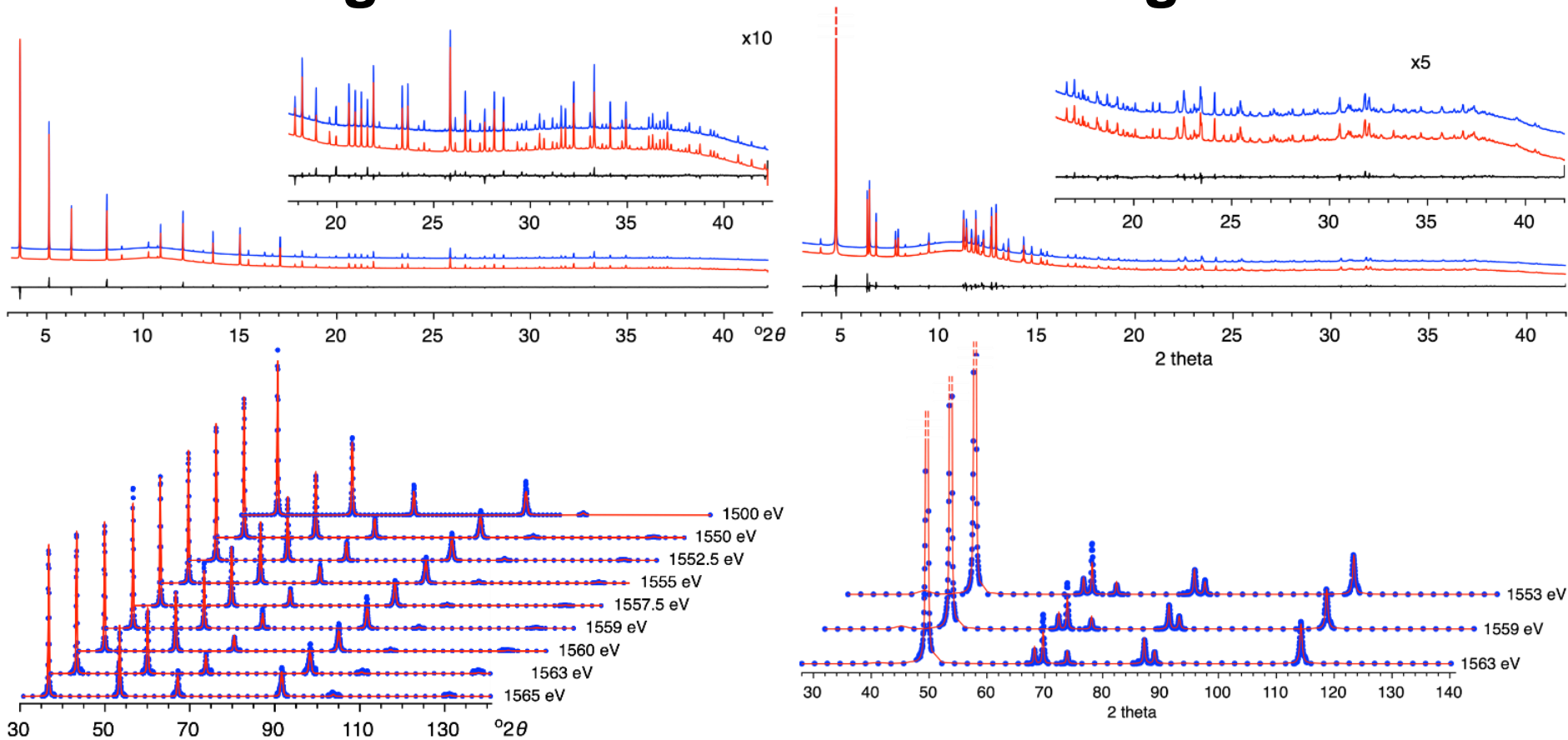


Refinement of resonant data collected from LTA

The F_{hkl} values calculated for zeolite A across Al K-edge energies. The small but significant differences arise from near the Al K-edge. Each reflection is affected slightly differently by the changes in the aluminum scattering factor and these allow the aluminium distribution to be determined



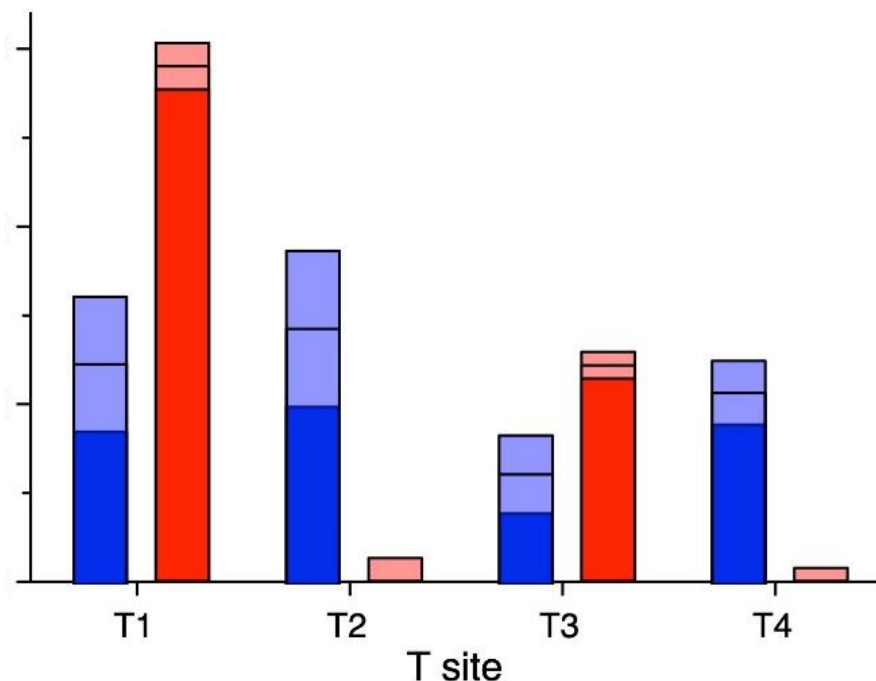
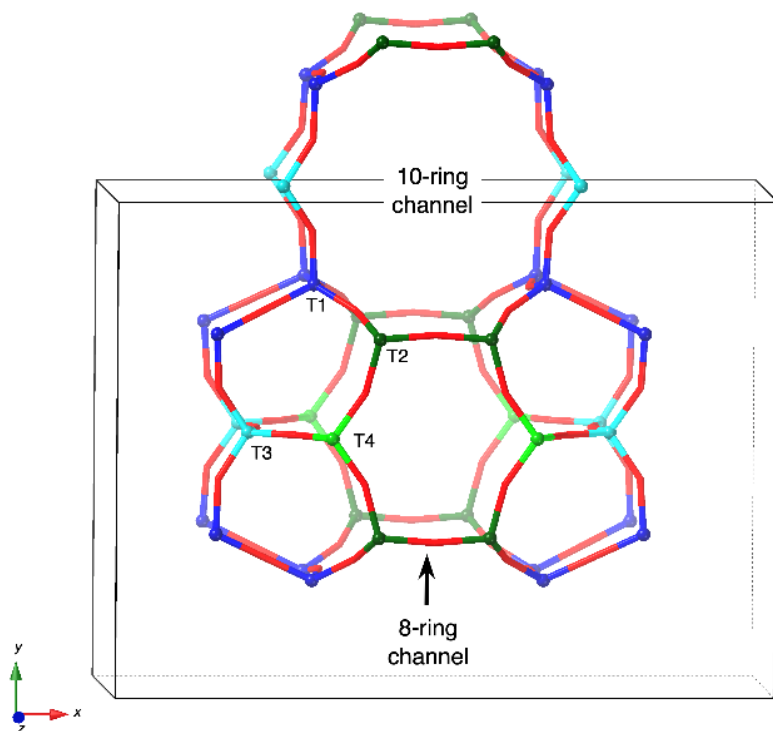
Structure Refinement using conventional and Al K-edge data



Structure refinement of Zeolite A

Structure refinement of zeolite FER

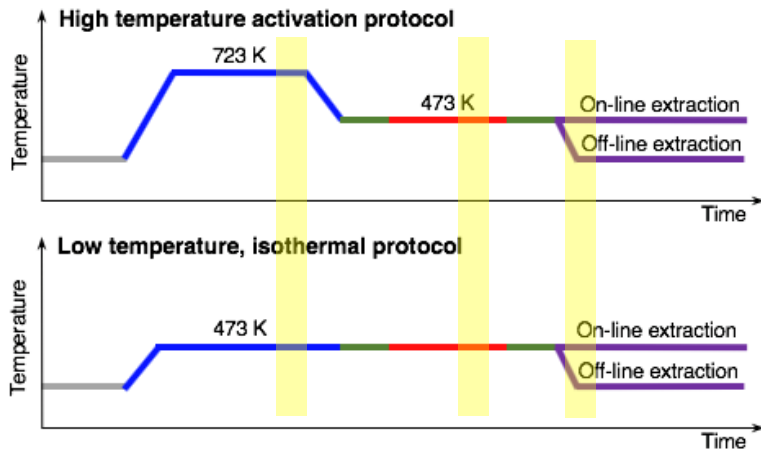
Refinement of resonant data collected from FER



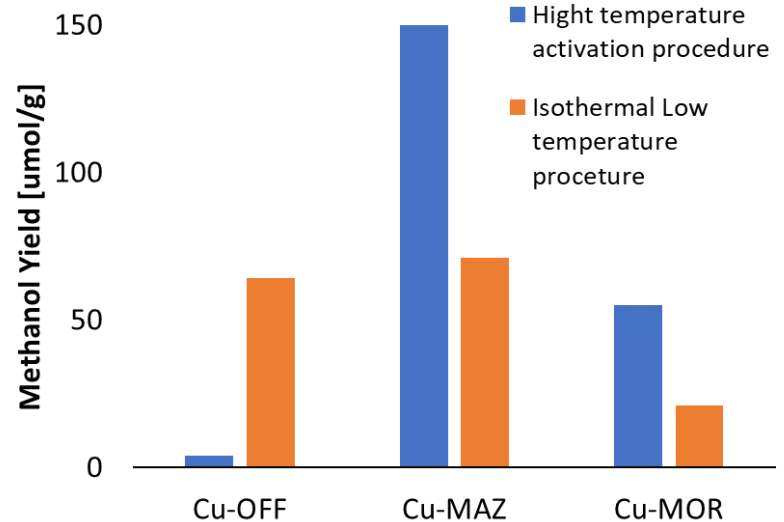
The ordering of the 2.2 aluminium atoms per unit cell over the four T-sites in FER1 (blue) and FER-PYRR (red)

Anomalous diffraction across copper K-edge

The aim of this project is to exploit anomalous scattering at the Cu K-edge to elucidate the structure of the copper species present during the partial oxidation of methane to methanol (MtM)

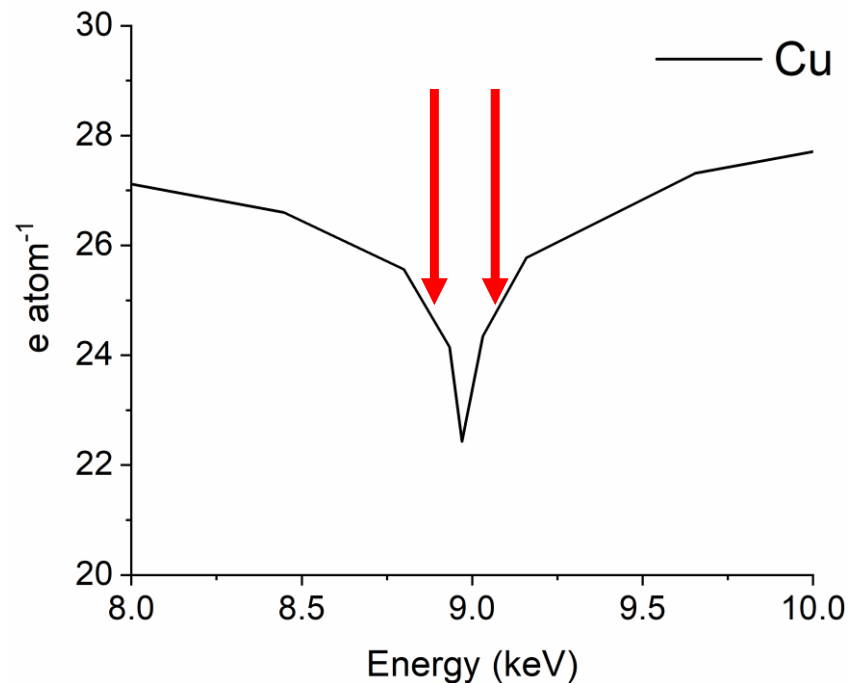
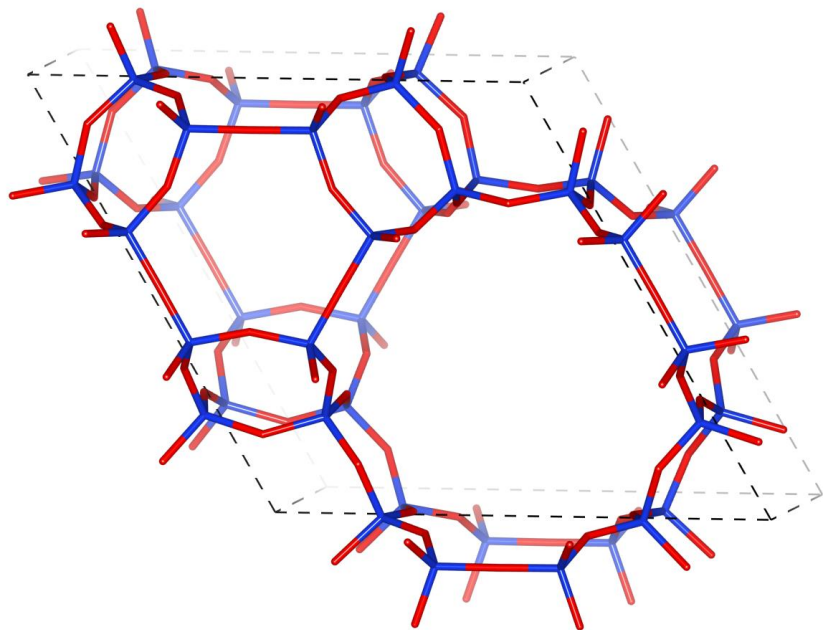


Copper offretite underwent isothermal and high-temperature procedures for methane-to-methanol conversion



Cu-offretite preforms better at lower temperature

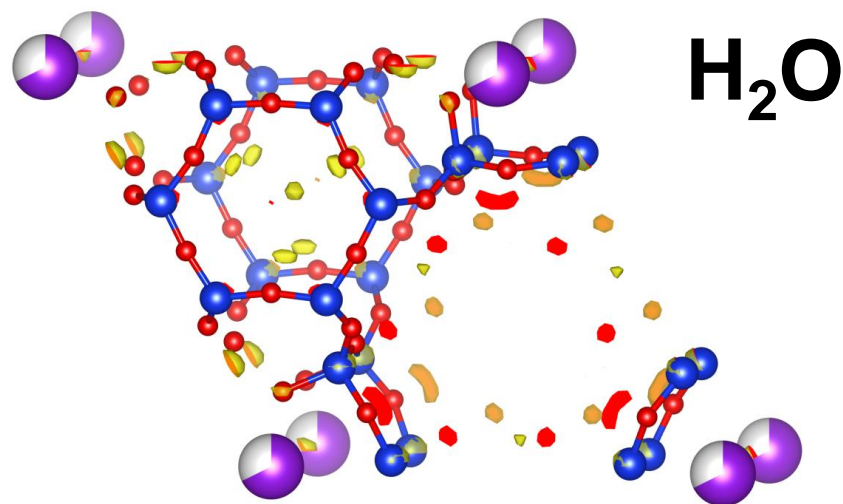
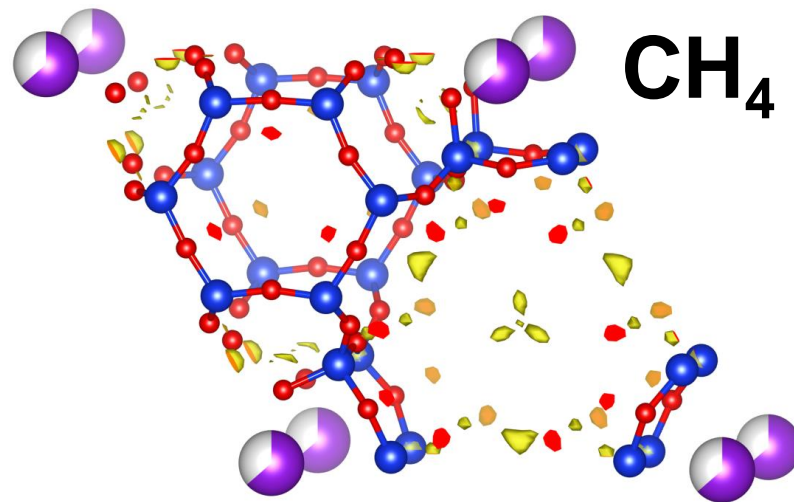
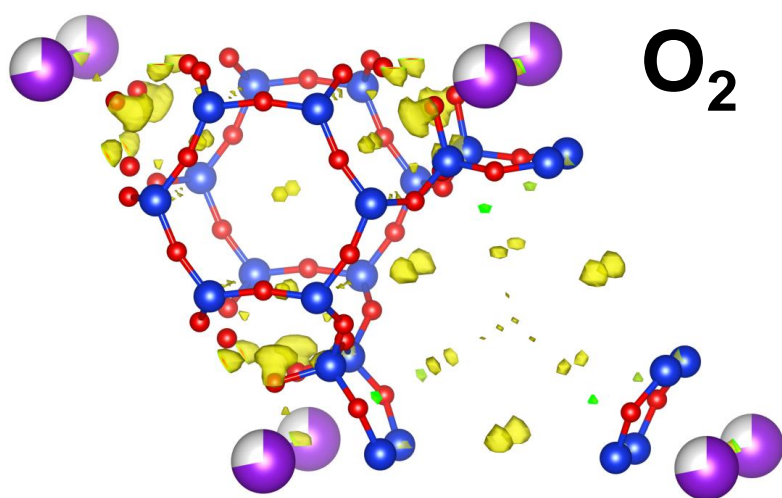
Anomalous diffraction across copper K-edge



Offretite is hexagonal structure with 12-ring channels along z-axis. It is composed of gmelinite and cancrinite cages

Each sample was measured at off-resonance (17.5 keV) and on-resonance conditions (8.97 keV and 8.98 keV)

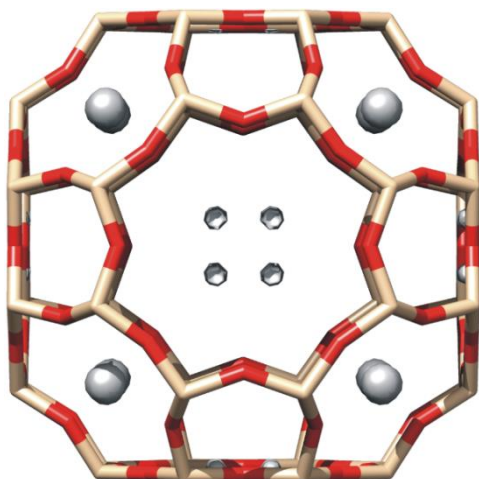
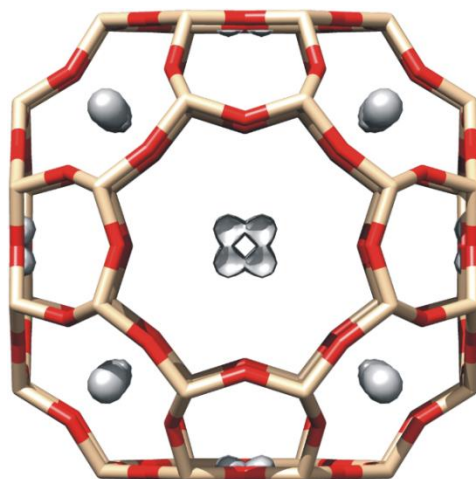
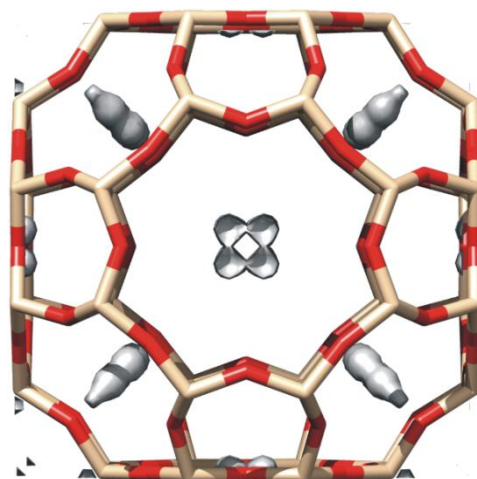
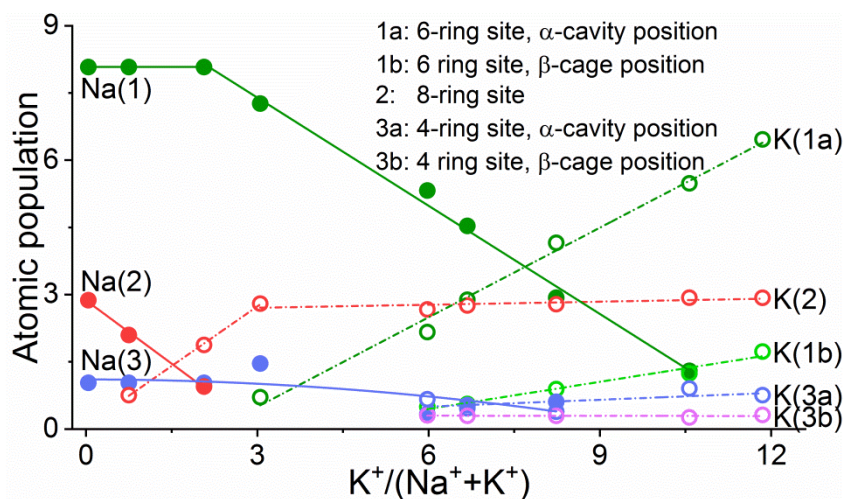
High resolution diffraction of offretite



OFF structure reveals the electron densities near 8-ring window of gmelinite cage upon MtM protocol. Similar observation was done on Cu-Omega

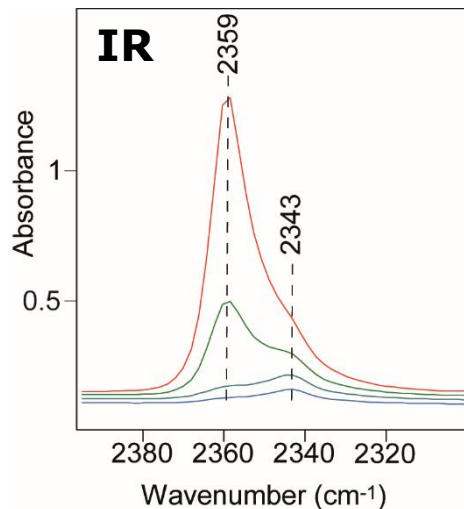
Anomalous diffraction is needed for ambiguous assignment of these densities to copper, oxygen or carbon

The population of Na⁺ and K⁺ in |Na_{12-x}K_x|-A

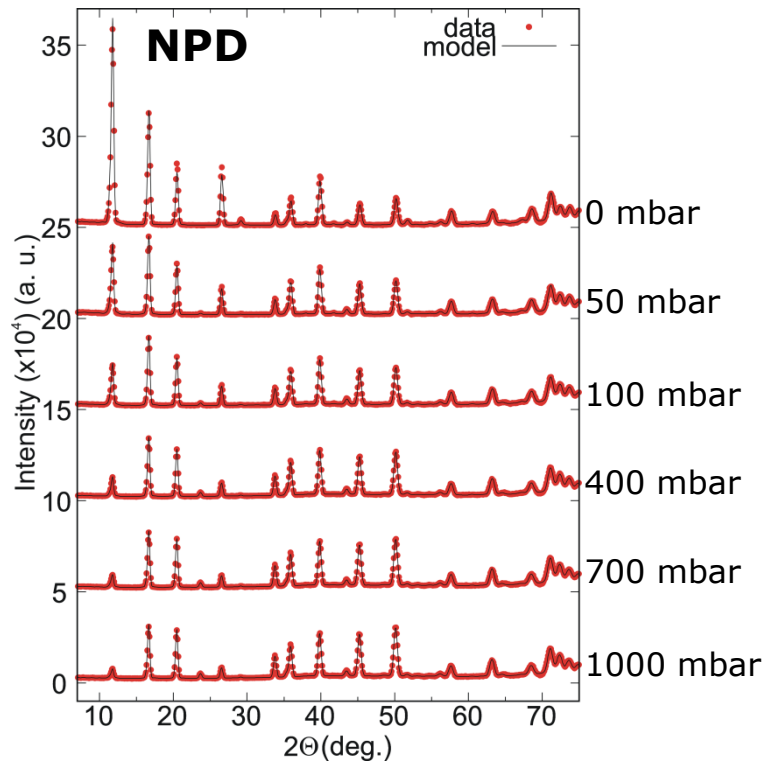
|Na₁₂|-A|Na₉K₃|-A|Na_{5.3}K_{6.7}|-A

- K⁺ and Na⁺ populations are well resolved due to different positioning
- 8-ring is favored by cation replacement at low K⁺-content
- K⁺ gradually substitutes Na⁺ in 6-ring

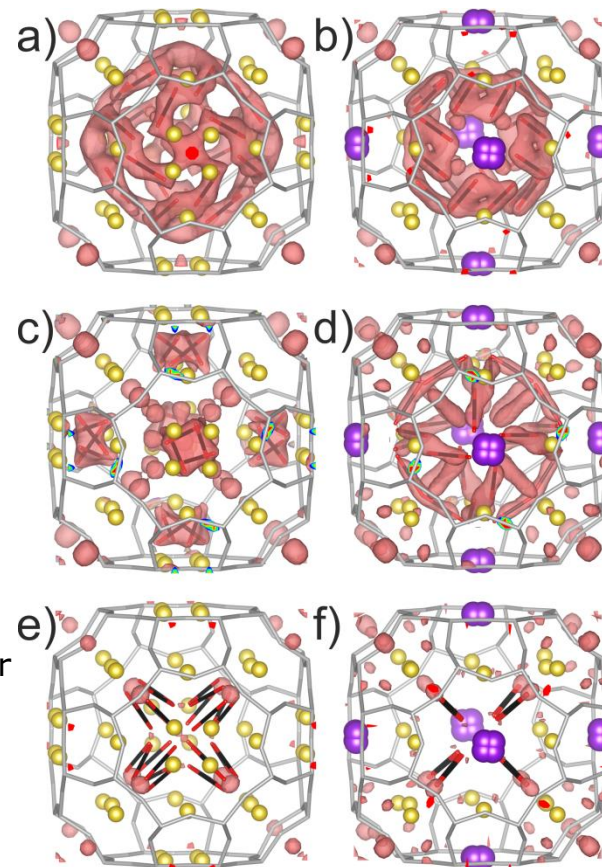
The chemical nature of physisorbed CO₂



IR bands showed differentiation of physisorbed CO₂ at |Na₁₂|-A

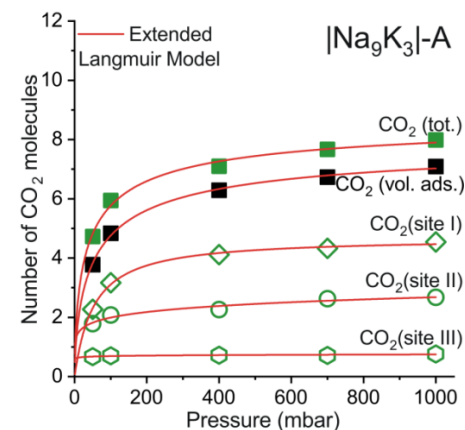
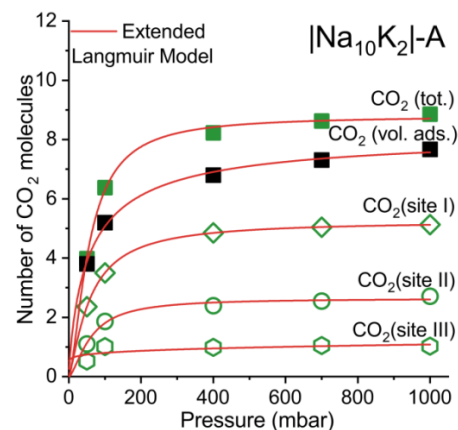
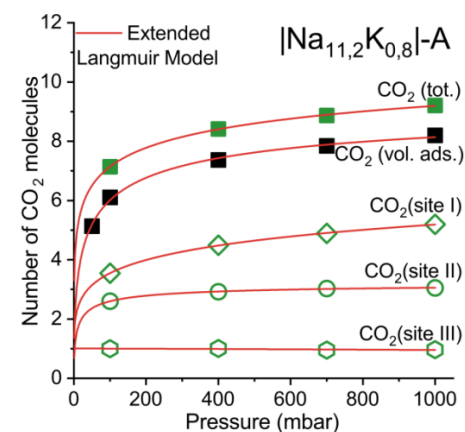
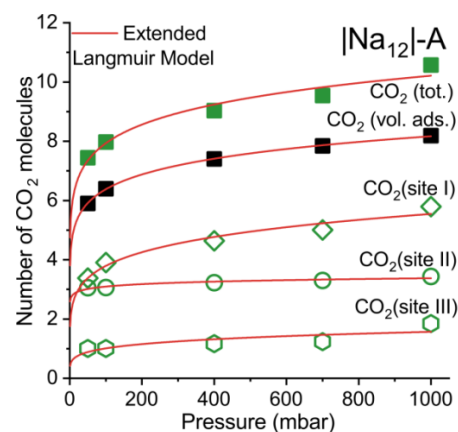
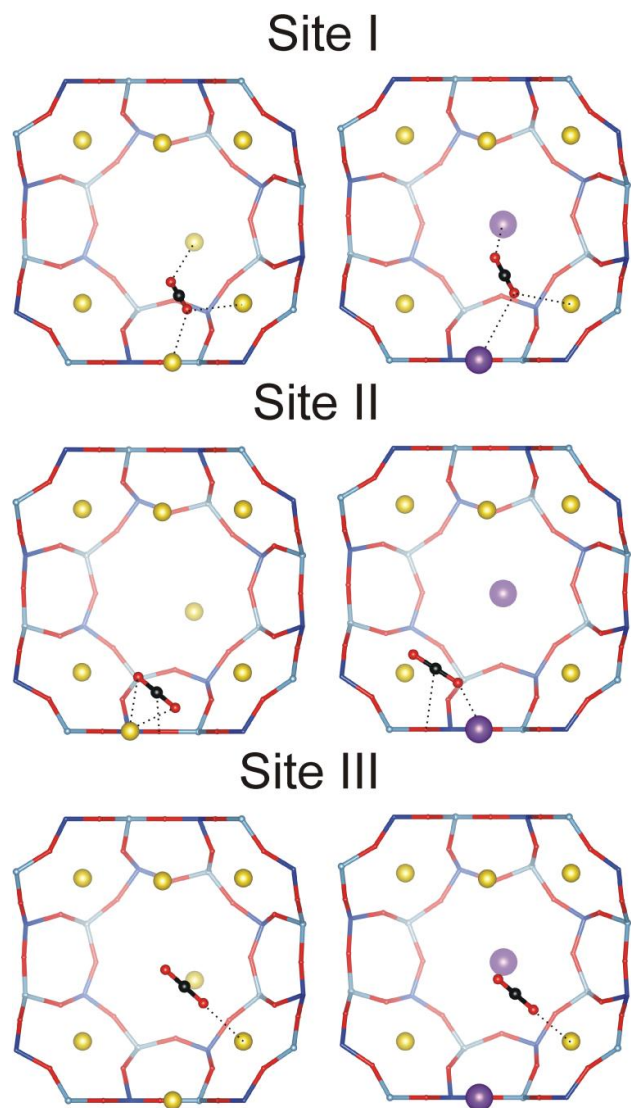


Rietveld analyses of the *in situ* neutron powder diffraction patterns of |Na₉K₃|-A



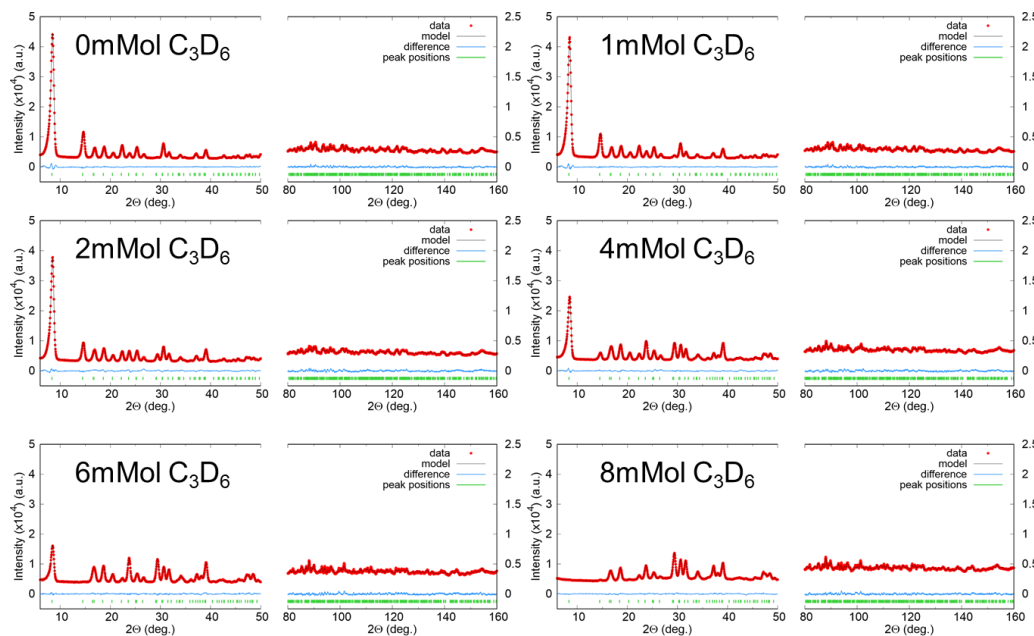
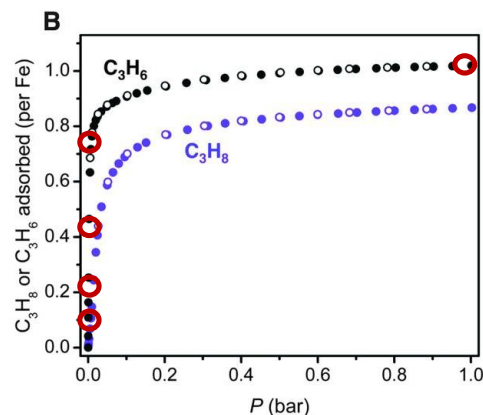
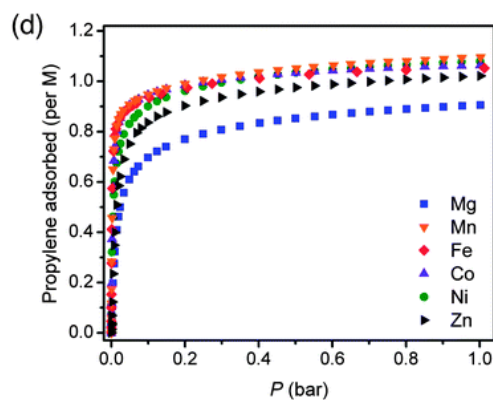
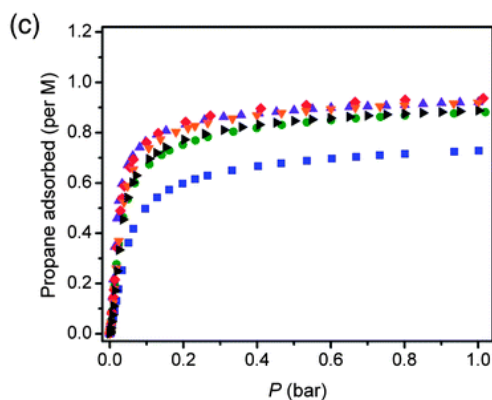
Difference Fourier maps of 3 sites of CO₂ for |Na₁₂|-A (left) and |Na₉K₃|-A (right)

Site-specific physisorption of CO₂



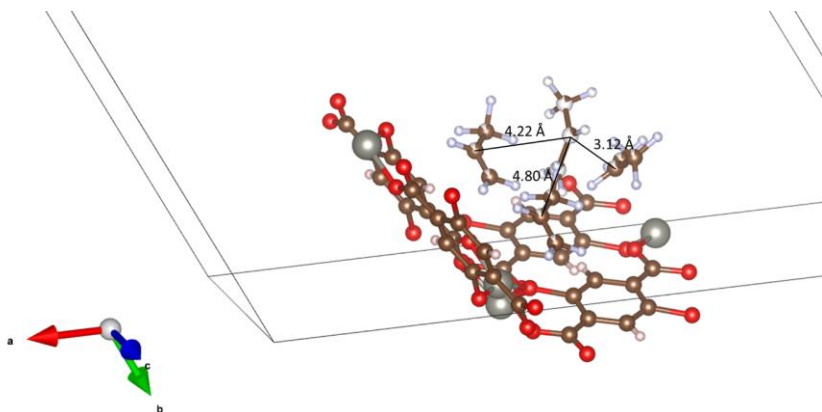
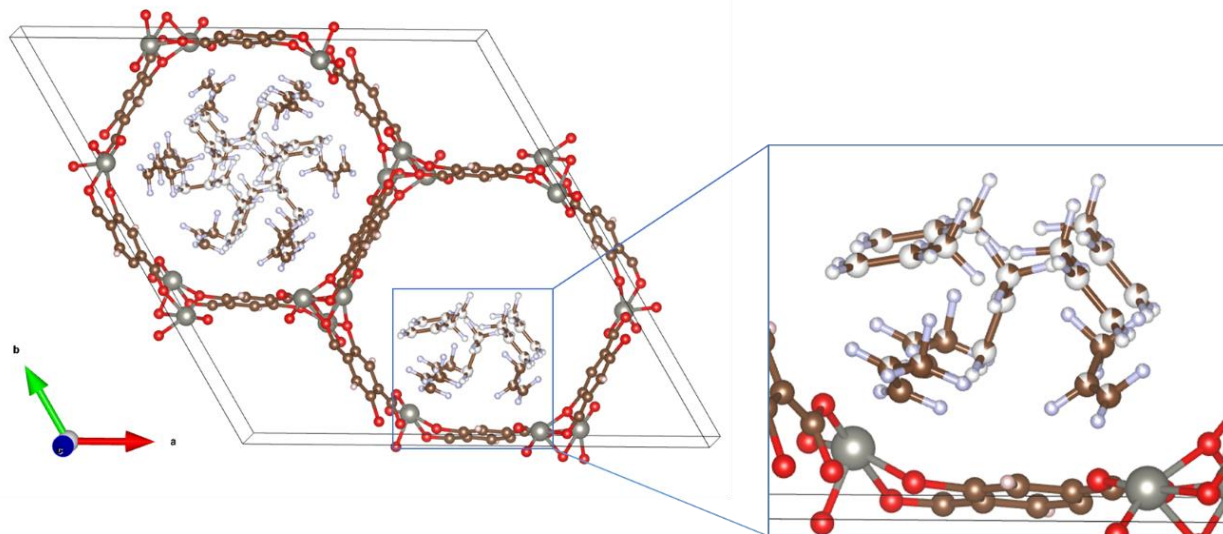
Atomic positions and site specific isotherms of adsorbed CO₂

Adsorption of deuterated olefins



Rietveld refinement profile
for Zn-MOF-74 as function
of D_6H_{12} adsorption

Adsorption of deuterated olefins



The refined propene-loaded Zn-MOF-74 structure with intermolecular distances

The propene density is increased inside the porous system upon formation of 2nd layer of adsorption

References

1. <http://pd.chem.ucl.ac.uk/pd/welcome.htm>
2. <http://prism.mit.edu/xray/education/downloads.html>
3. <http://www.crystal.mat.ethz.ch/people/staff/mlynne/>

Thank you for your attention!